RENESAS

RL78/L12

RENESAS MCU

Datasheet

R01DS0157EJ0221 Rev.2.21 Feb 01, 2023

True low-power platform (62.5 μ A/MHz, and 0.64 μ A for operation with only RTC and LVD) for the LCD-based applications, with the on-chip LCD controller and driver, 8- to 32-Kbyte code flash memory, 1.6-V to 5.5-V operation, and 31 DMIPS at 24 MHz

1. OUTLINE

1.1 Features

Ultra-Low Power Technology

- 1.6 V to 5.5 V operation from a single supply
- Stop (RAM retained): 0.23 μ A, (LVD enabled): 0.31 μ A
- Halt (RTC + LVD): 0.64 *µ*A
- Supports snooze
- Operating: 62.5 µA/MHz
- LCD operating current (Capacitor split method): 0.12 μ A
- LCD operating current (Internal voltage boost method): 0.63 μ A (V_{DD} = 3.0 V)

16-bit RL78 CPU Core

- Delivers 31 DMIPS at maximum operating frequency of 24 MHz
- Instruction Execution: 86% of instructions can be executed in 1 to 2 clock cycles
- CISC Architecture (Harvard) with 3-stage pipeline
- Multiply Signed & Unsigned: 16 x 16 to 32-bit result in 1 clock cycle
- MAC: 16 x 16 to 32-bit result in 2 clock cycles
- 16-bit barrel shifter for shift & rotate in 1 clock cycle
- 1-wire on-chip debug function

Code Flash Memory

- Density: 8 KB to 32 KB
- Block size: 1 KB
- On-chip single voltage flash memory with protection from block erase/writing
- Self-programming with flash shield window function

Data Flash Memory

- Data flash with background operation
- Data flash size: 2 KB size
- Erase cycles: 1 Million (typ.)
- Erase/programming voltage: 1.8 V to 5.5 V

RAM

- 1 KB and 1.5 KB size options
- Supports operands or instructions
- Back-up retention in all modes

High-speed On-chip Oscillator

- 24 MHz with +/- 1% accuracy over voltage (1.8 V to 5.5 V) and temperature (-20°C to 85°C)
- Pre-configured settings: 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz & 1 MHz

Reset and Supply Management

- Power-on reset (POR) monitor/generator
- Low voltage detection (LVD) with 14 setting options (Interrupt and/or reset function)

LCD Controller/Driver

- Up to 35 seg x 8 com or 39 seg x 4 com
- Supports capacitor split method, internal voltage boost method and resistance division method
- Supports waveform types A and B
- Supports LCD contrast adjustment (16 steps)
- Supports LCD blinking

Direct Memory Access (DMA) Controller

- Up to 2 fully programmable channels
- Transfer unit: 8- or 16-bit

Multiple Communication Interfaces

- Up to $1 \times I^2C$ multi-master
- Up to 2 × Simplified SPI (CSI^{Note1}) (7-, 8-bit)
- Up to 1 × UART (7-, 8-, 9-bit)
- Up to 1 × LIN

Extended-Function Timers

- Multi-function 16-bit timers: Up to 8 channels
- Real-time clock (RTC): 1 channel (full calendar and alarm function with watch correction function)
- Interval Timer: 12-bit, 1 channel
- 15 kHz watchdog timer: 1 channel (window function)

Rich Analog

- ADC: Up to 10 channels, 10-bit resolution, 2.1 µs conversion time
- Supports 1.6 V
- Internal reference voltage (1.45 V)
- On-chip temperature sensor

Safety Features (IEC or UL 60730 compliance)

- Flash memory CRC calculation
- RAM parity error check
- RAM write protection
- SFR write protection
- · Illegal memory access detection
- Clock frequency detection
- ADC self-test

General Purpose I/O

- 5V tolerant, high-current (up to 20 mA per pin)
- Open-Drain, Internal Pull-up support

Operating Ambient Temperature

- TA: -40 °C to +85 °C (A: Consumer applications)
- TA: -40 °C to +105 °C (G: Industrial applications)

Package Type and Pin Count

From 7mm x 7mm to 12mm x 12mm QFP: 32, 44, 48, 52, 64

Notes 1. Although the CSI function is generally called SPI, it is also called CSI in this product, so it is referred to as such in this manual.



Flash ROM	Data flash	RAM			RL78/L12		
			32 pins	44 pins	48 pins	52 pins	64 pins
32 KB	2 KB	1.5 KB ^{Note}	R5F10RBC	R5F10RFC	R5F10RGC	R5F10RJC	R5F10RLC
16 KB	2 KB	1 KB ^{Note}	R5F10RBA	R5F10RFA	R5F10RGA	R5F10RJA	R5F10RLA
8KB	2 KB	1 KB ^{Note}	R5F10RB8	R5F10RF8	R5F10RG8	R5F10RJ8	-

Note In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

Remark The functions mounted depend on the product. See 1.6 Outline of Functions.



1.2 List of Part Numbers

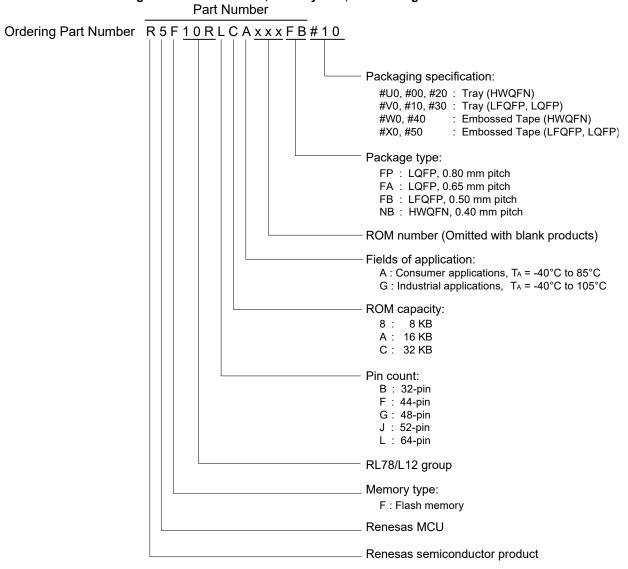


Figure 1-1. Part Number, Memory Size, and Package of RL78/L12



(1	/2)
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Table 1-1	List of	Ordoring	Part Numbers
Table I-I.		Ordening	rait numbers

Pin			Fields of	Ordering Part Number			
count	Package	Data flash	Application Product Name Packaging Specifications Atted A R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP #V0, #X0, #30 Ited A R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP #V0, #X0, #30 G R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP #V0, #X0, #30 ited A R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP #V0, #X0, #30 ited A R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP #V0, #X0 ited A R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP #V0, #X0 ited A R5F10RF8GFP, R5F10RFAAFP, R5F10RFCAFP #V0, #X0 ited A R5F10RF8GFP, R5F10RFAGFP, R5F10RFCAFP #V0, #X0 ited A R5F10RF8GFP, R5F10RFAGFP, R5F10RFCGFP #V0, #X0	RENESAS Code			
32 pins		Mounted	А	R5F10RB8AFP, R5F10RBAAFP, R5F10RBCAFP	#V0, #X0, #30	PLQP0032GB-A	
	LQFP (7 × 7 mm,				#10, #50	PLQP0032GB-A PLQP0032GE-A	
	0.8mm pitch)		G	R5F10RB8GFP, R5F10RBAGFP, R5F10RBCGFP	#V0, #X0, #30	PLQP0032GB-A	
					#10, #50	PLQP0032GB-A PLQP0032GE-A	
44 pins	44-pin plastic	Mounted	А	R5F10RF8AFP, R5F10RFAAFP, R5F10RFCAFP	#V0, #X0	PLQP0044GC-A	
	LQFP (10 × 10 mm,				#10, #50	PLQP0044GC-A PLQP0044GC-D PLQP0044GE-A	
	0.8mm pitch)				#30	PLQP0044GC-A PLQP0044GC-D	
			G	R5F10RF8GFP, R5F10RFAGFP, R5F10RFCGFP	#V0, #X0	PLQP0044GC-A	
						#10, #50	PLQP0044GC-A PLQP0044GC-D PLQP0044GE-A
					#30	PLQP0044GC-A PLQP0044GC-D	
48 pins		Mounted	А	R5F10RG8AFB, R5F10RGAAFB, R5F10RGCAFB	#V0, #X0	PLQP0048KF-A	
	LFQFP (7 × 7 mm,				#10, #50	PLQP0048KB-B PLQP0048KL-A	
	0.5mm pitch)				#30	PLQP0048KB-B	
			G	R5F10RG8GFB, R5F10RGAGFB, R5F10RGCGFB	#V0, #X0	PLQP0048KF-A	
					#10, #50	PLQP0048KB-B PLQP0048KL-A	
					#30	PLQP0048KB-B	
52 pins		Mounted	А	R5F10RJ8AFA, R5F10RJAAFA, R5F10RJCAFA	#V0, #X0	PLQP0052JA-A	
	LQFP (10 × 10				#10, #30, #50	PLQP0052JA-A PLQP0052JD-B	
	mm, 0.65mm		G	R5F10RJ8GFA, R5F10RJAGFA, R5F10RJCGFA	#V0, #X0	PLQP0052JA-A	
	pitch)				#10, #30, #50	PLQP0052JA-A PLQP0052JD-B	

Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/L12.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

			Fields of	Ordering Part Number						
Pin count	Package	Data flash	Application	Product Name	Packaging Specifications	RENESAS Code				
64 pins	64-pin plastic	Mounted	A	R5F10RLAANB, R5F10RLCANB	#U0, #W0	PWQN0064LA-A				
	HWQFN				#00, #20, #40	PWQN0064LB-A				
	(8 × 8 mm, 0.4mm pitch)		G	R5F10RLAGNB, R5F10RLCGNB	#U0, #W0	PWQN0064LA-A				
	•••••••				#00, #20, #40	PWQN0064LB-A				
	64-pin plastic	Mounted	А	R5F10RLAAFB, R5F10RLCAFB	#V0, #X0	PLQP0064KF-A				
(LFQFP (10 × 10 mm,				#10, #50	PLQP0064KB-C PLQP0064KL-A				
	0.5mm pitch)		#30	PLQP0064KB-C						
							G	R5F10RLAGFB, R5F10RLCGFB	#V0, #X0	PLQP0064KF-A
							#10, #50	PLQP0064KB-C PLQP0064KL-A		
					#30	PLQP0064KB-C				
	64-pin plastic	Mounted	A	R5F10RLAAFA, R5F10RLCAFA	#V0, #X0	PLQP0064JA-A				
	LQFP (12 × 12 mm,					#10, #30, #50	PLQP0064JA-A PLQP0064JB-A			
	0.65mm pitch)		G	R5F10RLAGFA, R5F10RLCGFA	#V0, #X0	PLQP0064JA-A				
						#10, #30, #50	PLQP0064JA-A PLQP0064JB-A			

 Table 1-1. List of Ordering Part Numbers

(2/2)

Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/L12.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.



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1.3 Pin Configuration (Top View)

1.3.1 32-pin products

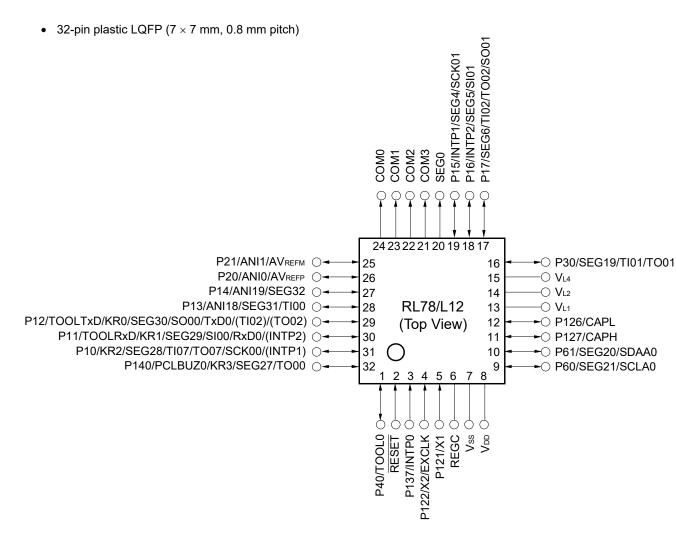


Table 1-2. Alternate function of 32-pin products

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Pin No.	I/O	debug	Analog	НМІ			Timer		Communications Interface	
32LQFP	Digital port	Power supply, system, clock, c	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P40	TOOL0								
2		RESET								
3	P137			INTP0						
4	P122	X2/EXCLK								



 Table 1-2. Alternate function of 32-pin products

(2/2)

Pin	I/O	D	Analog	HMI			Timer		Communications	Interface
No.		lebu				1				
32LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
5	P121	X1								
6		REGC								
7		V _{SS}								
8		V _{DD}								
9	P60					SEG21				SCLA0
10	P61					SEG20				SDAA0
11	P127					CAPH				
12	P126					CAPL				
13						V _{L1}				
14						V _{L2}				
15						V _{L4}				
16	P30					SEG19	TI01/TO01			
17	P17					SEG6	TI02/TO02		SO01	
18	P16			INTP2		SEG5			SI01	
19	P15			INTP1		SEG4			SCK01	
20						SEG0				
21						COM3				
22						COM2				
23						COM1				
24						COM0				
25	P21		ANI1/AV _{REFM}							
26	P20		ANI0/AV _{REFP}							
27	P14		ANI19		1	SEG32				
28	P13		ANI18			SEG31	TI00			
29	P12	TOOLTxD			KR0	SEG30	(TI02)/(TO02)		SO00/TxD0	
30	P11	TOOLRxD		(INTP2)	KR1	SEG29			SI00/RxD0	
31	P10			(INTP1)	KR2	SEG28	TI07/TO07		SCK00	
32	P140	PCLBUZ0		,	KR3	SEG27	TO00	1		

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1. OUTLINE

1.3.2 44-pin products

• 44-pin plastic LQFP (10 × 10 mm, 0.8 mm pitch)

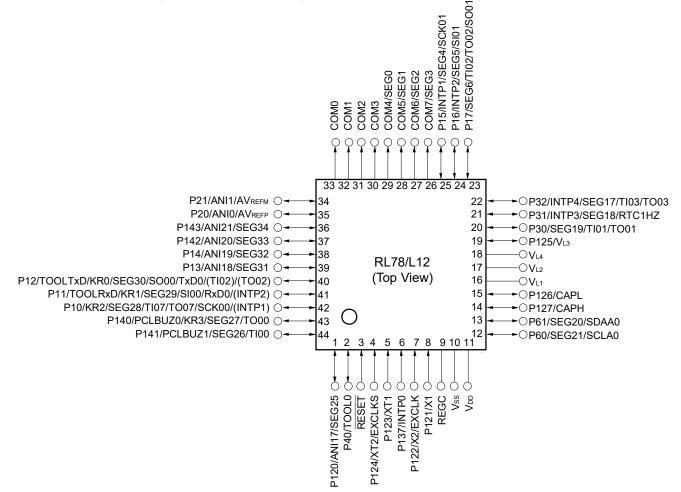


Table 1-3. Alternate function of 44-pin products

(1/3)

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Pin No.	I/O	ebug	Analog	нмі			Timer		Communications Interface	
44LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P40	TOOL0								
3		RESET								
4	P124	XT2/EXCLKS								
5	P123	XT1								



 Table 1-3. Alternate function of 44-pin products

(2/3)

	I/O			HMI		uon oi 44-pin			Communicat	(2/3)
Pin No.	1/0	6no	Analog	HIVII			Timer		Communicat Interface	lons
44LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
6	P137			INTP0						
7	P122	X2/EXCLK								
8	P121	X1								
9		REGC								
10		V _{SS}								
11		V _{DD}								
12	P60					SEG21				SCLA0
13	P61					SEG20				SDAA0
14	P127					САРН				
15	P126					CAPL				
16						V _{L1}				
17						V _{L2}				
18						V _{L4}				
19	P125					V _{L3}				
20	P30					SEG19	TI01/TO01			
21	P31			INTP3		SEG18		RTC1HZ		
22	P32			INTP4		SEG17	TI03/TO03			
23	P17					SEG6	TI02/TO02		SO01	
24	P16			INTP2		SEG5			SI01	
25	P15			INTP1		SEG4			SCK01	
26				1		COM7/SEG3				
27				1		COM6/SEG2				
28						COM5/SEG1				
29						COM4/SEG0				
30						COM3				
31						COM2				
32						COM1				
33						COM0				



			Table 1-3	3. Alterna	te func	tion of 44-pir	n products			(3/3)
Pin No.	I/O	ebug	Analog	НМІ			Timer		Communicat Interface	ions
44LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
34	P21		ANI1/AV _{REFM}							
35	P20		ANI0/AV _{REFP}							
36	P143		ANI21			SEG34				
37	P142		ANI20			SEG33				
38	P14		ANI19			SEG32				
39	P13		ANI18			SEG31				
40	P12	TOOLTxD			KR0	SEG30	(TI02)/(TO02)		SO00/TxD0	
41	P11	TOOLRxD		(INTP2)	KR1	SEG29			SI00/RxD0	
42	P10			(INTP1)	KR2	SEG28	TI07/TO07		SCK00	
43	P140	PCLBUZ0			KR3	SEG27	ТО00			
44	P141	PCLBUZ1				SEG26	Т100			

Table 1-3. Alternate function of 44-pin products

(3/3)

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

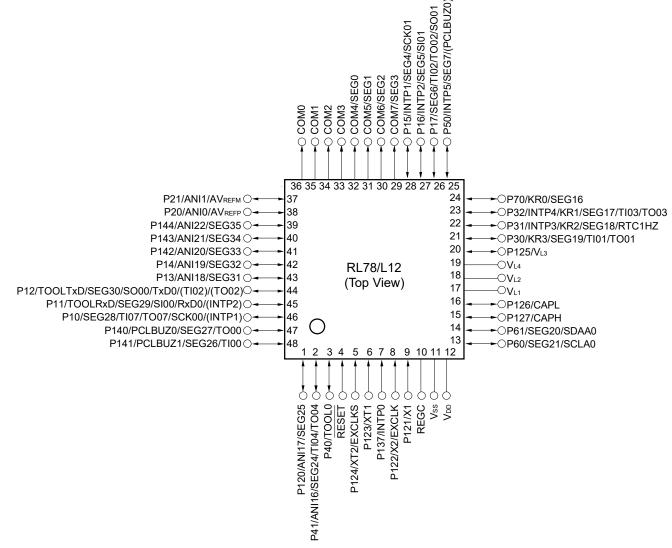
Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



1.3.3 48-pin products

• 48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)



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Table 1-4. Alternate function of 48-pin products

(1/3)

							pin producto			(
Pin No.	I/O	, debug	Analog	НМІ			Timer		Communications Interface	
48LFQFP	Digital port	Power supply, system, clock,	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P41		ANI16			SEG24	TI04/TO04			
3	P40	TOOL0								



Table 1-4. Alternate function of 48-pin products

(2/3)

Pin No.	I/O	debug	Analog	НМІ			-pin products		Communications Interface	(2/3)
48LFQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
4		RESET								
5	P124	XT2/EXCLKS								
6	P123	XT1								
7	P137			INTP0						
8	P122	X2/EXCLK								
9	P121	X1								
10		REGC								
11		V _{SS}								
12		V _{DD}								
13	P60					SEG21				SCLA0
14	P61					SEG20				SDAA0
15	P127					САРН				
16	P126					CAPL				
17						V _{L1}				
18						V _{L2}				
19						V _{L4}				
20	P125					V _{L3}				
21	P30				KR3	SEG19	TI01/TO01			
22	P31			INTP3	KR2	SEG18		RTC1HZ		
23	P32			INTP4	KR1	SEG17	TI03/TO03			
24	P70				KR0	SEG16				
25	P50	(PCLBUZ0)		INTP5		SEG7				
26	P17					SEG6	TI02/TO02		SO01	
27	P16			INTP2		SEG5			SI01	
28	P15			INTP1		SEG4			SCK01	
29						COM7/SEG3				
30						COM6/SEG2				
31						COM5/SEG1				
32						COM4/SEG0				



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 Table 1-4. Alternate function of 48-pin products

(3/3)

Pin No.	I/O	ebug	Analog	НМІ			Timer		Communications Interface	
48LFQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
33						СОМЗ				
34						COM2				
35						COM1				
36						COM0				
37	P21		ANI1/AV _{REFM}							
38	P20		ANI0/AV _{REFP}							
39	P144		ANI22			SEG35				
40	P143		ANI21			SEG34				
41	P142		ANI20			SEG33				
42	P14		ANI19			SEG32				
43	P13		ANI18			SEG31				
44	P12	TOOLTxD				SEG30	(TI02)/(TO02)		SO00/TxD0	
45	P11	TOOLRxD		(INTP2)		SEG29			SI00/RxD0	
46	P10			(INTP1)		SEG28	TI07/TO07		SCK00	
47	P140	PCLBUZ0				SEG27	ТО00			
48	P141	PCLBUZ1				SEG26	Т100			

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



1.3.4 52-pin products

• 52-pin plastic LQFP (10 × 10 mm, 0.65 mm pitch)



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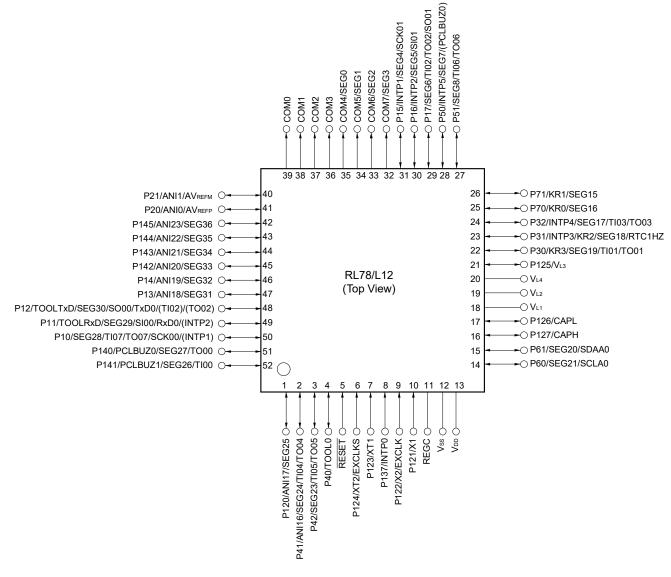


Table 1-5. Alternate function of 52-pin products

(1/3)

Pin No.	I/O	debug	Analog	НМІ			Timer		Communications Interface	i
52LQFP	Digital port	Power supply, system, clock, d	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
1	P120		ANI17			SEG25				
2	P41		ANI16			SEG24	TI04/TO04			



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 Table 1-5. Alternate function of 52-pin products

(2/3)

Pin	I/O	_	Analog	НМІ			Timer		Communications	3
No.		lebuç							Interface	
52LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
3	P42					SEG23	TI05/TO05			
4	P40	TOOL0								
5		RESET								
6	P124	XT2/EXCLKS								
7	P123	XT1								
8	P137			INTP0						
9	P122	X2/EXCLK								
10	P121	X1								
11		REGC								
12		V _{SS}								
13		V _{DD}								
14	P60					SEG21				SCLA0
15	P61					SEG20				SDAA0
16	P127					CAPH				
17	P126					CAPL				
18						V _{L1}				
19						V _{L2}				
20						V _{L4}				
21	P125					V _{L3}				
22	P30				KR3	SEG19	TI01/TO01			
23	P31			INTP3	KR2	SEG18		RTC1HZ		
24	P32			INTP4		SEG17	TI03/TO03			
25	P70				KR0	SEG16				
26	P71				KR1	SEG15				
27	P51					SEG8	TI06/TO06			
28	P50	(PCLBUZ0)		INTP5		SEG7				
29	P17					SEG6	TI02/TO02		SO01	
30	P16			INTP2		SEG5		1	SI01	



 Table 1-5. Alternate function of 52-pin products

(3/3)

Pin No.	I/O	bnq	Analog	НМІ			Timer		Communications Interface	;
52LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
31	P15			INTP1		SEG4			SCK01	
32						COM7/SEG3				
33						COM6/SEG2				
34						COM5/SEG1				
35						COM4/SEG0				
36						COM3				
37						COM2				
38						COM1				
39						COM0				
40	P21		ANI1/AV _{REFM}							
41	P20		ANI0/AV _{REFP}							
42	P145		ANI23			SEG36				
43	P144		ANI22			SEG35				
44	P143		ANI21			SEG34				
45	P142		ANI20			SEG33				
46	P14		ANI19			SEG32				
47	P13		ANI18			SEG31				
48	P12	TOOLTxD				SEG30	(TI02)/(TO02)		SO00/TxD0	
49	P11	TOOLRxD		(INTP2)		SEG29			SI00/RxD0	
50	P10			(INTP1)		SEG28	TI07/TO07		SCK00	
51	P140	PCLBUZ0				SEG27	ТО00			
52	P141	PCLBUZ1				SEG26	TI00			

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

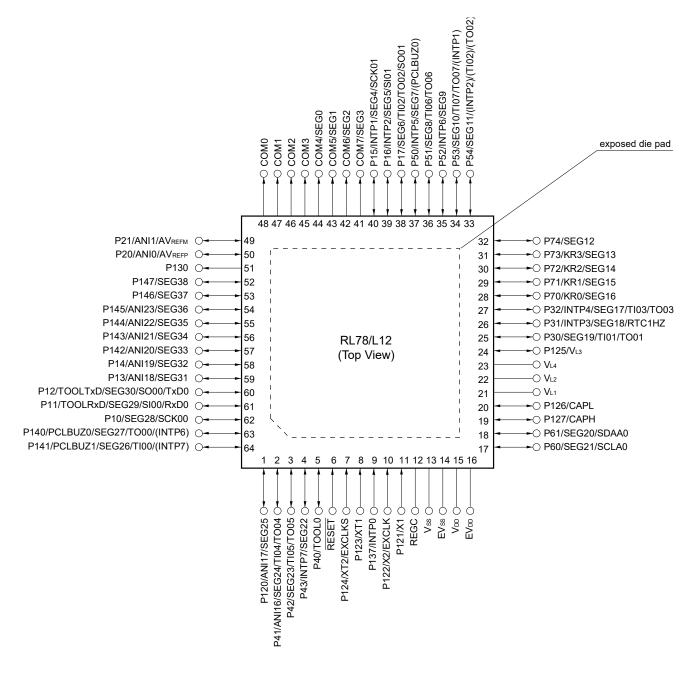
2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.3.5 64-pin products

RL78/L12

• 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm pitch)

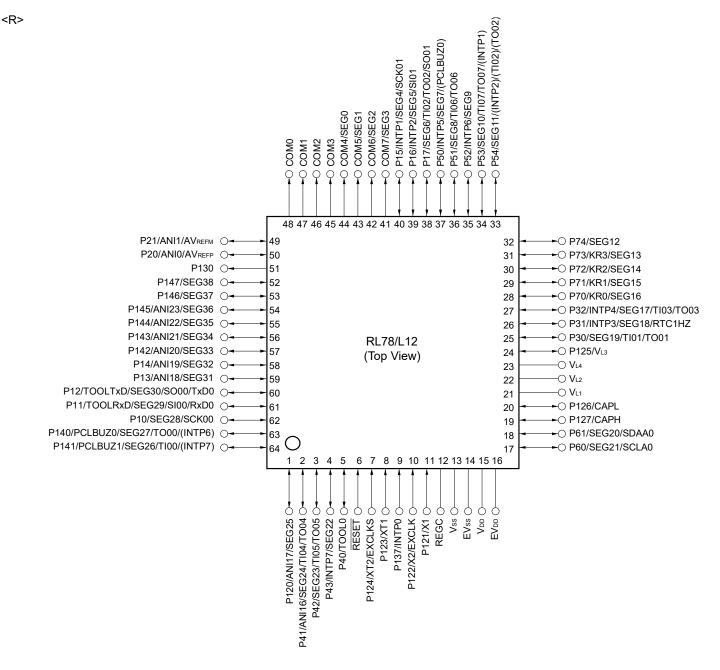
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RENESAS

- 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)
- 64-pin plastic LQFP (12 × 12 mm, 0.65 mm pitch)



<r></r>

Table 1-6. Alternate function of 64-pin products

(1/3)

			Table 1-6. Alternate function of 64-pin products						(1/3		
Pin No.	I/O		Analog	НМІ			Timer		Communications I	nterface	
		debug									
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA	
1	P120		ANI17			SEG25					
2	P41		ANI16			SEG24	TI04/TO04				
3	P42					SEG23	TI05/TO05				
4	P43			INTP7		SEG22					
5	P40	TOOL0									
6		RESET									
7	P124	XT2/EXCLKS									
8	P123	XT1									
9	P137			INTP0							
10	P122	X2/EXCLK									
11	P121	X1									
12		REGC									
13		V _{ss}									
14		EV _{ss}									
15		V _{DD}									
16		EV _{DD}									
17	P60					SEG21				SCLA0	
18	P61					SEG20				SDAA0	
19	P127					CAPH					
20	P126					CAPL					
21						V _{L1}					
22						V _{L2}					
23						V _{L4}					
24	P125					V _{L3}					
25	P30					SEG19	TI01/TO01				
26	P31			INTP3		SEG18		RTC1HZ			
27	P32			INTP4		SEG17	TI03/TO03				
28	P70				KR0	SEG16					



<r></r>

Table 1-6. Alternate function of 64-pin products

(2/3)

Pin	I/O		Analog HMI				Timer		Communications Interface		
No.	1/0		Analog	1 11011			Timer		Communications	Internace	
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA	
29	P71				KR1	SEG15					
30	P72				KR2	SEG14					
31	P73				KR3	SEG13					
32	P74					SEG12					
33	P54			(INTP2)		SEG11	(TI02)/(TO02)				
34	P53			(INTP1)		SEG10	TI07/TO07				
35	P52			INTP6		SEG9					
36	P51					SEG8	TI06/TO06				
37	P50	(PCLBUZ0)		INTP5		SEG7					
38	P17					SEG6	TI02/TO02		SO01		
39	P16			INTP2		SEG5			SI01		
40	P15			INTP1		SEG4			SCK01		
41						COM7/SEG3					
42						COM6/SEG2					
43						COM5/SEG1					
44						COM4/SEG0					
45						COM3					
46						COM2					
47						COM1					
48						COM0					
49	P21		ANI1/AV _{REFM}								
50	P20		ANI0/AV _{REFP}								
51	P130										
52	P147					SEG38					
53	P146					SEG37					
54	P145		ANI23			SEG36					
55	P144		ANI22			SEG35					
56	P143		ANI21			SEG34					



Table 1-6. Alternate function of 64-pin products

(3/3)

										(3/3)
Pin No.	I/O		Analog	НМІ		Timer		Communications Interface		
64HWQFN, 64LFQFP, 64LQFP	Digital port	Power supply, system, clock, debug	A/D converter	Interrupt function	Key Interrupt function	LCD controller/driver	Timer array unit	Real-time clock	Serial array unit	Serial interface IICA
57	P142		ANI20			SEG33				
58	P14		ANI19			SEG32				
59	P13		ANI18			SEG31				
60	P12	TOOLTxD				SEG30			SO00/TxD0	
61	P11	TOOLRxD				SEG29			SI00/RxD0	
62	P10					SEG28			SCK00	
63	P140	PCLBUZ0		(INTP6)		SEG27	ТО00			
64	P141	PCLBUZ1		(INTP7)		SEG26	Т100			

Cautions 1. Make EVss pin the same potential as Vss pin.

- 2. Make V_{DD} pin the same potential as EV_{DD} pin.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).
- Remarks 1. For pin identification, see 1.4 Pin Identification.
 - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD} pins and connect the V_{SS} and EV_{SS} pins to separate ground lines.
 - **3.** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).



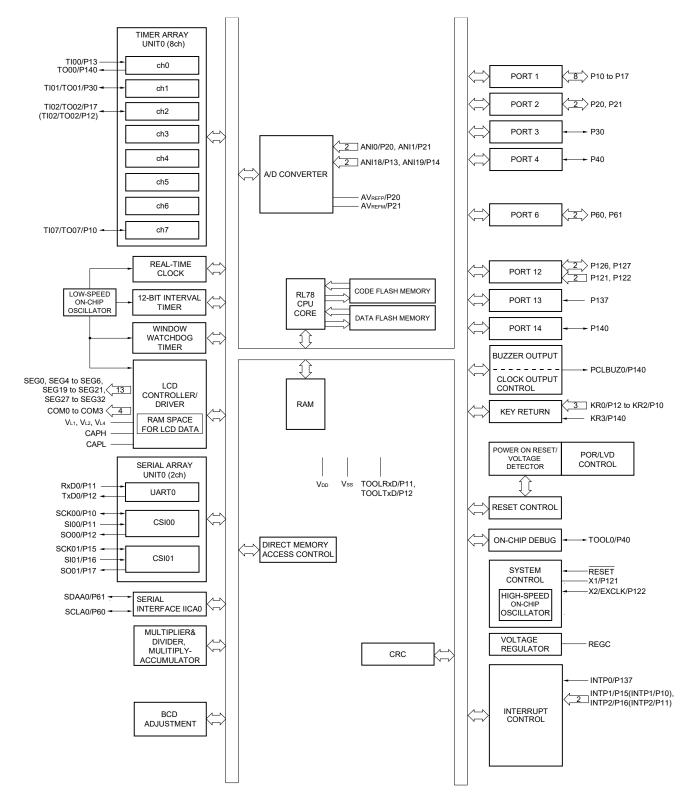
1.4 Pin Identification

<r></r>	ANIO, ANI1,		P130, P137:	Port 13
	ANI16 to ANI23:	Analog Input	P140 to P147:	Port 14
	AVREFM:	Analog Reference	PCLBUZ0, PCLBUZ1:	Programmable Clock
		Voltage Minus		Output/Buzzer Output
	AVREFP:	Analog Reference	REGC:	Regulator Capacitance
		Voltage Plus	RESET:	Reset
	CAPH, CAPL:	Capacitor for LCD	RTC1HZ:	Real-time Clock Correction Clock
	COM0 to COM7,			(1 Hz) Output
	EVDD:	Power Supply for Port	RxD0:	Receive Data
	EVss:	Ground for Port	SCK00, SCK01,	
	EXCLK:	External Clock Input	SCLA0:	Serial Clock Input/Output
		(Main System Clock)	SDAA0:	Serial Data Input/Output
	EXCLKS:	External Clock Input	SEG0 to SEG38:	LCD Segment Output
		(Subsystem Clock)	SI00, SI01:	Serial Data Input
	INTP0 to INTP7:	Interrupt Request From	SO00, SO01:	Serial Data Output
		Peripheral	TI00 to TI07:	Timer Input
	KR0 to KR3:	Key Return	TO00 to TO07:	Timer Output
	P10 to P17:	Port 1	TOOL0:	Data Input/Output for Tool
	P20, P21:	Port 2	TOOLRxD, TOOLTxD:	Data Input/Output for External Device
	P30 to P32:	Port 3	TxD0:	Transmit Data
	P40 to P43:	Port 4	VDD:	Power Supply
	P50 to P54:	Port 5	VL1 to VL4:	LCD Power Supply
	P60, P61:	Port 6	Vss:	Ground
	P70 to P74:	Port 7	X1, X2:	Crystal Oscillator (Main System Clock)
	P120 to P127:	Port 12	XT1, XT2:	Crystal Oscillator (Subsystem Clock)



1.5 Block Diagram

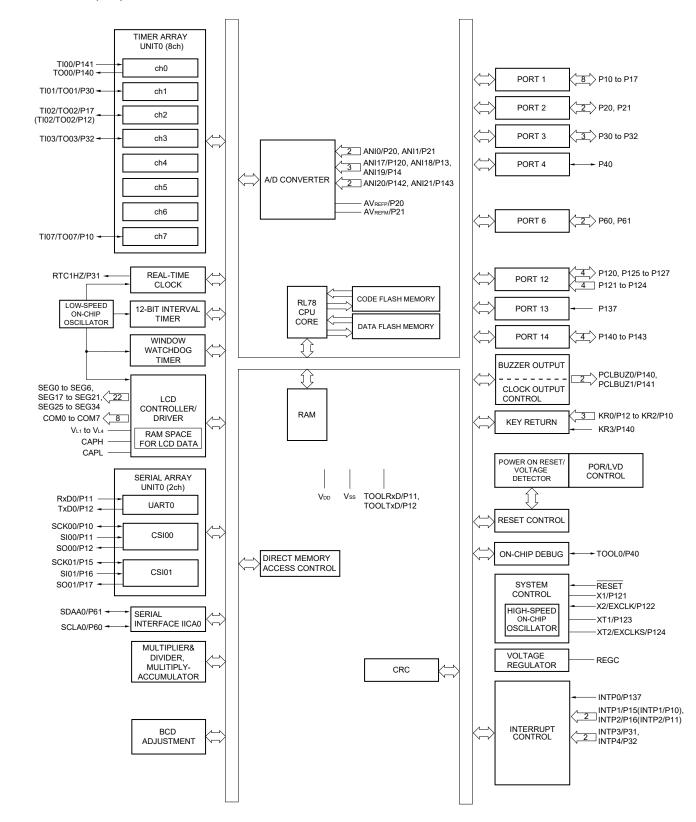
1.5.1 32-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

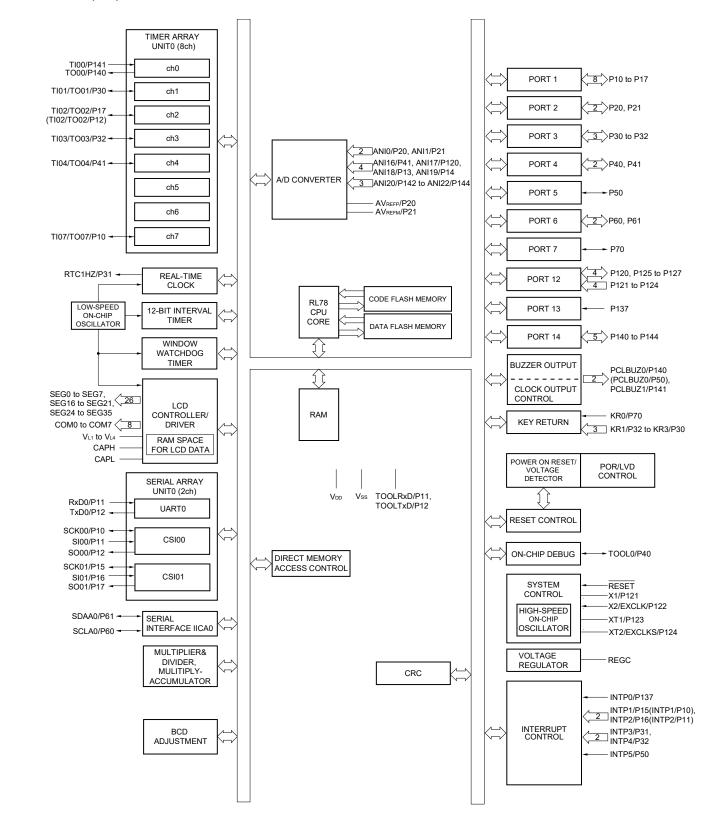


1.5.2 44-pin products



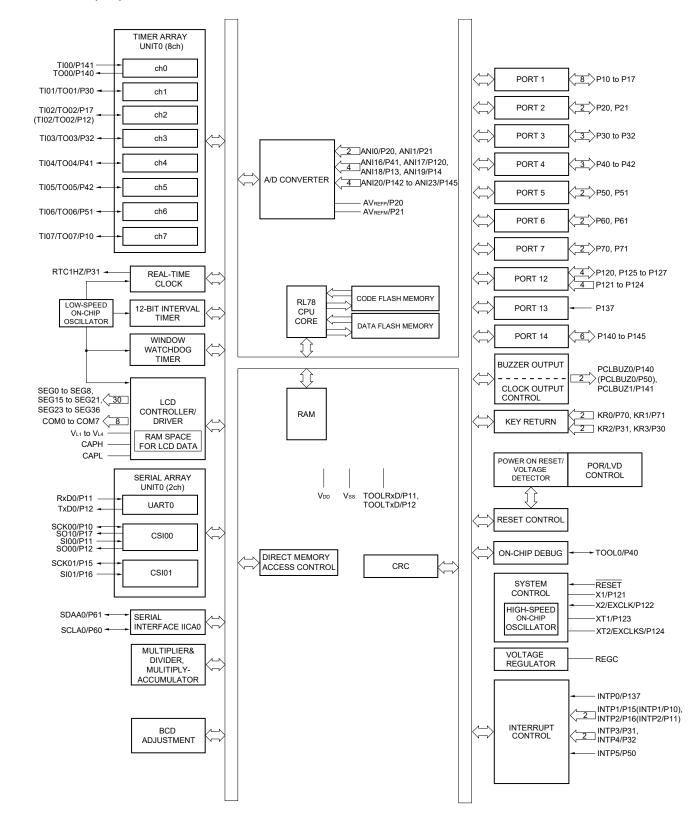
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.3 48-pin products



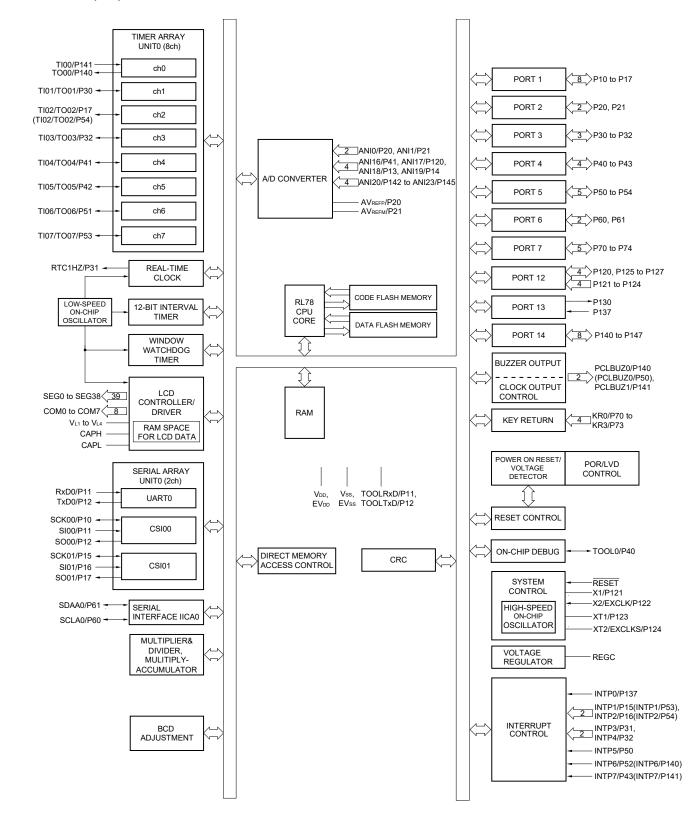
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.4 52-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.5 64-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.6 Outline of Functions

Caution This outline describes the functions at the time when Peripheral I/O redirection register (PIOR) is set to 00H.

		Itom	20 nin	11	10	EQ min	(1 64 pip			
		Item	32-pin	44-pin	48-pin	52-pin	64-pin			
			R5F10RBx	R5F10RFx	R5F10RGx	R5F10RJx	R5F10RLx			
Code flash memory (KB)			8 to 32	8 to 32	8 to 32	8 to 32	16, 32			
Da	ta flash	memory (KB)	2	2	2	2	2			
RA	M (KB)		1, 1.5 ^{Note 1}	1, 1.5 ^{Note 1}	1, 1.5 ^{Note 1}	1, 1.5 ^{Note 1}	1, 1.5 ^{Note 1}			
Мe	mory s	pace	1 MB							
Ma sys clo	stem	High-speed system clock	HS (high-speed HS (high-speed LS (low-speed	(1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) IS (high-speed main) operation: 1 to 20 MHz (V_{DD} = 2.7 to 5.5 V), IS (high-speed main) operation: 1 to 16 MHz (V_{DD} = 2.4 to 5.5 V), S (low-speed main) operation: 1 to 8 MHz (V_{DD} = 1.8 to 5.5 V), V (low-voltage main) operation: 1 to 4 MHz (V_{DD} = 1.6 to 5.5 V)						
		High-speed on-chip oscillator clock	HS (high-speed LS (low-speed	HS (high-speed main) operation: 1 to 24 MHz (V_{DD} = 2.7 to 5.5 V), HS (high-speed main) operation: 1 to 16 MHz (V_{DD} = 2.4 to 5.5 V), LS (low-speed main) operation: 1 to 8 MHz (V_{DD} = 1.8 to 5.5 V), LV (low-voltage main) operation: 1 to 4 MHz (V_{DD} = 1.6 to 5.5 V)						
Subsystem clock			_	,	cillation, external : ′P.): V₀₀ = 1.6 to	subsystem clock i 5.5 V	nput (EXCLKS)			
Low-speed on-chip oscillator clock		Internal oscillation 15 kHz (TYP.): V _{DD} = 1.6 to 5.5 V								
General-purpose register		urpose register	8 bits \times 32 regis	sters (8 bits $ imes$ 8 r	egisters $ imes$ 4 ban	ks)				
Mir	nimum i	nstruction execution time	0.04167 <i>μ</i> s (Hig	gh-speed on-chip	oscillator clock:	fill = 24 MHz ope	eration)			
			0.05 μ s (High-speed system clock: f _{MX} = 20 MHz operation)							
			30.5 μs (Subsystem clock: fsuв = 32.768 kHz operation)							
Ins	truction	set	 Data transfer (8/16 bits) Adder and subtractor/logical operation (8/16 bits) Multiplication (8 bits × 8 bits) Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc. 							
		ber of I/O port pins and ated to drive an LCD	28	40	44	48	58			
	I/O port	Total	20	29	33	37	47			
		CMOS I/O	15	22	26	30	39			
		CMOS input	3	5	5	5	5			
		CMOS output	_	_	_	_	1			
		N-ch open-drain I/O (EV _{DD} tolerance)	2	2	2	2	2			
	Pins d	edicated to drive an LCD	8	11	11	11	11			
LC	D contr	oller/driver	-	boosting methoe are switchable.	d, capacitor split	method, and ext	ernal resistanc			
		Segment signal output	13	22 (18) Note 2	26 (22) Note 2	30 (26) Note 2	39 (35) Note 2			

Notes 1. In the case of the 1 KB, and 1.5 KB, this is 630 bytes when the self-programming function and data flash function is used.

2. The values in parentheses are the number of signal outputs when 8 com is used.

	Item	32-pin	44-pin	48-pin	52-pin	64-pin			
		R5F10RBx	R5F10RFx	R5F10RGx	R5F10RJx	R5F10RLx			
Timer	16-bit timer	8 channels	8 channels 8 channels (with 1 channel remote control output function)						
_	Watchdog timer		L	1 channel		· · ·			
_	Real-time clock (RTC)			1 channel					
	12-bit interval timer (IT)			1 channel					
-	Timer output	4 channels (PWM outputs: 3 ^{Note 1})	5 channels (PWM outputs: 4 ^{Note 1})	6 channels (PWM outputs: 5 ^{Note 1})					
	RTC output	_	1 • 1 Hz (subsys	tem clock: fsub =	= 32.768 kHz)				
Clock output/l	buzzer output	1			2				
		(Main system • 256 Hz, 512 32.768 kHz	 2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: fmain = 20 MHz operation) 256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz, 32.768 kHz (Subsystem clock: fsub = 32.768 kHz operation) 						
8/10-bit resolu	ution A/D converter	4 channels	7 channels	9 channels	10 channels	10 channels			
Serial interfac	ce	Simplified SP	l (CSI): 2 channe	el/UART (LIN-bus	s supported): 1 ch	nannel			
I ² C bus	3	1 channel	1 channel	1 channel	1 channel	1 channel			
Multiplier and accumulator	divider/multiply-	 16 bits × 16 bits = 32 bits (Unsigned or signed) 32 bits ÷ 32 bits = 32 bits (Unsigned) 16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed) 							
DMA controlle	er	2 channels	Γ	T	1	[
Vectored inter	rrupt Internal	23	23	23	23	23			
sources	External	4	6	7	7	9			
Key interrupt				4					
Reset		 Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution ^{Note 2} Internal reset by RAM parity error Internal reset by illegal-memory access 							
Power-on-res	et circuit	Power-on-reset: 1.51 ±0.04 V Power-down-reset: 1.50 ±0.04 V							
Voltage detec	stor	Rising edge : 1.67 V to 4.06 V (14 stages) Falling edge : 1.63 V to 3.98 V (14 stages)							
		Provided							
On-chip debu	g function	Provided							
On-chip debu Power supply	-	Provided V _{DD} = 1.6 to 5.5	V						

Notes 1. The number of PWM outputs varies depending on the setting of channels in use (the number of masters and slaves).

 The illegal instruction is generated when instruction code FFH is executed. Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

2. ELECTRICAL SPECIFICATIONS (A, G: $T_A = -40$ to $+85^{\circ}$ C)

This chapter describes the electrical specifications for the products "A: Consumer applications ($T_A = -40$ to $+85^{\circ}$ C)" and "G: Industrial applications (with $T_A = -40$ to $+85^{\circ}$ C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EVDD, or EVss pin, replace EVDD with VDD, or replace EVss with Vss.



(1/3)

2.1 Absolute Maximum Ratings

Absolute	Maximum	Ratings	(T _A = 25°C)
----------	---------	---------	-------------------------

	i itatings (i	R – 20 0 j		(1/3)
Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	Vdd	V _{DD} = EV _{DD}	-0.5 to +6.5	V
	EVDD	V _{DD} = EV _{DD}	-0.5 to +6.5	V
	EVss		-0.5 to +0.3	V
REGC pin input voltage	VIREGC	REGC	-0.3 to +2.8 and -0.3 to V_DD + $0.3^{\text{Note 1}}$	V
Input voltage	VI1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	-0.3 to EV_DD +0.3 and -0.3 to V_DD + $0.3^{\text{Note 2}}$	V
	V ₁₂	P60, P61 (N-ch open-drain)	-0.3 to EV_{DD} +0.3 and -0.3 to V_{DD} + $0.3^{\text{Note 2}}$	V
	Vı3	P20, P21, P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
Output voltage	V ₀₁	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	-0.3 to EV_DD + 0.3 and -0.3 to V_DD + 0.3 $^{\text{Note 2}}$	<
	V ₀₂	P20, P21	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
Analog input voltage	Vaii	ANI16 to ANI23	-0.3 to EV _{DD} + 0.3 and -0.3 to AV _{REF} (+) + 0.3 Notes 2, 3	V
	Vai2	ANIO, ANI1	-0.3 to V _{DD} + 0.3 and -0.3 to AV _{REF} (+) + 0.3 Notes 2, 3	V

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
 - 2. Must be 6.5 V or lower.
 - **3.** Do not exceed $AV_{REF(+)}$ + 0.3 V in case of A/D conversion target pin.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - **2.** AV_{REF(+)} : + side reference voltage of the A/D converter.
 - 3. Vss : Reference voltage



(2/3)

Absolute Maximum Ratings (T_A = 25°C)

	• •	•			•
Parameter	Symbols		Conditions	Ratings	Unit
LCD voltage	VL1	V∟1 voltage ^{Note 1}		–0.3 to +2.8 and –0.3 to V∟4 + 0.3	V
	VL2	VL2 voltage ^{Note 1}		-0.3 to V _{L4} + 0.3 ^{Note 2}	V
	VL3	VL3 voltage ^{Note 1}		–0.3 to VL4 + 0.3 $^{\rm Note\ 2}$	V
	VL4 VL4 voltage ^{Note 1}			–0.3 to +6.5	V
	VLCAP	CAPL, CAPH vol	tage ^{Note 1}	–0.3 to VL4 + 0.3 $^{\rm Note\ 2}$	V
	Vlout	COM0 to COM7, SEG0 to	External resistance division method	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
		SEG38,	Capacitor split method	-0.3 to V _{DD} + 0.3 ^{Note 2}	
		output voltage	Internal voltage boosting method	-0.3 to V _{L4} + 0.3 ^{Note 2}	

Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the VL1, VL2, VL3, and VL4 pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47 μ F ± 30%) and connect a capacitor (0.47 μ F ± 30%) between the CAPL and CAPH pins.

- 2. Must be 6.5 V or lower.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss : Reference voltage



(3/3)

Absolute Maximum Ratings (T_A = 25°C)

Unit Parameter Conditions Symbols Ratings P10 to P17, P30 to P32, -40 Output current, high IOH1 Per pin mΑ P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147 Total of all pins -70 P10 to P14, P40 to P43, P120, mΑ –170 mA P130, P140 to P147 P15 to P17, P30 to P32, -100 mΑ P50 to P54, P70 to P74, P125 to P127 -0.5 Іон2 Per pin P20, P21 mΑ Total of all pins -1 mΑ P10 to P17, P30 to P32, 40 Output current, low **I**OL1 Per pin mΑ P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147 Total of all pins 70 P10 to P14, P40 to P43, P120, mΑ 170 mA P130, P140 to P147 100 P15 to P17, P30 to P32, mΑ P50 to P54, P60, P61, P70 to P74, P125 to P127 OL2 Per pin P20, P21 1 mΑ 2 Total of all pins mΑ ΤA -40 to +85 °C Operating ambient In normal operation mode temperature In flash memory programming mode Storage temperature Tstg -65 to +150 °C

- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (fx) ^{Note}	Ceramic resonator/ crystal resonator	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	1.0		20.0	MHz
		$2.4~V \leq V_{DD} \leq 2.7~V$	1.0		16.0	MHz
		$1.8~V \leq V_{DD} < 2.7~V$	1.0		8.0	MHz
		$1.6 \text{ V} \le V_{\text{DD}} < 1.8 \text{ V}$	1.0		4.0	MHz
XT1 clock oscillation frequency (f _{XT}) ^{Note}	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. Refer to **2.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

2.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

Oscillators	Parameters		Conditions			MAX.	Unit
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1		24	MHz
High-speed on-chip oscillator		–20 to +85°C	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	-1		+1	%
clock frequency accuracy			$1.6~V \leq V_{\text{DD}} < 1.8~V$	-5		+5	%
		–40 to –20°C	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	-1.5		+1.5	%
			$1.6~V \leq V_{\text{DD}} < 1.8~V$	-5.5		+5.5	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

Notes 1. High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

2. This indicates the oscillator characteristics only. Refer to 2.4 AC Characteristics for instruction execution time.

2.3 DC Characteristics

2.3.1 Pin characteristics

(TA = -40 to +85°C, 1.6 V \leq EVDD = VDD \leq 5.5 V, Vss = EVss = 0 V)

(1/5)

((114)
Items	Symbol		Conditions			TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147					-10.0 Note 2	mA
		Total of P10 to P14, P40 to P43, P120, P130, P140 to P147 (When duty = 70% ^{Note 3})	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			-40.0	mA	
			$2.7~V \leq EV_{\text{DD}} < 4.0~V$			-8.0	mA	
			$1.8~V \leq EV_{\text{DD}} < 2.7~V$			-4.0	mA	
				$1.6~V \leq EV_{\text{DD}} < 1.8~V$			-2.0	mA
		Total of P15 to P17, P30 to P32, P50 to P54, P70 to P74, P125 to P127 (When duty = 70% ^{Note 3})		$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			-60.0	mA
				$2.7~V \leq EV_{\text{DD}} < 4.0~V$			-15.0	mA
				$1.8~V \leq EV_{\text{DD}} < 2.7~V$			-8.0	mA
				$1.6~V \leq EV_{\text{DD}} < 1.8~V$			-4.0	mA
		Total of all pins (When duty = 70% ^{Note 3})					-100.0	mA
	Іон2	P20, P21	Per pin				-0.1	mA
			Total of all pins	$1.6~V \leq V_{\text{DD}} \leq 5.5~V$			-0.2	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} and EV_{DD} pins to an output pin.

- 2. Do not exceed the total current value.
- **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (IOH × 0.7)/(n × 0.01)
- <Example> Where n = 80% and IoH = -40.0 mA

Total output current of pins = $(-40.0 \times 0.7)/(80 \times 0.01) \cong -35.0 \text{ mA}$

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol		Conditions			TYP.	MAX.	Unit
Output current, low ^{Note 1}	lol1	Per pin for P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147					20.0 Note 2	mA
		Per pin for P60, P61					15.0 Note 2	mA
		Total of P10 to P14, P40 to P43, P120, P130, P140 to P147 (When duty = 70% ^{Note 3})		$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			70.0	mA
				$2.7~V \leq EV_{\text{DD}} < 4.0~V$			15.0	mA
				$1.8~V \leq EV_{\text{DD}} < 2.7~V$			9.0	mA
				$1.6~V \leq EV_{\text{DD}} < 1.8~V$			4.5	mA
		Total of P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127 (When duty = 70% ^{Note 3})		$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			80.0	mA
				$2.7~V \leq EV_{\text{DD}} < 4.0~V$			35.0	mA
				$1.8~V \leq EV_{\text{DD}} < 2.7~V$			20.0	mA
		(**********	, , , , , , , , , ,	$1.6~V \leq EV_{\text{DD}} < 1.8~V$			10.0	mA
		Total of all pins (When duty = 70% ^{Note 3})					150.0	mA
	Iol2	P20, P21	Per pin				0.4	mA
			Total of all pins	$1.6~V \leq V_{\text{DD}} \leq 5.5~V$			0.8	mA

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$



- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} and EV_{DD} pins to an output pin.
 - 2. Do not exceed the total current value.
 - **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = $(I_{OH} \times 0.7)/(n \times 0.01)$
- <Example> Where n = 80% and IoL = 70.0 mA

Total output current of pins = $(70.0 \times 0.7)/(80 \times 0.01) \approx 61.25$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



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Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0.8EVDD		EVdd	V
	V _{IH2}	P10, P11, P15, P16 TTL input buffer $4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		2.2		EVDD	V
			TTL input buffer $3.3 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$	2.0		EVDD	V
			TTL input buffer 1.6 V \leq EV _{DD} $<$ 3.3 V	1.50		EVDD	V
	Vінз	P20, P21		0.7V _{DD}		VDD	V
	V _{IH4} P60, P61			0.7EV _{DD}		EVDD	V
	VIH5	P121 to P124, P137, EXCLK, EXCLKS, RESET		0.8Vdd		VDD	V
Input voltage, low	VIL1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	0		0.2EVDD	V	
	VIL2	P10, P11, P15, P16	TTL input buffer $4.0 \text{ V} \leq EV_{\text{DD}} \leq 5.5 \text{ V}$	0		0.8	V
			TTL input buffer $3.3 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$	0		0.5	V
			TTL input buffer $1.6 \text{ V} \leq \text{EV}_{\text{DD}} < 3.3 \text{ V}$	0		0.32	V
	VIL3	P20, P21	0		0.3Vdd	V	
	VIL4	P60, P61	0		0.3EV _{DD}	V	
	VIL5	P121 to P124, P137, EXCLK, EXCLK	0		0.2VDD	V	

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$



Caution The maximum value of VIH of P10, P12, P15, P17 is EVDD, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(4/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	Voh1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$\label{eq:VDD} \begin{array}{l} 4.0 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{OH1}} = -10 \mbox{ mA} \end{array}$	EVDD-1.5			V
		P125 to P127, P130, P140 to P147	$\label{eq:VDD} \begin{array}{l} 4.0 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{OH1}} = -3.0 \mbox{ mA} \end{array}$	EVDD-0.7			V
			$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -2.0 \ mA \end{array} \end{array}$	EVDD-0.6			V
			$\label{eq:logit} \begin{array}{l} 1.8 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{OH1}} = -1.5 \mbox{ mA} \end{array}$	EV _{DD} -0.5			V
			$\label{eq:logit} \begin{array}{l} 1.6 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{OH1}} = -1.0 \mbox{ mA} \end{array}$	EVDD-0.5			\vee
	Voh2	P20, P21	1.6 V \leq Vdd \leq 5.5 V, Іон2 = -100 μ А	Vdd-0.5			V
Output voltage, Vo	Vol1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120,	$\label{eq:VDD} \begin{array}{l} 4.0 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{OL1}} = 20 \mbox{ mA} \end{array}$			1.3	\vee
		P125 to P127, P130, P140 to P147	$\label{eq:VDD} \begin{array}{l} 4.0 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{DL1}} = 8.5 \mbox{ mA} \end{array}$			0.7	V
			$\label{eq:local_def} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 3.0 \ mA \end{array}$			0.6	V
			$eq:local_$			0.4	V
			$eq:local_$			0.4	V
			$1.6 \text{ V} \leq \text{EV}_{\text{DD}} < 5.5 \text{ V},$ $I_{\text{OL1}} = 0.3 \text{ mA}$			0.4	V
	Vol2	P20, P21	$1.6 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ Iol2 = 400 μ A			0.4	V
	Vol3	P60, P61	$\label{eq:VDD} \begin{array}{l} 4.0 \mbox{ V} \leq EV_{\mbox{DD}} \leq 5.5 \mbox{ V}, \\ I_{\mbox{DL3}} = 15.0 \mbox{ mA} \end{array}$			2.0	V
			$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 5.0 \ mA \end{array}$			0.4	V
			$\label{eq:def-loss} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 3.0 \ mA \end{array}$			0.4	V
			$\begin{array}{l} 1.8 \ \text{V} \leq \text{EV}_{\text{DD}} \leq 5.5 \ \text{V}, \\ \text{I}_{\text{OL3}} = 2.0 \ \text{mA} \end{array}$			0.4	V
			$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 5.5 \text{ V},$ Iol3 = 1.0 mA			0.4	V

Caution P10, P12, P15, P17 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



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Items	Symbol	Conditio	ons		MIN.	TYP.	MAX.	Unit
Input leakage current, high	ILIH1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	VI = EVDD)			1	μA
	ILIH2	P20, P21, P137, RESET	VI = VDD				1	μA
	Іцнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VDD	In input port or external clock input			1	μA
				In resonator connection			10	μA
Input leakage current, low	Ilil1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	Vi = EVss				-1	μA
	ILIL2	P20, P21, P137, RESET	VI = Vss				-1	μA
	Ililis	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = Vss	In input port or external clock input			-1	μA
				In resonator connection			-10	μA
On-chip pll-up	Ru1	VI = EVss	SEGxx p	ort				
resistance			2.4 V ≤	$EV_{DD} = V_{DD} \le 5.5 V$	10	20	100	kΩ
			$1.6~\text{V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} < 2.4~\text{V}$		10	30	100	kΩ
	Ru2		Ports other than above (Except for P60, P61, and P130)		10	20	100	kΩ

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

(5/5)

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.3.2 Supply current characteristics

(TA = -40 to +85°C, 1.6 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

(1/3)

Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply	IDD1	Operating	HS (high-speed	f⊪ = 24 MHz ^{Note 3}	Basic	V _{DD} = 5.0 V		1.5		mA
current		mode	main) mode ^{Note 5}		operation	V _{DD} = 3.0 V		1.5		mA
Note 1					Normal	V _{DD} = 5.0 V		3.3	5.0	mA
					operation	V _{DD} = 3.0 V		3.3	5.0	mA
				fıн = 16 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		2.5	3.7	mA
					operation	V _{DD} = 3.0 V		2.5	3.7	mA
			LS (low-speed	fili = 8 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		1.2	1.8	mA
	main) mode ^{Note 5}		operation	V _{DD} = 2.0 V		1.2	1.8	mA		
		LV (low-	fili = 4 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		1.2	1.7	mA	
		voltage main) mode ^{Note 5}		operation	V _{DD} = 2.0 V		1.2	1.7	mA	
			HS (high-speed	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.4	mA
			main) mode ^{Note 5}	V _{DD} = 5.0 V	operation	Resonator connection		3.0	4.6	mA
				f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.4	mA
			V _{DD} = 3.0 V	operation	Resonator connection		3.0	4.6	mA	
			f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		1.8	2.6	mA	
			V _{DD} = 5.0 V	operation	Resonator connection		1.8	2.6	mA	
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		1.8	2.6	mA
			LS (low-speed main) mode ^{Note 5}	V _{DD} = 3.0 V	operation	Resonator connection		1.8	2.6	mA
				f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	1.7	mA
				V _{DD} = 3.0 V	operation	Resonator connection		1.1	1.7	mA
				f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	1.7	mA
				V _{DD} = 2.0 V	operation	Resonator connection		1.1	1.7	mA
			Subsystem	fsue = 32.768 kHz ^{Note 4}	Normal	Square wave input		3.5	4.9	μA
			clock operation	T _A = -40°C	operation	Resonator connection		3.6	5.0	μA
				fsue = 32.768 kHz ^{Note 4}	Normal	Square wave input		3.6	4.9	μA
				T _A = +25°C	operation	Resonator connection		3.7	5.0	μA
				fsue = 32.768 kHz ^{Note 4}	Normal	Square wave input		3.7	5.5	μA
				T _A = +50°C	operation	Resonator connection		3.8	5.6	μA
				fsue = 32.768 kHz ^{Note 4}	Normal	Square wave input		3.8	6.3	μA
				T _A = +70°C operation		Resonator connection		3.9	6.4	μA
				fsue = 32.768 kHz ^{Note 4}	Normal	Square wave input		4.1	7.7	μA
				T _A = +85°C operation		Resonator connection		4.2	7.8	μA

(Notes and Remarks are listed on the next page.)

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- **Notes 1.** Total current flowing into V_{DD} and EV_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD} or Vss, EVss. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation).
- 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V \leq V_DD \leq 5.5 V@1 MHz to 24 MHz

2.4 V \leq V_DD \leq 5.5 V@1 MHz to 16 MHz

- LS (low-speed main) mode: $~~1.8~V \leq V_{\text{DD}} \leq 5.5~V@1~\text{MHz}$ to 8 MHz
- LV (low-voltage main) mode: $~1.6~V \leq V_{\text{DD}} \leq 5.5~V@1~\text{MHz}$ to 4 MHz
- **Remarks 1.** f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C



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Parameter	Symbol			Conditions				MAX.	Unit
Supply	IDD2	HALT	HS (high-speed	fill = 24 MHz ^{Note 4}	V _{DD} = 5.0 V		0.44	1.28	mA
current	Note 2	mode	main) mode Note 6		V _{DD} = 3.0 V		0.44	1.28	mA
Note 1				f⊪ = 16 MHz ^{Note 4}	V _{DD} = 5.0 V		0.40	1.00	mA
					V _{DD} = 3.0 V		0.40	1.00	mA
			LS (low-speed	fill = 8 MHz Note 4	V _{DD} = 3.0 V		260	530	μA
			main) mode ^{Note 6}		V _{DD} = 2.0 V		260	530	μA
			LV (low-voltage main) mode ^{Note 6}	fill = 4 MHz Note 4	V _{DD} = 3.0 V		420	640	μA
					V _{DD} = 2.0 V		420	640	μA
			HS (high-speed	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.00	mA
			main) mode ^{Note 6}	V _{DD} = 5.0 V	Resonator connection		0.45	1.17	mA
				f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.00	mA
			V _{DD} = 3.0 V	Resonator connection		0.45	1.17	mA	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	0.60	mA
				V _{DD} = 5.0 V	Resonator connection		0.26	0.67	mA
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	0.60	mA
				V _{DD} = 3.0 V	Resonator connection		0.26	0.67	mA
			LS (low-speed	f _{MX} = 8 MHz ^{Note 3} ,	Square wave input		95	330	μA
			main) mode ^{Note 6}	V _{DD} = 3.0 V	Resonator connection		145	380	μA
				f _{MX} = 8 MHz ^{Note 3} ,	Square wave input		95	330	μA
			Subsystem	V _{DD} = 2.0 V	Resonator connection		145	380	μA
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.31	0.57	μA
			clock operation	T _A = -40°C	Resonator connection		0.50	0.76	μA
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.37	0.57	μA
				T _A = +25°C	Resonator connection		0.56	0.76	μA
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.46	1.17	μA
				T _A = +50°C	Resonator connection		0.65	1.36	μA
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.57	1.97	μA
				T _A = +70°C	Resonator connection		0.76	2.16	μA
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.85	3.37	μA
			T _A = +85°C	Resonator connection		1.04	3.56	μA	
	Ірдз	D3 STOP mode Note 7	T _A = -40°C		0.17	0.50	μA		
			T _A = +25°C				0.23	0.50	μA
			T _A = +50°C			0.32	1.10	μA	
			T _A = +70°C				0.43	1.90	μA
			T _A = +85°C				0.71	3.30	μA

(TA = -40 to +85°C, 1.6 V \leq EV_DD = V_DD \leq 5.5 V, Vss = EVss = 0 V)

(2/3)

(Notes and $\ensuremath{\textit{Remarks}}$ are listed on the next page.)

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Notes 1. Total current flowing into V_{DD} and EV_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD} or V_{SS}, EV_{SS}. The following points apply in the HS (high-speed main), LS (low-speed main), and LV (low-voltage main) modes.

- The currents in the "TYP." column do not include the operating currents of the peripheral modules.
- The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- 2. During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- 5. When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$ @1 MHz to 24 MHz
 - 2.4 V \leq V_{DD} \leq 5.5 V@1 MHz to 16 MHz
 - LS (low-speed main) mode: $1.8 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}@1 \text{ MHz}$ to 8 MHz
 - LV (low-voltage main) mode: 1.6 V \leq V_DD \leq 5.5 V@1 MHz to 4 MHz
- 7. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. file: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



(T _A = –40 to +	85°C, 1.6	$V \leq EV_{DD} = V_{DD}$	≤ 5.5 V, Vss =	EVss = 0 V)		(3/3)		
Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on- chip oscillator operating current	_{FIL} Note 1					0.20		μA
RTC operating current	IRTC Notes 1, 2, 3	fmain is stopped				0.08		μA
12-bit interval timer current	i⊤ Notes 1, 2, 4					0.08		μA
Watchdog timer operating current	WDT Notes 1, 2, 5	fı∟ = 15 kHz						μA
A/D converter operating current	IADC Notes 1, 6	When conversion at maximum speed		$V_{REFP} = V_{DD} = 5.0 V$ de, AV _{REFP} = V _{DD} = 3.0 V		1.3 0.5	1.7 0.7	mA mA
A/D converter reference voltage current	ADREF Note 1				75.0		μA	
Temperature sensor operating current	TMPS Note 1					75.0		μA
LVD operating current	ILVD Notes 1, 7							μA
Self- programming operating current	FSP Notes 1, 9					2.50	12.20	mA
BGO operating current	IBGO Notes 1, 8					2.00	12.20	mA
LCD operating current	LCD1 Notes 11, 12	External resistance	division method	$V_{DD} = EV_{DD} = 5.0 V$ $V_{L4} = 5.0 V$		0.04	0.20	μA
	LCD2 Note 11	Internal voltage boo	osting method	V _{DD} = EV _{DD} = 5.0 V V _{L4} = 5.1 V (VLCD = 12H)		1.12	3.70	μA
				V _{DD} = EV _{DD} = 3.0 V V _{L4} = 3.0 V (VLCD = 04H)		0.63	2.20	μA
	LCD3 Note 11	Capacitor split method $V_{DD} = EV_{DD} = 3.0 V$ $V_{L4} = 3.0 V$				0.12	0.50	μA
SNOOZE	ISNOZ Note 1	ADC operation	The mode is perfo	rmed Note 10		0.50	0.60	mA
operating current			The A/D conversic performed, Low vo = 3.0 V	1.20	1.44	mA		
		Simplified SPI (CSI)/UART operation				0.70	0.84	mA

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

(3/3)

(Notes and Remarks are listed on the next page.)



- Notes 1. Current flowing to VDD.
 - 2. When high speed on-chip oscillator and high-speed system clock are stopped.
 - 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
 - 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
 - 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.
 - 6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
 - 7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
 - 8. Current flowing only during data flash rewrite.
 - 9. Current flowing only during self programming.
 - **10.** For shift time to the SNOOZE mod.
 - 11. Current flowing only to the LCD controller/driver. The supply current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1 or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.

The TYP. value and MAX. value are following conditions.

- When fsub is selected for system clock, LCD clock = 128 Hz (LCDC0 = 07H)
- 4-Time-Slice, 1/3 Bias Method
- **12.** Not including the current that flows through the external divider resistor when the external resistance division method is used.
- **Remarks 1.** fil: Low-speed on-chip oscillator clock frequency
 - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 3. fcLK: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is $T_A = 25^{\circ}C$



2.4 AC Characteristics

2.4.1 Basic operation

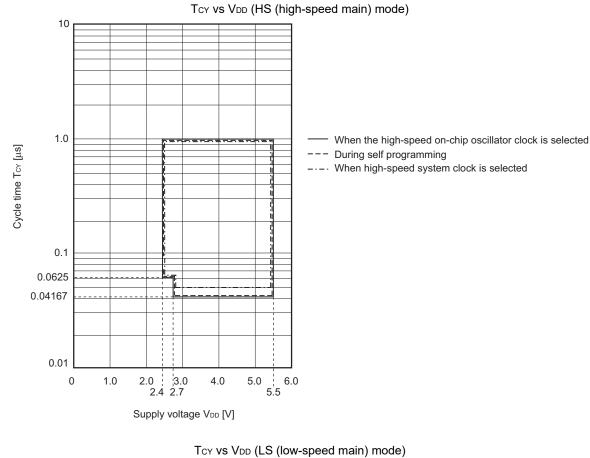
$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

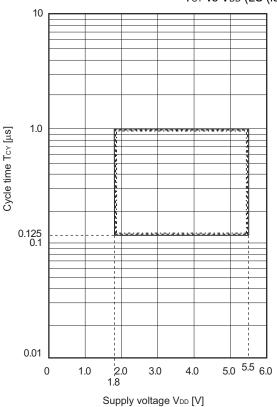
ltems	Symbol		Condition	;	MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсү	Main system	HS (high-spee	d $2.7 V \leq V_{DD} \leq 5.5 V$	0.04167		1	μS
instruction execution time)		clock (fmain)	main) mode	$2.4 V \le V_{DD} < 2.7 V$	0.0625		1	μS
		operation	LV (low voltag main) mode	e $1.6 V \le V_{DD} \le 5.5 V$	0.25		1	μs
			LS (low-speed main) mode	$1.8 V \le V_{DD} \le 5.5 V$	0.125		1	μS
		Subsystem clo operation	ock (fsua)	$1.8 V \le V_{DD} \le 5.5 V$	28.5	30.5	31.3	μS
		In the self	HS (high-spee				1	μs
		programming mode	main) mode	$2.4 V \le V_{DD} < 2.7 V$			1	μS
			LV (low voltag main) mode	e $1.8 V \le V_{DD} \le 5.5 V$	0.25		1	μS
			LS (low-speed main) mode	$1.8 V \le V_{DD} \le 5.5 V$	0.125		1	μs
External main system clock	fex	$2.7~V \leq V_{\text{DD}} \leq$	5.5 V		1.0		20.0	MHz
frequency		$2.4~V \leq V_{\text{DD}} < 2$	2.7 V		1.0		16.0	MHz
		$1.8~V \leq V_{\text{DD}} < 100$	2.4 V		1.0		8.0	MHz
		$1.6 V \le V_{DD} <$	1.8 V		1.0		4.0	MHz
	fexs				32 24		35	kHz
External main system clock input high-level width, low-level width	texh, texl	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$						ns
		$2.4 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$		30			ns	
		$1.8 V \le V_{DD}$ <	2.4 V		60			ns
		$1.6 V \le V_{DD} <$	1.8 V		120			ns
	texhs, texls				13.7			μS
TI00 to TI07 input high-level width, low-level width	tт⊪, tт⊫				1/fмск+10			ns
TO00 to TO07 output frequency	fто	HS (high-spee	ed 4.0 V	$\leq EV_{DD} \leq 5.5 \text{ V}$			16	MHz
		main) mode	2.7 V	\leq EV _{DD} < 4.0 V			8	MHz
			2.4 V	\leq EV _{DD} < 2.7 V			4	MHz
		LS (low-speed mode	I main) 1.8 V	$\leq EV_{\text{DD}} \leq 5.5 \text{ V}$			4	MHz
		LV (low voltag main) mode	e 1.6 V	$\leq EV_{DD} \leq 5.5 V$			2	MHz
PCLBUZ0, PCLBUZ1 output	f PCL	HS (high-spee		$\leq EV_{DD} \leq 5.5 \text{ V}$			16	MHz
frequency		main) mode	2.7 V	\leq EV _{DD} < 4.0 V			8	MHz
				\leq EV _{DD} < 2.7 V			4	MHz
		LS (low-speed mode	,	$\leq EV_{DD} \leq 5.5 V$			4	MHz
		LV (low-voltag main) mode		$\leq EV_{DD} \leq 5.5 V$			4	MHz
		,	-	≤ EV _{DD} < 1.8 V			2	MHz
Interrupt input high-level width, low-level width	tinth, tint∟	INTP0		\leq VDD \leq 5.5 V	1			μS
		INTP1 to INTF		$\leq EV_{DD} \leq 5.5 V$	1			μS
Key interrupt input low-level width	t kr	KR0 to KR3		$\leq EV_{DD} \leq 5.5 V$	250			ns
RESET low-level width	tao		1.6 V	≤ EV _{DD} < 1.8 V	1 10			μS
RESET IOW-IEVEL WIDTN	trsl				10			μS

Remark fmck: Timer array unit operation clock frequency

(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n). n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation



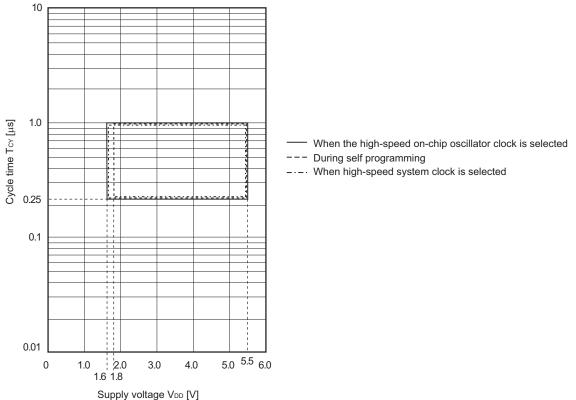


----- When the high-speed on-chip oscillator clock is selected

--- During self programming

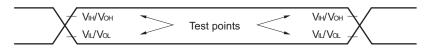
---- When high-speed system clock is selected



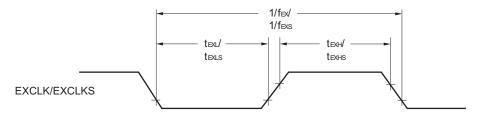


TCY VS VDD (LV (low-voltage main) mode)

AC Timing Test Points

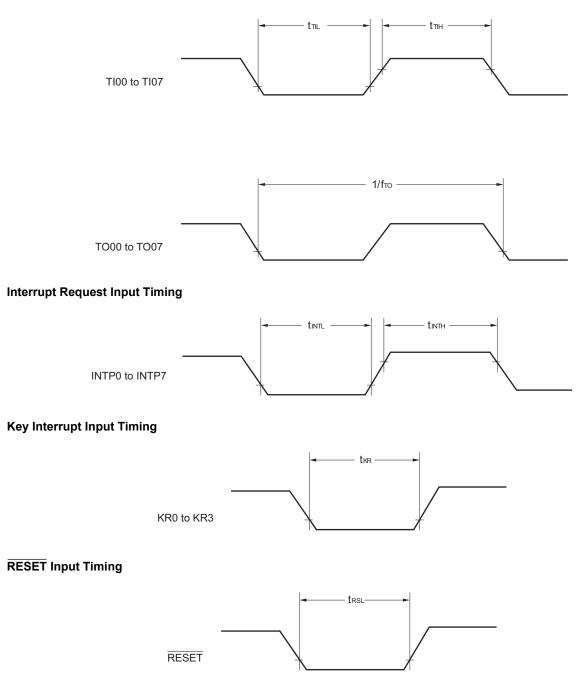


External System Clock Timing





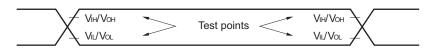
TI/TO Timing





2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

(1) During communication at same potential (UART mode) ($T_A = -40$ to +85°C, 1.6 V $\leq EV_{DD} = V_{DD} \leq 5.5$ V, Vss = EVss = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate Note 1		2.4 \	$V \leq EV_{DD}$ = $V_{DD} \leq 5.5 V$		f мск/6		fмск/6		fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		4.0		1.3		0.6	Mbps
		1.8 \	$1.8 \text{ V} \leq \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \leq 5.5 \text{ V}$				fмск/6		fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ ^{Note 2}				1.3		0.6	Mbps
		1.6 \	$1.6 \text{ V} \leq \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \leq 5.5 \text{ V}$						fмск/6	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2						0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

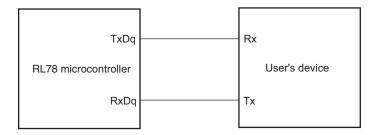
2. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

24 MHz (2.7 V \leq VDD \leq 5.5 V)
16 MHz (2.4 V \leq VDD \leq 5.5 V)
8 MHz (1.8 V \leq VDD \leq 5.5 V)
4 MHz (1.6 V \leq VDD \leq 5.5 V)

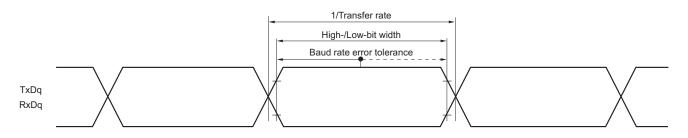
Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).



UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



- **Remarks 1.** q: UART number (q = 0), g: PIM and POM number (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	(Conditions	• •	h-speed Mode	•	/-speed Mode		-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1	2.7 V ≤ E\	$V_{\text{DD}} \leq 5.5 \text{ V}$	167 Note 1		500 Note 1		1000 Note 1		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		250 Note 1		500 Note 1		1000 Note 1		ns
		1.8 V ≤ EV	$V_{\text{DD}} \leq 5.5 \text{ V}$			500 Note 1		1000 Note 1		ns
		1.6 V ≤ EV	$V_{\text{DD}} \leq 5.5 \text{ V}$					1000 Note 1		ns
SCKp high-/low-level width	tĸнı, tĸ∟ı	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		tксү1/2 – 12		tксү1/2 - 50		tксү1/2 - 50		ns
		2.7 V ≤ EV	$\prime_{\text{DD}} \leq 5.5 \text{ V}$	tксү1/2 – 18		tксү1/2 - 50		tксү1/2 – 50		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		tксү1/2 – 38		tксү1/2 - 50		tксү1/2 – 50		ns
		1.8 V ≤ E\	$V_{\text{DD}} \leq 5.5 \text{ V}$			tксү1/2 – 50		tксү1/2 – 50		ns
		$1.6~V \leq EV_{\text{DD}} \leq 5.5~V$						tксү1/2 – 100		ns
SIp setup time (to SCKp↑) Note 2	tsik1	$2.7 \text{ V} \le \text{EV}$	$ m DD \leq 5.5~V$	44		110		110		ns
Note 2		$2.4 \text{ V} \leq \text{EV}$	$V_{\text{DD}} \leq 5.5 \text{ V}$	75		110		110		ns
		1.8 V ≤ EV	$V_{\text{DD}} \leq 5.5 \text{ V}$			110		110		ns
		1.6 V ≤ EV						220		ns
SIp hold time (from SCKp [↑]) Note 3	tksi1	$2.4 \text{ V} \le \text{EV}$	$ m DD \leq 5.5~V$	19		19		19		ns
11016 2		$1.8 V \le EV$	$V_{\text{DD}} \leq 5.5 \text{ V}$			19		19		
		1.6 V ≤ EV	$V_{DD} \leq 5.5 \text{ V}$					19		
Delay time from SCKp↓ to	tkso1	C = 30 pF Note 5	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		25		25		25	ns
SOp output Note 4			$1.8~V \leq EV_{\text{DD}} \leq 5.5~V$				25		25	
			$1.6~V \leq EV_{\text{DD}} \leq 5.5~V$						25	

$(T_{A} = -40 \text{ to } +85^{\circ}\text{C})$	$1.6 V \le EV_{DD} = V_{DD} \le 5$	5.5 V, Vss = EVss = 0 V)
(17 4010.000,		

Notes 1. For CSI00, set a cycle of 2/fмск or longer. For CSI01, set a cycle of 4/fмск or longer.

- **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. C is the load capacitance of the SCKp and SOp output lines.
- Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

(**Remarks** are listed on the next page.)

- **Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM numbers (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00, 01))

(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input) (1/2)

Parameter	Symbol	Conc	litions	HS (high main) MIN.	•	LS (low main) MIN.	•	`	-voltage Mode MAX.	Unit
SCKp cycle time ^{Note 5}	tксү2	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$	20 MHz < fмск	NIIN. 8/fмск		IVIIIN.		IVIIIN.		ns
			 fмск ≤ 20 MHz	6/fмск		6/ f мск		6/fмск		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}$	16 MHz < fмск	8/fмск						ns
			fмск ≤ 16 MHz	6/fмск		6/ f мск		6/fмск		ns
		$2.4~V \leq EV_{DD} \leq 5.5~V$		6/fмск and 500		6/fмск		6/fмск		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} < 2.4 \text{ V}$				6/ f мск		6/fмск		ns
		$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$						6/fмск		ns
SCKp high-/low-level width	tкн2, tкL2	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		tксү2/2 - 7		tксү2/2 – 7		tксү2/2 - 7		ns
		$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$		tксү2/2 - 8		tксү2/2 - 8		tксү2/2 - 8		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 2.7 \text{ V}$		tксү2/2 – 18		tксү2/2 – 18		tксү2/2 – 18		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 2.4 \text{ V}$				tксү2/2 – 18		tксү2/2 – 18		ns
		$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$						tксү2/2 - 66		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsık2	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$		1/fмск + 30		1/fмск + 30		1/fмск + 30		
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 2.4 \text{ V}$				1/fмск + 30		1/fмск + 30		ns
		$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$						1/fмск + 40		ns
SIp hold time (from SCKp↑) ^{Note 2}	tksiz $2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 2.4 \text{ V}$				1/fмск + 31		1/fмск + 31		ns
	$1.6 \text{ V} \le \text{EV}_{\text{DD}} < 1.8 \text{ V}$							1/fмск +		ns
							250			

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

(Notes, Caution, and Remarks are listed on the next page.)



(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input) (2/2)

Parameter	Symbol	Cc	onditions	HS (high- speed main) Mode	LS (low- speed main) Mode	LV (low- voltage main) Mode	Unit	Para meter	Symbol	Conditions
Delay time from SCKp↓ to SOp	tkso2	C = 30 pF ^{Note 4}	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		2/fмск + 44		2/fмск + 110		2/fмск + 110	ns
output ^{Note 3}			$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}$		2/fмск + 44		2/fмск + 110		2/fмск + 110	ns
			$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$		2/fмск + 75		2/fмск + 110		2/fмск + 110	ns
			$1.8 \text{ V} \leq \text{EV}_{\text{DD}} < 2.4 \text{ V}$				2/fмск + 110		2/fмск + 110	ns
		$1.6 \text{ V} \leq \text{EV}_{\text{DD}} < 1.8 \text{ V}$							2/fмск + 220	ns

(TA = -40 to +85°C, 1.6 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

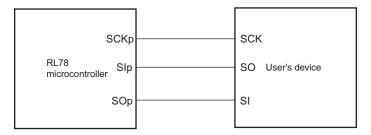
- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SCKp and SOp output lines.
 - 5. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

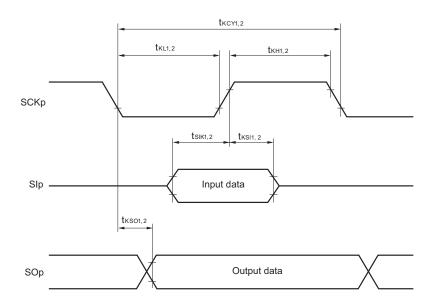
- **Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM number (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



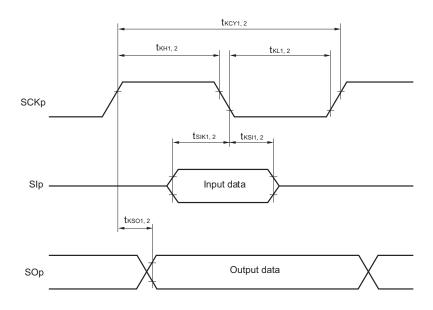
Simplified SPI (CSI) mode connection diagram (during communication at same potential)

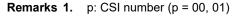


Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)





2. m: Unit number, n: Channel number (mn = 00, 01)



(4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

(1/2)

Parameter	Symbol		Conc	litions	HS (higł main)	•	LS (low main)	•	``	-voltage Mode	Unit
					MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Reception	$\begin{array}{l} 4.0 \ V \leq EV \\ 2.7 \ V \leq V_b \end{array}$,		fмск/6 Note 1		fмск/6 Note 1		fмск/6 Note 1	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3		4.0		1.3		0.6	Mbps
			$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$			fмск/6 Note 1		fмск/6 Note 1		fмск/6 Note 1	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3		4.0		1.3		0.6	Mbps
			2.4 V ≤ EV 1.6 V ≤ Vb	² / _{DD} < 3.3 V, ≤ 2.0 V		fмск/6 Note 1		fмск/6 Note 1		fмск/6 Note 1	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3		4.0		1.3		0.6	Mbps
			$\begin{array}{l} 1.8 \ V \leq EV \\ 1.6 \ V \leq V_b \end{array}$	/ _{DD} < 3.3 V, ≤ 2.0 V				fмск/6 Notes 1, 2		fMCK/6 Notes 1, 2	bps
				Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$				1.3		0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

- **2.** Use it with $EV_{DD} \ge V_b$.
- 3. The maximum operating frequencies of the CPU/peripheral hardware clock (f_{CLK}) are:

 $\begin{array}{ll} \text{HS (high-speed main) mode:} & 24 \ \text{MHz} \ (2.7 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}) \\ & 16 \ \text{MHz} \ (2.4 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}) \\ \text{LS (low-speed main) mode:} & 8 \ \text{MHz} \ (1.8 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}) \\ \text{LV (low-voltage main) mode:} & 4 \ \text{MHz} \ (1.6 \ \text{V} \leq \text{V}_{\text{DD}} \leq 5.5 \ \text{V}) \\ \end{array}$

- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (32-pin to 52pin products)/EVDD tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** V_b[V]: Communication line voltage
 - 2. q: UART number (q = 0), g: PIM and POM number (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)



(4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

(2/2)

Parameter	Symbol		Conditions		h-speed Mode	•	v-speed Mode	•	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Transmission	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V \end{array}$		Note 1		Note 1		Note 1	bps
			Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega, V_b = 2.7 \text{ V}$		2.8 ^{Note 2}		2.8 ^{Note 2}		2.8 ^{Note 2}	Mbps
			$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V$		Note 3		Note 3		Note 3	bps
			Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega$ $V_b = 2.3 \text{ V}$		1.2 ^{Note 4}		1.2 ^{Note 4}		1.2 ^{Note 4}	Mbps
			$2.4 V \le EV_{DD} < 3.3 V,$ $1.6 V \le V_b \le 2.0 V$		Note 6		Note 6		Note 6	bps
			Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 5.5 k Ω V _b = 1.6 V		0.43 ^{Note 7}		0.43 ^{Note 7}		0.43 ^{Note 7}	Mbps
			$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V \end{array}$				Notes 5, 6		Notes 5, 6	bps
			Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega, V_b = 1.6 \text{ V}$				0.43 ^{Note 7}		0.43 ^{Note 7}	Mbps

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

Notes 1. The smaller maximum transfer rate derived by using f_{MCK}/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq EV_{DD} \leq 5.5 V and 2.7 V \leq V_b \leq 4.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 \text{ [\%]}$$

 * This value is the theoretical value of the relative difference between the transmission and reception sides.

2. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

3. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD} < 4.0 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate = $\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$ [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{|\text{Transfer rate} \times 2|} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{|\text{Transfer rate}|}) \times \text{Number of transferred bits}} \times 100 [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- **4.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.
- 5. Use it with $EV_{DD} \ge V_b$.
- **6.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V \leq EV_{DD} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

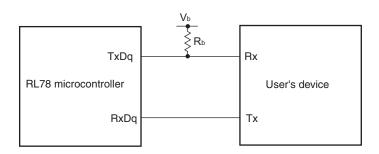
Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

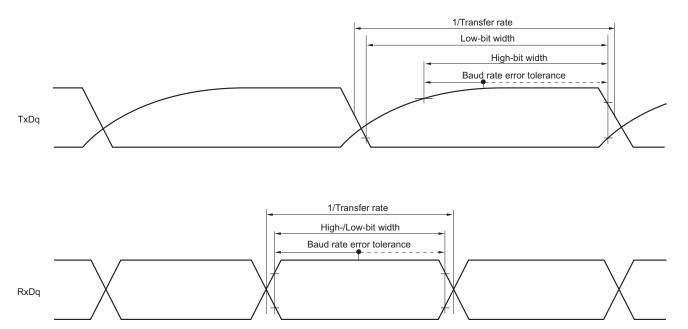
- **7.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 6 above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance (32-pin to 52pin products)/EV_{DD} tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.



UART mode connection diagram (during communication at different potential)



UART mode bit width (during communication at different potential) (reference)



 Remarks 1.
 R_b[Ω]:Communication line (TxDq) pull-up resistance,

 C_b[F]: Communication line (TxDq) load capacitance, V_b[V]: Communication line voltage

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 1)

 fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

(5) Communication at different potential (2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

Parameter	Symbol		Conditions	speed	high- main) ode	LS (low main)	/-speed Mode	-	low- e main) ode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1	tксү1 ≥ 2/f с∟к	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 20 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	200 Note 1		1150 Note 1		1150 Note 1		ns
			$\begin{array}{c} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 20 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$			1150 Note 1		1150 Note 1		ns
SCKp high-level width	t кн1	$4.0~V \leq EV_{\text{DD}}$	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V,	t ксү1/2		t ксү1/2		tксү1/2		ns
		$C_b = 20 \text{ pF}, R_b = 1.4 \text{ k}\Omega$		- 50		- 50		- 50		
			2.7 V \leq EV _{DD} < 4.0 V, 2.3 V \leq V _b \leq 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ			tксү1/2 – 120		tксү1/2 – 120		ns
SCKp low-level width	t ĸ∟1	$4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V,$		t ксү1/2		tксү1/2		t ксү1/2		ns
		C₀ = 20 pF, R	& _b = 1.4 kΩ	- 7		- 50		- 50		
		$2.7 \text{ V} \leq \text{EV}_{\text{DD}}$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}$	< 4.0 V, 2.3 V \leq V _b \leq 2.7 V, R _b = 2.7 kΩ	tксү1/2 – 10		tксү1/2 - 50		tксү1/2 - 50		ns
SIp setup time (to SCKp↑) ^{Note 2}	tsıĸı	4.0 V ≤ EV _{DD} C _b = 20 pF, R	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, R _b = 1.4 kΩ	58		479		479		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}$	< 4.0 V, 2.3 V \leq V _b \leq 2.7 V, $R_b = 2.7 \text{ k}\Omega$	121		479		479		ns
SIp hold time	t _{KSI1}	$4.0 V \le EV_{DD}$	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V,	10		10		10		ns
(from SCKp↑) Note 2		C₀ = 20 pF, R	ω = 1.4 kΩ							
		$2.7 V \le EV_{DD}$	$< 4.0 V, 2.3 V \le V_b \le 2.7 V,$	10		10		10		ns
		C₀ = 20 pF, R	$R_{\rm b}$ = 2.7 k Ω							
Delay time from SCKp↓ to SOp output ^{Note 2}	tkso1	4.0 V ≤ EV _{DD} C _b = 20 pF, R	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, R _b = 1.4 kΩ		60		60		60	ns
		2.7 V ≤ EV _{DD} C _b = 20 pF, R	< 4.0 V, 2.3 V \leq V _b \leq 2.7 V, R _b = 2.7 kΩ		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 3}	tsıĸı	$4.0 \text{ V} \leq \text{EV}_{\text{DD}}$ $C_{\text{b}} = 20 \text{ pF}, \text{ R}$	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V, R _b = 1.4 kΩ	23		110		110		ns
			< 4.0 V, 2.3 V \leq V _b \leq 2.7 V, R_b = 2.7 kΩ	33		110		110		ns
SIp hold time (from SCKp↓) ^{Note 3}	tksi1	4.0 V ≤ EV _{DD}	$\begin{split} &C_b = 20 \text{ pF}, \text{R}_b = 2.7 \text{k}\Omega \\ &4.0 \text{V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{V}, 2.7 \text{V} \leq \text{V}_b \leq 4.0 \text{V}, \\ &C_b = 20 \text{pF}, \text{R}_b = 1.4 \text{k}\Omega \end{split}$			10		10		ns
		$\begin{aligned} & C_{D} = 20 \ \text{pr}, \ \text{rw} = 1.4 \ \text{kg} 2 \\ \\ & 2.7 \ \text{V} \leq \text{EV}_{\text{DD}} < 4.0 \ \text{V}, \ 2.3 \ \text{V} \leq \text{V}_{\text{b}} \leq 2.7 \ \text{V}, \\ & C_{\text{b}} = 20 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{aligned}$		10		10		10		ns
Delay time from SCKp↑ to SOp output ^{Note 3}	tkso1	-	\leq 5.5 V, 2.7 V \leq V _b \leq 4.0 V,		10		10		10	ns
·			< 4.0 V, 2.3 V \leq V _b \leq 2.7 V,		10		10		10	ns

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

(Notes, Caution and Remarks are listed on the next page.)



- Notes 1. For CSI00, set a cycle of 2/fмск or longer. For CSI01, set a cycle of 4/fмск or longer.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - **3.** When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)



(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/3)

Parameter	Symbol		Conditions	speed	high- main) ode	`	/-speed Mode	voltage		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy1	tксү1 ≥ 4/f с∟к		300		1150		1150		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		500		1150		1150		ns
			$\label{eq:2.4} \begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1150		1150		1150		ns
			$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note}}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			1150		1150		ns
SCKp high-level width	tкнı	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 8 \\ C_b = 30 \ pF, \ R_b = 8 \end{array}$	5.5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	tксү1/2 - 75		tксү1/2 - 75		tксү1/2 – 75		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 1$	4.0 V, 2.3 V ≤ V₅ ≤ 2.7 V, = 2.7 kΩ	tксү1/2 – 170		tксү1/2 – 170		tксү1/2 – 170		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 30 \text{ pF}, R_{\text{b}} = 30 \text{ pF}$	3.3 V, 1.6 V ≤ V₅ ≤ 2.0 V, = 5.5 kΩ	tксү1/2 - 458		tксү1/2 - 458		tксү1/2 - 458		ns
		$1.8 V \le EV_{DD} < 30 C_b = 30 pF, R_b = 30 PF$	3.3 V, 1.6 V ≤ V _b ≤ 2.0 V ^{Note} , = 5.5 kΩ			tксү1/2 - 458		tксү1/2 - 458		ns
SCKp low-level width	tĸ∟ı	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq S \\ C_b = 30 \ pF, \ R_b = S \end{array}$	5.5 V, 2.7 V ≤ V₅ ≤ 4.0 V, = 1.4 kΩ	tксү1/2 – 12		tксү1/2 - 50		tксү1/2 - 50		ns
			$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$			tксү1/2 - 50		tксү1/2 - 50		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 3$	3.3 V, 1.6 V ≤ V₅ ≤ 2.0 V, = 5.5 kΩ	tксү1/2 - 50		tксү1/2 - 50		tксү1/2 - 50		ns
			$\label{eq:VDD} \begin{split} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V \ ^{\text{Note}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$			tксү1/2 - 50		tксү1/2 – 50		ns

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

Note Use it with $EV_{DD} \ge V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (32-pin to 52pin products)/EV_{DD} tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/3)

Parameter	Symbol	Conditions	speed	high- I main) ode	speed	(low- main) ode	voltage	low- e main) ode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑) ^{Note 1}	tsiĸ1	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	81		479		479		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	177		479		479		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	479		479		479		ns
					479		479		ns
SIp hold time (from SCKp↑) ^{Note 1}	tksi1	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	19		19		19		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	19		19		19		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	19		19		19		ns
					19		19		ns
Delay time from SCKp↓ to SOp output ^{Note 1}	tkso1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$		100		100		100	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		195		195		195	ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		483		483		483	ns
						483		483	ns
SIp setup time (to SCKp↓) ^{Note 2}	tsiĸ1	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \; 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	44		110		110		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	44		110		110		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	110		110		110		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note } 3}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$			110		110		ns

(TA = -40 to +85°C, 1.8 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EV_{ss} = 0 V)

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. Use it with $EV_{DD} \ge V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (32-pin to 52pin products)/EV_{DD} tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (3/3)

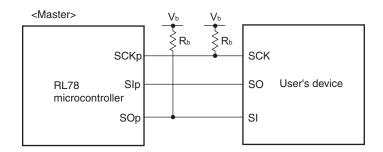
Parameter	Symbol	Conditions	speed	high- ∣main)	speed	,	voltage	low- e main)	Unit
			MIN.	ode MAX.	MIN.	ode MAX.	MIN.	ode MAX.	
SIp hold time (from SCKp↓) ^{Note 2}	tksi1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	19		19		19		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V, \\ C_{b} = 30 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$	19		19		19		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	19		19		19		ns
					19		19		ns
Delay time from SCKp↑ to SOp output ^{Note 2}	tkso1	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		25		25		25	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		25		25		25	ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$		25		25		25	ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note } 3}, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$				25		25	ns

(TA = -40 to +85°C, 1.8 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EV_{SS} = 0 V)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. Use it with $EV_{DD} \ge V_b$.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32-pin to 52pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.



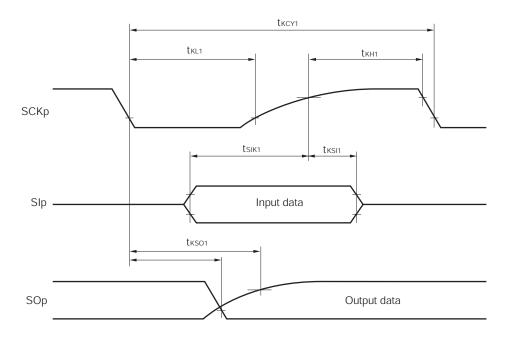
Simplified SPI (CSI) mode connection diagram (during communication at different potential)



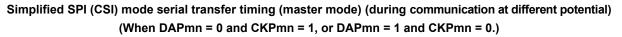
- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - **2.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
 - 3. fMCK: Serial array unit operation clock frequency

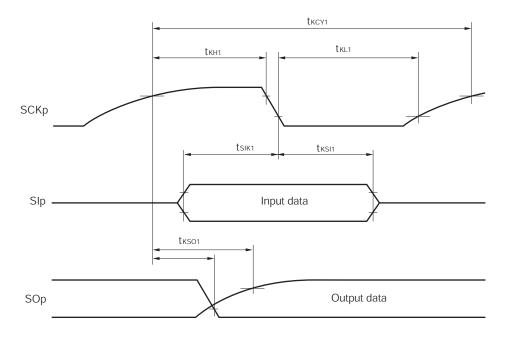
(Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)





Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





Remark p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Con	ditions	speed mo	high- main) ode	main)		voltage mo	(low- e main) ode	Unit
	-		1	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 1	t ксү2	$4.0 V \le EV_{DD} \le 5.5 V$,	20 MHz < fmck \leq 24 MHz	12/fмск						ns
		$2.7 V \le V_b \le 4.0 V$	8 MHz < fмск ≤ 20 MHz	10/fмск						ns
			4 MHz < fмск ≤ 8 MHz	8/fмск		16/fмск				ns
			fмск ≤ 4 MHz	6/fмск		10/fмск		10/fмск		ns
		$2.7 V \le EV_{DD} < 4.0 V$,	20 MHz < $f_{MCK} \le 24$ MHz	16/fмск						ns
		$2.3 V \le V_b \le 2.7 V$	16 MHz < fmck \leq 20 MHz	14/fмск						ns
			8 MHz < fмск ≤ 16 MHz	12/fмск						ns
			4 MHz < fмск ≤ 8 MHz	8/fмск		16/fмск				ns
			fмск ≤4 MHz	6/fмск		10/fмск		10/fмск		ns
		$2.4~V \leq EV_{DD} < 3.3~V,$	$20 \text{ MHz} < f_{\text{MCK}} \le 24 \text{ MHz}$	36/fмск						ns
		$1.6 V \le V_b \le 2.0 V$	$16 \text{ MHz} < f_{\text{MCK}} \le 20 \text{ MHz}$	32/fмск						ns
			$8 \text{ MHz} < f_{\text{MCK}} \le 16 \text{ MHz}$	26/fмск						ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	16/fмск		16/fмск				ns
			$f_{MCK} \! \leq \! 4 \; MHz$	10/ f мск		10/f мск		10/f мск		ns
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$	4 MHz < fмск ≤ 8 MHz			16/fмск				ns
		$1.6~V \le V_b \le 2.0~V^{\text{Note}\text{2}}$	fмск≤4 MHz			10/f мск		10/fмск		ns
SCKp high-/low-level width	level t_{KH2} , $4.0 V \le E_{V}$	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$	$V, 2.7 \text{ V} \le V_b \le 4.0 \text{ V}$	tксү2/2 – 12		tксү2/2 - 50		tксү2/2 - 50		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 4.0 \text{ V}$	$V, 2.3 V \le V_b \le 2.7 V$	tксү2/2 – 18		tксү2/2 - 50		tксү2/2 – 50		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V}$	$V_{,} 1.6 V \le V_{b} \le 2.0 V_{b}$	tксү2/2 - 50		tксү2/2 - 50		tксү2/2 - 50		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{DD} < 3.3 \ V \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{No}} \end{array}$				tксү2/2 - 50		tксү2/2 - 50		ns
SIp setup time (to SCKp↑) ^{Note 3}	tsik2	$4.0 \text{ V} \le \text{EV}_{\text{DD}} < 5.5 \text{ V}$	/, 2.7 V \le V _b \le 4.0 V	1/fмск + 20		1/fмск + 30		1/fмск + 30		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}$	/, 2.3 V \leq V _b \leq 2.7 V	1/fмск + 20		1/fмск + 30		1/f _{мск} + 30		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V}$	$V_{,} 1.6 V \le V_{b} \le 2.0 V_{,}$	1/fмск + 30		1/fмск + 30		1/f _{мск} + 30		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{\text{DD}} < 3.3 \ V \\ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V^{\text{No}} \end{array}$				1/fмск + 30		1/fмск + 30		ns
SIp hold time (from SCKp↑) ^{Note 4}	tksi2	$4.0 \text{ V} \leq \text{EV}_{\text{DD}} < 5.5 \text{ V}$	$V, 2.7 V \le V_b \le 4.0 V$	1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0$		/, 2.3 V \leq V _b \leq 2.7 V	1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
			/, 1.6 V \le V _b \le 2.0 V	1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
		$\begin{array}{l} 1.8 \ V \leq EV_{\text{DD}} < 3.3 \ V \\ 1.6 \ V \leq V_{b} \leq 2.0 \ V^{\text{No}} \end{array}$			1/fмск + 31		1/fмск + 31		ns	

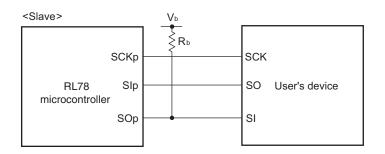
(Notes, Caution and Remarks are listed on the next page.)

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

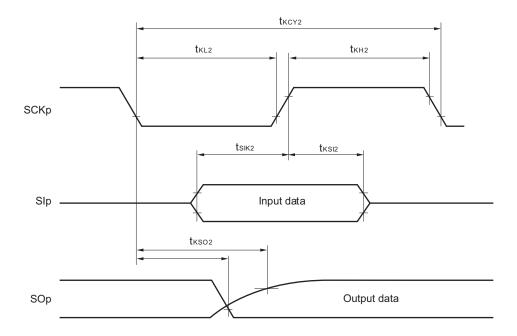
(T _A = -40 to +85°	C, 1.8 V ≤	$EV_{DD} = V_{DD} \le 5.5 V$, $V_{SS} = EV_{SS} = 0$	ss = 0 V)						(2/2)
Parameter	Symbol	Conditions	speed	(high- I main) ode	``	/-speed mode	voltage	(low- e main) ode	Unit
			MIN. MAX		MIN.	MAX.	MIN.	MAX.	
Delay time from SCKp↓ to SOp output ^{Note 5}	tkso2			2/fмск + 120		2/fмск + 573		2/fмск + 573	ns
		$\label{eq:V_def} \begin{split} 2.7 \ V &\leq EV_{\text{DD}} < 4.0 \ \text{V}, \ 2.3 \ \text{V} \leq V_b \leq 2.7 \ \text{V}, \\ C_b &= 30 \ \text{pF}, \ R_b = 2.7 \ \text{k}\Omega \end{split}$		2/fмск + 214		2/fмск + 573		2/fмск + 573	ns
		$\label{eq:V_def} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns
		$ \begin{split} 1.8 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split} $				2/fмск + 573		2/fмск + 573	ns

- Notes 1. Transfer rate in the SNOOZE mode : MAX. 1 Mbps
 - **2.** Use it with $EV_{DD} \ge V_b$.
 - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 5. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[†]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance (32-pin to 52-pin products)/EVDD tolerance (64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

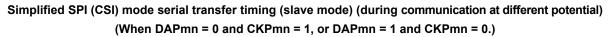
Simplified SPI (CSI) mode connection diagram (during communication at different potential)

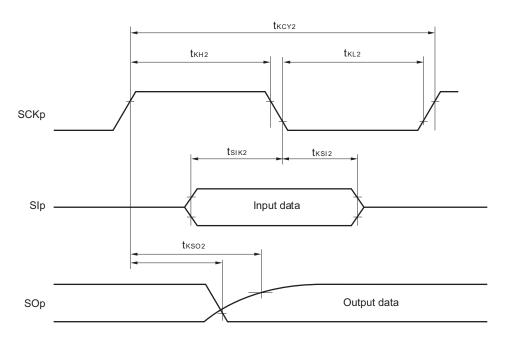


- **Remarks 1.** $R_b[\Omega]$:Communication line (SOp) pull-up resistance, $C_b[F]$: Communication line (SOp) load capacitance, Vb[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
 - 3. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





Remark p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

2.5.2 Serial interface IICA

(1) I²C standard mode

(TA = -40 to +85°C, 1.6 V \leq EV_DD = V_DD \leq 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	1		speed	high- l main) ode		/-speed Mode	voltage	(low- e main) ode	Unit
				MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscl	Standard	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$	0	100	0	100	0	100	kHz
		mode: fclk≥ 1 MHz	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$	0	100	0	100	0	100	
			$1.8~V \leq EV_{\text{DD}} \leq 5.5~V$			0	100	0	100	
			$1.6~V \leq EV_{\text{DD}} \leq 5.5~V$					0	100	
Setup time of restart condition	tsu:sta	$2.7 V \le EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			4.7		4.7		
		$1.6 V \le EV_{DD}$	≤ 5.5 V					4.7		
Hold time Note 1	thd:sta	$2.7 \text{ V} \leq EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			4.0		4.0		
		$1.6 V \le EV_{DD}$	≤ 5.5 V					4.0		
Hold time when SCLA0 = "L"	tLow	$2.7 \text{ V} \leq EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			4.7		4.7		
		$1.6 V \le EV_{DD}$	≤ 5.5 V					4.7		
Hold time when SCLA0 = "H"	tніgн	$2.7 \text{ V} \leq EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		μs
		$2.4 \text{ V} \leq EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			4.0		4.0		
		$1.6 V \le EV_{DD}$	≤ 5.5 V					4.0		
Data setup time (reception)	tsu:dat	$2.7 V \leq EV_{DD}$	≤ 5.5 V	250		250		250		ns
		$2.4 V \le EV_{DD}$	≤ 5.5 V	250		250		250		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			250		250		
		$1.6 V \le EV_{DD}$	≤ 5.5 V					250		
Data hold time (transmission) ^{Note 2}	thd:dat	$2.7 \text{ V} \leq EV_{DD}$	≤ 5.5 V	0	3.45	0	3.45	0	3.45	μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	0	3.45	0	3.45	0	3.45	
		$1.8 V \le EV_{DD}$	≤ 5.5 V			0	3.45	0	3.45	
		$1.6 V \le EV_{DD}$	≤ 5.5 V					0	3.45	
Setup time of stop condition	tsu:sto	$2.7 V \leq EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	4.0		4.0		4.0		
		$1.8~V \leq EV_{\text{DD}} \leq 5.5~V$				4.0		4.0		
		$1.6 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$						4.0		
Bus-free time	t BUF	$2.7 \text{ V} \leq EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		μs
		$2.4 V \le EV_{DD}$	≤ 5.5 V	4.7		4.7		4.7		
		$1.8 V \le EV_{DD}$	≤ 5.5 V			4.7		4.7		
		$1.6 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$						4.7		

(Notes and Remark are listed on the next page.)

- <R> Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.
 - 2. The maximum value (MAX.) of the:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
 - **Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 k Ω



(2) I²C fast mode

(TA = -40 to +85°C, 1.6 V \leq EV_DD = V_DD \leq 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol		Conditions	speed	high- I main) ode	•	/-speed Mode	voltage	low- e main) ode	Unit
				MIN.	MAX.	MIN.	MIN.	MAX.	MIN.	
SCLA0 clock frequency	fscL	Fast mode:	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$	0	400	0	400	0	400	kHz
		fc∟κ≥ 3.5 MHz	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$	0	400	0	400	0	400	
			$1.8~V \leq EV_{\text{DD}} \leq 5.5~V$			0	400	0	400	
Setup time of restart condition	tsu:sta	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$				0.6		0.6		
Hold time Note 1	thd:sta	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		
		$1.8 \ V \leq EV_{\text{DD}}$	≤ 5.5 V			0.6		0.6		
Hold time when SCLA0 = "L"	t LOW	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		
		$1.8 \ V \leq EV_{\text{DD}}$	≤ 5.5 V			1.3		1.3		
Hold time when SCLA0 = "H"	t HIGH	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		
		$1.8 \ V \leq EV_{\text{DD}}$	$\leq 5.5 \text{ V}$			0.6		0.6		
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	100		100		100		ns
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	100		100		100		
		$1.8 \ V \leq EV_{\text{DD}}$	$\leq 5.5 \text{ V}$			100		100		
Data hold time (transmission) ^{Note 2}	thd:dat	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	0	0.9	0	0.9	0	0.9	μs
		$2.4~V \leq EV_{\text{DD}}$	$\leq 5.5 \text{ V}$	0	0.9	0	0.9	0	0.9	
		$1.8 \ V \leq EV_{\text{DD}}$	$\leq 5.5 \text{ V}$			0	0.9	0	0.9	
Setup time of stop condition	tsu:sto	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	0.6		0.6		0.6		
		$1.8 \ V \leq EV_{\text{DD}}$	$\leq 5.5 \text{ V}$			0.6		0.6		
Bus-free time	t BUF	$2.7~V \leq EV_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		μs
		$2.4~V \leq EV_{\text{DD}}$	≤ 5.5 V	1.3		1.3		1.3		
		$1.8 \ V \leq EV_{\text{DD}}$			1.3		1.3			

<R>

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: C_b = 320 pF, R_b = 1.1 k Ω



(3) I^2C fast mode plus

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

Parameter	Symbol	Cor	ditions		h-speed Mode		LS (low-speed main) Mode		LV (low-voltage main) Mode			
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.			
SCLA0 clock frequency	fscL	Fast mode plus: fc∟k ≥ 10 MHz	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$	0	1000		-	_	_	kHz		
Setup time of restart condition	tsu:sta	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		0.26		—		—		μs		
Hold time ^{Note 1}	thd:sta	$2.7~V \leq EV_{\text{DD}} \leq 5.5$	5 V	0.26		—						μs
Hold time when SCLA0 = "L"	t∟ow	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.5$	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.5 \text{ V}$			—		_		μs		
Hold time when SCLA0 = "H"	tніgн	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.5$	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			_		—		μs		
Data setup time (reception)	tsu:dat	$2.7 \text{ V} \leq EV_{DD} \leq 5.5$	5 V	50		_	-	_	_	μs		
Data hold time (transmission) ^{Note 2}	thd:dat	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5$	5 V	0	0.45	_	_	_	_	μS		
Setup time of stop condition	tsu:sto	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5$	$7 V \leq EV_{DD} \leq 5.5 V$ $7 V \leq EV_{DD} \leq 5.5 V$ $7 V \leq EV_{DD} \leq 5.5 V$				-		_	μs		
Bus-free time	tbuf	$2.7 \text{ V} \leq EV_{DD} \leq 5.5$	5 V	0.5		_	-	_	_	μS		

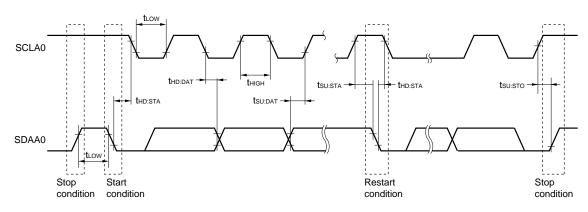
Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

- Caution The values in the above table are applied even when bit 2 (PIOR2) in the peripheral I/O redirection register (PIOR) is 1. At this time, the pin characteristics (IOH1, IOL1, VOH1, VOL1) must satisfy the values in the redirect destination.
- **Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode plus: C_b = 120 pF, R_b = 1.1 k Ω

IICA serial transfer timing





2.6 Analog Characteristics

2.6.1 A/D converter characteristics

Classification of A/D converter characteristics

		Reference Voltage						
	Reference voltage (+) = AVREFP	Reference voltage (+) = V _{DD}	Reference voltage (+) = VBGR					
Input channel	Reference voltage (-) = AVREFM	Reference voltage (-) = Vss	Reference voltage (-) = AVREFM					
ANIO, ANI1	_	Refer to 2.6.1 (3).	Refer to 2.6.1 (4) .					
ANI16 to ANI23	Refer to 2.6.1 (2) .							
Internal reference voltage Temperature sensor output voltage	Refer to 2.6.1 (1) .		_					

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : internal reference voltage, and temperature sensor output voltage

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, 1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = 10^{\circ}\text{C}, 10^{\circ}\text{C},$
AVREFP, Reference voltage (–) = AVREFM = 0 V)

Parameter	Symbol	Condit	ions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		1.2	±3.5	LSB
		AV _{REFP} = V _{DD} ^{Note 3}	$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 4}}$		1.2	±7.0	LSB
Conversion time	t CONV	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal reference	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
		sensor output voltage (HS	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	E _{zs}	10-bit resolution	$1.8~V \leq AV_{REFP} \leq 5.5~V$			±0.25	%FSR
		AV _{REFP} = V _{DD} Note 3	$1.6~V \leq AV_{\text{REFP}} \leq 5.5~V^{\text{Note 4}}$			±0.50	%FSR
Full-scale error ^{Notes 1, 2}	E _{FS}	10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.25	%FSR
		AV _{REFP} = V _{DD} ^{Note 3}	$1.6~V \leq AV_{\text{REFP}} \leq 5.5~V^{\text{Note 4}}$			±0.50	%FSR
Integral linearity	ILE	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±2.5	LSB
error ^{Note 1}		AV _{REFP} = V _{DD} ^{Note 3}	$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 4}}$			±5.0	LSB
Differential linearity	DLE	sensor output voltage (HS (high-speed main) mode)1.8 10-bit resolution AVREFP = V_{DD} Note 31.8 1.610-bit resolution AVREFP = V_{DD} Note 31.8 1.610-bit resolution AVREFP = V_{DD} Note 31.6 1.610-bit resolution AVREFP = V_{DD} Note 31.6 1.6	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±1.5	LSB
error ^{Note 1}		AV _{REFP} = V _{DD} ^{Note 3}	$1.6~V \leq V_{\text{DD}} \leq 5.5~V^{\text{Note 4}}$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $		±2.0	LSB
Analog input voltage	Vain	0	speed main) mode)		$V_{BGR} ^{\text{Note 5}}$		V
	Vbgr	Temperature sensor output vol (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-	0		VTMPS25 Note 5		V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When AV_{REFP} < V_{DD}, the MAX. values are as follows.
- Overall error: Add ± 1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add $\pm 0.05\%$ FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/Differential linearity error: Add ±0.5 LSB to the MAX. value when AVREFP = VDD.

- 4. Values when the conversion time is set to 57 μ s (min.) and 95 μ s (max.).
- 5. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

(2) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target pin : ANI16 to ANI23

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, 1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = 0 \text{ or } 1.6 \text{ V} \le 1.6 \text{ V} \ge 1$
AVREFP, Reference voltage (–) = AVREFM = 0 V)

Parameter	Symbol	Condit	tions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1} AINL	AINL	L 10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$		1.2	±5.0	LSB
		$AV_{REFP} = EV_{DD} = V_{DD} Note 3$	$\begin{array}{l} 1.6 \ V \leq AV_{\text{REFP}} \leq 5.5 \ V \\ \text{Note 4} \end{array}$		1.2	10 .2 ±5.0 .2 ±8.5 39 39 39 39 ±0.35 ±0.60 ±0.35 ±0.60 ±0.60 ±10.60 ±0.60 ±2.5 ±2.0 ±2.5 AVREFP and and	LSB
Conversion time	t CONV	10-bit resolution	$3.6~V \le V \text{DD} \le 5.5~V$	2.125		1.2 ± 5.0 1.2 ± 8.5 39 39 39 39 40.39 95 ± 0.35 ± 0.60 ± 0.60 ± 0.60 ± 0.60 ± 3.5 ± 6.0 ± 2.0 ± 2.5 ± 2.5	μs
		AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.7~V \leq V_{DD} \leq 5.5~V$	3.1875		39	μS
			$1.8~V \leq V \text{DD} \leq 5.5~V$	17		39	μS
			$1.6~V \leq V \text{DD} \leq 5.5~V$	57		95	μS
Zero-scale error ^{Notes 1, 2}	Ezs	AVPEER = FVDD = VDD Note 3	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.35	%FSR
		AV _{REFP} = EV _{DD} = V _{DD} Note 3	$\begin{array}{l} 1.6 \ V \leq AV_{\text{REFP}} \leq 5.5 \ V \\ \text{Note 4} \end{array}$		±0.6	±0.60	%FSR
Full-scale error ^{Notes 1, 2}	E _{FS}	10-bit resolution	$1.8~V \le AV_{\text{REFP}} \le 5.5~V$			±0.35	%FSR
		AV _{REFP} = EV _{DD} = V _{DD} Note 3	$\begin{array}{l} 1.6 \ V \leq AV_{\text{REFP}} \leq 5.5 \ V \\ \text{Note 4} \end{array}$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution	$1.8~V \le AV_{\text{REFP}} \le 5.5~V$			±3.5	LSB
		$2.7 V \le VDD$ $1.8 V \le VDD$ $1.8 V \le VDD$ $1.6 V \le AVR$ $1.8 V \le AVR$	$\begin{array}{l} 1.6 \ V \leq AV_{\text{REFP}} \leq 5.5 \ V \\ \text{Note 4} \end{array}$			±6.0	LSB
Differential linearity error	DLE	10-bit resolution	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$			±2.0	LSB
Note 1		AV _{REFP} = EV _{DD} = V _{DD} Note 3	$\begin{array}{l} 1.6 \ V \leq AV_{\text{REFP}} \leq 5.5 \ V \\ \text{Note 4} \end{array}$			±2.5	LSB
Analog input voltage	VAIN			0		AVREFP	V
						and EV _{DD}	

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AV_{REFP} < EV_{DD} = V_{DD}, the MAX. values are as follows. Overall error: Add ±4.0 LSB to the MAX. value when AV_{REFP} = V_{DD}. Zero-scale error/Full-scale error: Add ±0.20%FSR to the MAX. value when AV_{REFP} = V_{DD}. Integral linearity error/Differential linearity error: Add ±2.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.
- 4. When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).



(3) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{ss} (ADREFM = 0), target pin : ANI0, ANI1, ANI16 to ANI23, internal reference voltage, and temperature sensor output voltage

$(T_A = -40 \text{ to } +85^{\circ}C, 1.6 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{\text{DD}},$	Reference voltage (-)
= Vss)	

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$		1.2	±7.0	LSB
			$1.6~V \leq V_{\text{DD}} \leq 5.5~V$ Note 3		1.2	±10.5	LSB
Conversion time	t CONV	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.1875		39	μs
			$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
			1.6 V \leq V _{DD} \leq 5.5 V Note 3 ion 3.6 V \leq V _{DD} \leq 5.5 V 2.7 V \leq V _{DD} \leq 5.5 V 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V ion iternal tage, and sensor output high-speed ion 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V ion 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V Note 3 ion 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V Note 3 ion 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V Note 3 ion 1.8 V \leq V _{DD} \leq 5.5 V 1.6 V \leq V _{DD} \leq 5.5 V Note 3 ion 1.8 V \leq V _{DD} \leq 5.5 V Note 3 23 ion 1.8 V \leq V _{DD} \leq 5.5 V Note 3 23 ion 1.8 V \leq V _{DD} \leq 5.5 V Note 3 3<	57		95	μs
		10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
		reference voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{DD} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
						±0.85	%FSR
Full-scale error ^{Notes 1, 2}	Ers	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
						±0.85	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$			±4.0	LSB
						±6.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution	$1.8~V \le V_{\text{DD}} \le 5.5~V$			±2.0	LSB
						±2.5	LSB
Analog input voltage	VAIN	ANI0, ANI1	•	0		Vdd	V
		ANI16 to ANI23		0		EVDD	V
		Internal reference voltage (2.4 V \leq V _{DD} \leq 5.5 V, HS (hig	h-speed main) mode)		V _{BGR} Note 4		V
		Temperature sensor output	voltage	8 1.1 2.125 1.1 3.1875 1.1 17 57 2.375 3.5625 17 17 17 17 10 17 10 17 11 17 11 17 11 17 11 17 11 17 11 17 11 17 11 17 11 17 11 17 12 17 13 17 14 17 15 17 16 10 17 17 17 17 17 17 17 17 18 17 19 10 10 10 11 10 11 10 11 10 11 10 11 10 11	V _{TMPS25} Note 4		V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When the conversion time is set to 57 μ s (min.) and 95 μ s (max.).
- 4. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.

(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target pin : ANI0, ANI16 to ANI23

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{ss}} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{\text{BGR}} \text{ }^{\text{Note 3}}, \text{ Reference voltage (-)} = \text{AV}_{\text{REFM}} \text{ }^{\text{Note 4}} = 0 \text{ V}, \text{ HS (high-speed main) mode)}$

Parameter	Symbol	Cond	itions	MIN.	TYP.	MAX.	Unit
Resolution	RES				8		bit
Conversion time	t CONV	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±1.0	LSB
Analog input voltage	VAIN			0		VBGR Note 3	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 2.6.2 Temperature sensor/internal reference voltage characteristics.
- **4.** When reference voltage (–) = Vss, the MAX. values are as follows.

Zero-scale error: Add $\pm 0.35\%$ FSR to the MAX. value when reference voltage (–) = AV_{REFM}. Integral linearity error: Add ± 0.5 LSB to the MAX. value when reference voltage (–) = AV_{REFM}. Differential linearity error: Add ± 0.2 LSB to the MAX. value when reference voltage (–) = AV_{REFM}.

2.6.2 Temperature sensor/internal reference voltage characteristics

Symbol TYP. Conditions MIN. MAX. Unit Parameter Setting ADS register = 80H, T_A = +25°C 1.05 Temperature sensor output voltage VTMPS25 V 1.45 V Internal reference voltage Vbgr Setting ADS register = 81H 1.38 1.5 Temperature coefficient **F**VTMPS Temperature sensor that depends on the -3.6 mV/°C temperature Operation stabilization wait time 5 t_{AMP} μs

(TA = -40 to +85°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V) (HS (high-speed main) mode)

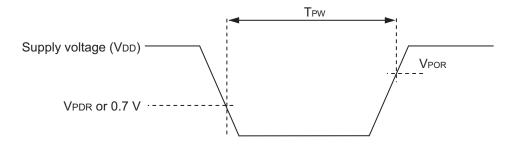


2.6.3 POR circuit characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	The power supply voltage is rising.	1.47	1.51	1.55	V
	VPDR	The power supply voltage is falling.	1.46	1.50	1.54	V
Minimum pulse width ^{Note}	TPW		300			μs

Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).





2.6.4 LVD circuit characteristics

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	VLVD0	Power supply rise time	3.98	4.06	4.14	V
voltage	Supply voltage level		Power supply fall time	3.90	3.98	4.06	V
		VLVD1	Power supply rise time	3.68	3.75	3.82	V
			Power supply fall time	3.60	3.67	3.74	V
		VLVD2	Power supply rise time	3.07	3.13	3.19	V
			Power supply fall time	3.00	3.06	3.12	V
		VLVD3	Power supply rise time	2.96	3.02	3.08	V
			Power supply fall time	2.90	2.96	3.02	V
		VLVD4	Power supply rise time	2.86	2.92	2.97	V
			Power supply fall time	2.80	2.86	2.91	V
		VLVD5	Power supply rise time	2.76	2.81	2.87	V
			Power supply fall time	2.70	2.75	2.81	V
		VLVD6	Power supply rise time	2.66	2.71	2.76	V
			Power supply fall time	2.60	2.65	2.70	V
		VLVD7	Power supply rise time	2.56	2.61	2.66	V
			Power supply fall time	2.50	2.55	2.60	V
		VLVD8	Power supply rise time	2.45	2.50	2.55	V
			Power supply fall time	2.40	2.45	2.50	V
		VLVD9	Power supply rise time	2.05	2.09	2.13	V
			Power supply fall time	2.00	2.04	2.08	V
		VLVD10	Power supply rise time	1.94	1.98	2.02	V
			Power supply fall time	1.90	1.94	1.98	V
		VLVD11	Power supply rise time	1.84	1.88	1.91	V
			Power supply fall time	1.80	1.84	1.87	V
		VLVD12	Power supply rise time	1.74	1.77	1.81	V
			Power supply fall time	1.70	1.73	1.77	V
		VLVD13	Power supply rise time	1.64	1.67	1.70	V
			Power supply fall time	1.60	1.63	1.66	V
Minimum pu	ulse width	tLw		300			μs
Detection d	elay time	tLD				300	μs



LVD Detection Voltage of Interrupt & Reset Mode

(T₄ = –40 to +85°C.	$= V_{DD} < 5.5 V$	Vss = EVss = 0 V)
۰.	$1A = -40 10 \cdot 00 0$, v 33 – Lv 33 – v v j

Parameter	Symbol		Conc	litions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	VLVDA0	Vpoc2,	VPOC1, VPOC0 = 0, 0, 0	, falling reset voltage	1.60	1.63	1.66	V
mode	VLVDA1		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.74	1.77	1.81	V
				Falling interrupt voltage	1.70	1.73	1.77	V
	VLVDA2		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	1.84	1.88	1.91	V
				Falling interrupt voltage	1.80	1.84	1.87	V
	VLVDA3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVDB1	Vpoc2,	VPOC1, VPOC0 = 0, 0, 1	, falling reset voltage	1.80	1.84	1.87	V
	VLVDB2		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.02	V
				Falling interrupt voltage	1.90	1.94	1.98	V
	VLVDB3		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.13	V
				Falling interrupt voltage	2.00	2.04	2.08	V
	VLVDB4		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.19	V
				Falling interrupt voltage	3.00	3.06	3.12	V
		Vpoc2,	VPOC1, VPOC0 = 0, 1, 0	, falling reset voltage	2.40	2.45	2.50	V
		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.66	V	
				Falling interrupt voltage	2.50	2.55	2.60	V
	VLVDC2		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.76	V
				Falling interrupt voltage	2.60	2.65	2.70	V
	VLVDC3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.68	3.75	3.82	V
				Falling interrupt voltage	3.60	3.67	3.74	V
	VLVDD0	Vpoc2,	VPOC1, VPOC0 = 0, 1, 1	, falling reset voltage	2.70	2.75	2.81	V
	VLVDD1	1	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	2.97	V
				Falling interrupt voltage	2.80	2.86	2.91	V
	VLVDD2	1	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.08	V
				Falling interrupt voltage	2.90	2.96	3.02	V
	VLVDD3		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.14	V
				Falling interrupt voltage	3.90	3.98	4.06	V

2.6.5 Supply voltage rise time

(T_A = -40 to +85°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V_{DD} reaches the operating voltage range shown in 2.4 AC Characteristics.

2.7 LCD Characteristics

2.7.1 Resistance division method

(1) Static display mode

(TA = -40 to +85°C, VL4 (MIN.) \leq VDD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.0		Vdd	V

(2) 1/2 bias method, 1/4 bias method

(TA = -40 to +85°C, VL4 (MIN.) \leq VDD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.7		Vdd	V

(3) 1/3 bias method

$(T_A = -40 \text{ to } +85^{\circ}C, V_{L4} \text{ (MIN.)} \le V_{DD} \le 5.5 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.5		Vdd	V



2.7.2 Internal voltage boosting method

(1) 1/3 bias method

(T_A = -40 to +85°C, 1.8 V \leq V_DD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Cond	litions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1	C1 to C4 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 <i>µ</i> F	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	VL2	C1 to C4 ^{Note 1} =	= 0.47 <i>µ</i> F	2 V _{L1} - 0.1	2 VL1	2 VL1	V
Tripler output voltage	VL4	C1 to C4 ^{Note 1} =	= 0.47 <i>μ</i> F	3 V∟1 – 0.15	3 VL1	3 VL1	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C4 ^{Note 1} =	= 0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between V_{L1} and GND

C3: A capacitor connected between VL2 and GND

C4: A capacitor connected between VL4 and GND

 $C1 = C2 = C3 = C4 = 0.47 \ \mu\text{F}{\pm}30\%$

- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- **3.** This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).



(2) 1/4 bias method

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1 Note 4	C1 to C5 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 <i>µ</i> F	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	VL2	C1 to C5 ^{Note 1} =	0.47 <i>μ</i> F	2 VL1 - 0.08	2 VL1	2 VL1	V
Tripler output voltage	VL3	C1 to C5 ^{Note 1} =	0.47 μF	$3 V_{L1} - 0.12$	3 VL1	3 VL1	V
Quadruply output voltage	VL4 Note 4	C1 to C5 ^{Note 1} =	0.47 μF	4 VL1-0.16	4 VL1	4 VL1	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C5 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

- C2: A capacitor connected between V_{L1} and GND
- C3: A capacitor connected between V_{L2} and GND
- C4: A capacitor connected between VL3 and GND

C5: A capacitor connected between V_{L4} and GND

 $C1 = C2 = C3 = C4 = C5 = 0.47 \ \mu\text{F}{\pm}30\%$

- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- 4. VL4 must be 5.5 V or lower.

2.7.3 Capacitor split method

1/3 bias method

(TA = -40 to +85°C, 2.2 V \leq VDD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V _{L4} voltage	VL4	C1 to C4 = 0.47 μ F ^{Note 2}		Vdd		V
V∟₂ voltage	VL2	C1 to C4 = 0.47 μ F ^{Note 2}	2/3 V _{L4} - 0.1	2/3 VL4	2/3 V _{L4} + 0.1	V
V _{L1} voltage	VL1	C1 to C4 = 0.47 μ F ^{Note 2}	1/3 VL4 - 0.1	1/3 VL4	1/3 V _{L4} + 0.1	V
Capacitor split wait time ^{Note 1}	tvwait		100			ms



- Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).
 - 2. This is a capacitor that is connected between voltage pins used to drive the LCD.
 - C1: A capacitor connected between CAPH and CAPL
 - C2: A capacitor connected between V_{L1} and GND
 - C3: A capacitor connected between V_{L2} and GND
 - C4: A capacitor connected between V_{L4} and GND
 - $C1 = C2 = C3 = C4 = 0.47 \ \mu F \pm 30\%$

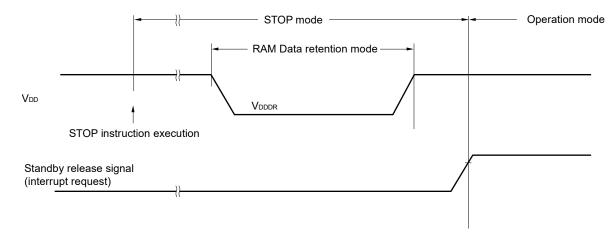


2.8 RAM Data Retention Characteristics

$(T_A = -40 \text{ to } +85^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 ^{Note}		5.5	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



2.9 Flash Memory Programming Characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	1		24	MHz
Number of code flash rewrites Note 1, 2, 3	Cerwr	Retained for 20 years T _A = 85°C	1,000			Times
Number of data flash rewrites Note 1, 2, 3		Retained for 1 year T _A = 25°C		1,000,000		
		Retained for 5 years T _A = 85°C	100,000			
		Retained for 20 years T _A = 85°C	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

- The retaining years are until next rewrite after the rewrite.
- 2. When using flash memory programmer and Renesas Electronics self programming library
- 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.

Remark When updating data multiple times, use the flash memory as one for updating data.

2.10 Dedicated Flash Memory Programmer Communication (UART)

(TA = -40 to +85°C, 1.8 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115,200		1,000,000	bps

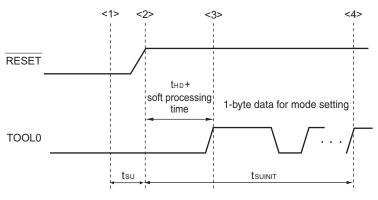


RL78/L12

2.11 Timing Specifications for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	ts∪	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}_{\text{DD}}$	/, Vss = EVss = 0 V)
--	----------------------



- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after a reset is released during this period.
 - tsu: Time to release the external reset after the TOOL0 pin is set to the low level
 - t_{HD}: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



3. ELECTRICAL SPECIFICATIONS (G: $T_A = -40$ to $+105^{\circ}$ C)

This chapter describes the electrical specifications for the products "G: Industrial applications ($T_A = -40$ to $+105^{\circ}$ C)".

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EVDD or EVss pin, replace EVDD with VDD, or replace EVss with Vss.
 - For derating with T_A = +85 to +105°C, contact our Sales Division or the vender's sales division. Derating means the specified reduction in an operating parameter to improve reliability.



Parameter	Арр	Application				
	A: Consumer applications, G: Industrial applications (with $T_A = -40$ to $+85^{\circ}C$)	G: Industrial applications				
Operating ambient temperature	T _A = -40 to +85°C	T _A = -40 to +105°C				
Operating mode	HS (high-speed main) mode:	HS (high-speed main) mode only:				
Operating voltage range	2.7 V \leq V_{DD} \leq 5.5 V@1 MHz to 32 MHz	$2.7~V \leq V_{\text{DD}} \leq 5.5~V@1~\text{MHz}$ to 32 MHz				
	2.4 V \leq V_{DD} \leq 5.5 V@1 MHz to 16 MHz	2.4 V \leq V_{DD} \leq 5.5 V@1 MHz to 16 MHz				
	LS (low-speed main) mode:					
	1.8 V \leq V_{DD} \leq 5.5 V@1 MHz to 8 MHz					
	LV (low-voltage main) mode:					
	1.6 V \leq V_{DD} \leq 5.5 V@1 MHz to 4 MHz					
High-speed on-chip oscillator clock	1.8 V \leq V_DD \leq 5.5 V:	$2.4~V \leq V_{\text{DD}} \leq 5.5~V;$				
accuracy	±1.0%@ T _A = -20 to +85°C	±2.0%@ T _A = +85 to +105°C				
	±1.5%@ T _A = -40 to -20°C	±1.0%@ T _A = -20 to +85°C				
	$1.6 \text{ V} \le \text{V}_{\text{DD}} < 1.8 \text{ V}$:	±1.5%@ T _A = -40 to -20°C				
	±5.0%@ T _A = -20 to +85°C					
	±5.5%@ T _A = -40 to -20°C					
Serial array unit	UART	UART				
	CSI00: fclk/2 (supporting 16 Mbps), fclk/4	CSI00: fclк/4				
	CSI01	CSI01				
	Simplified I ² C communication	Simplified I ² C communication				
IICA	Normal mode	Normal mode				
	Fast mode	Fast mode				
	Fast mode plus					
Voltage detector	Rise detection voltage: 1.67 V to 4.06 V	Rise detection voltage: 2.61 V to 4.06 V				
	(14 levels)	(8 levels)				
	Fall detection voltage: 1.63 V to 3.98 V	Fall detection voltage: 2.55 V to 3.98 V				
	(14 levels)	(8 levels)				

There are following differences between the products "G: Industrial applications ($T_A = -40$ to $+105^{\circ}C$)" and the products "A: Consumer applications, and G: Industrial applications ($T_A = -40$ to $+85^{\circ}C$)".

Remark The electrical characteristics of the products G: Industrial applications ($T_A = -40$ to $+105^{\circ}C$) are different from those of the products "A: Consumer applications, and G: Industrial applications (only with $T_A = -40$ to $+85^{\circ}C$)". For details, refer to **3.1** to **3.11**.



(1/3)

3.1 Absolute Maximum Ratings

				(110)
Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	Vdd	VDD = EVDD	-0.5 to +6.5	V
	EVDD	V _{DD} = EV _{DD}	-0.5 to +6.5	V
	EVss		-0.5 to +0.3	V
REGC pin input voltage	VIREGC	REGC	-0.3 to +2.8 and -0.3 to $V_{\rm DD}$ + 0.3 $^{Note\ 1}$	V
Input voltage	VI1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	-0.3 to EV_DD + 0.3 and -0.3 to V_DD + 0.3 $^{\text{Note 2}}$	V
	V ₁₂	P60, P61 (N-ch open-drain)	-0.3 to EV _{DD} + 0.3 and -0.3 to V _{DD} + 0.3 ^{Note 2}	V
	V _{I3}	P20, P21, P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
Output voltage	Vo1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	-0.3 to EV_DD + 0.3 and -0.3 to V_DD + 0.3 $^{\text{Note 2}}$	V
	V ₀₂	P20, P21	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
Analog input voltage	VAI1	ANI16 to ANI23	-0.3 to EV _{DD} + 0.3 and -0.3 to AV _{REF} (+) + 0.3 ^{Notes 2, 3}	V
	VAI2	ANIO, ANI1	-0.3 to V _{DD} + 0.3 and -0.3 to AV _{REF} (+) + 0.3 ^{Notes 2, 3}	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

- 2. Must be 6.5 V or lower.
- 3. Do not exceed $AV_{REF}(+) + 0.3 V$ in case of A/D conversion target pin.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - 2. AVREF (+) : + side reference voltage of the A/D converter.
 - 3. Vss : Reference voltage



(2/3)

Absolute Maximum Ratings (T_A = 25°C)

	J	- /			()
Parameter	Symbols		Conditions	Ratings	Unit
_CD voltage	VL1	V∟1 voltage ^{Note 1}		–0.3 to +2.8 and –0.3 to V∟4 + 0.3	V
	VL2	V _{L2} voltage ^{Note 1}		–0.3 to V_{L4} + 0.3 $^{Note\ 2}$	V
F	VL3	VL3 voltage ^{Note 1}		–0.3 to VL4 + 0.3 Note 2	V
	VL4	V₋₄ voltage ^{Note 1}		-0.3 to +6.5	V
	VLCAP	CAPL, CAPH voltage ^{Note 1}		–0.3 to VL4 + 0.3 Note 2	V
VLCAP	Vlout	COM0 to COM7, SEG0 to	External resistance division method	-0.3 to V _{DD} + 0.3 ^{Note 2}	V
		SEG38,	Capacitor split method	-0.3 to V _{DD} + 0.3 ^{Note 2}	
		output voltage	Internal voltage boosting method	-0.3 to V _{L4} + 0.3 ^{Note 2}	

Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the VL1, VL2, VL3, and VL4 pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47 μ F ± 30%) and connect a capacitor (0.47 μ F ± 30%) between the CAPL and CAPH pins.

- 2. Must be 6.5 V or lower.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss : Reference voltage



Absolute Maximum Ratings (T_A = 25°C)

(3/3)

		,			(0,0)
Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147	-40	mA
		Total of all pins –170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	-70	mA
			P15 to P17, P30 to P32, P50 to P54, P70 to P74, P125 to P127	-100	mA
	Іон2	Per pin	P20, P21	-0.5	mA
		Total of all pins		-1	mA
Output current, low	lol1	Per pin	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P130, P140 to P147	40	mA
		Total of all pins 170 mA	P10 to P14, P40 to P43, P120, P130, P140 to P147	70	mA
			P15 to P17, P30 to P32, P50 to P54, P60, P61, P70 to P74, P125 to P127	100	mA
	IOL2	Per pin	P20, P21	1	mA
		Total of all pins		2	mA
Operating ambient	TA	In normal operation	on mode	-40 to +105	°C
temperature		In flash memory p	programming mode		
Storage temperature	Tstg			-65 to +150	°C

- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



3.2 Oscillator Characteristics

3.2.1 X1, XT1 oscillator characteristics

(-,		- /			
Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	1.0		20.0	MHz
frequency (fx) ^{Note}	crystal resonator	$2.4~V \leq V_{\text{DD}} < 2.7~V$	1.0		16.0	MHz
XT1 clock oscillation frequency (f _{XT}) ^{Note}	Crystal resonator		32	32.768	35	kHz

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS}} = 0 \text{ V})$

- **Note** Indicates only permissible oscillator frequency ranges. Refer to **3.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.
- Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

3.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS}} = 0 \text{ V})$

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1		24	MHz
High-speed on-chip oscillator		–20 to +85°C	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	-1		+1	%
clock frequency accuracy		–40 to –20°C	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	-1.5		+1.5	%
		+85 to +105°C	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	-2.0		+2.0	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

Notes 1. High-speed on-chip oscillator frequency is selected by bits 0 to 3 of option byte (000C2H) and bits 0 to 2 of HOCODIV register.

2. This indicates the oscillator characteristics only. Refer to 3.4 AC Characteristics for instruction execution time.



3.3 DC Characteristics

3.3.1 Pin characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{SS}} = 0 \text{ V})$

(1/5)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Output current, I _{OH1} high ^{Note 1}	Іон1	Per pin for P10 to P17 P70 to P74, P120, P1					-3.0 Note 2	mA
		Total of P10 to P14, F	Total of P10 to P14, P40 to P43, P120, P130, P140 to P147				-30.0	mA
		,					-8.0	mA
		(When duty = 70% ^{Note 3})		$2.4~V \leq EV_{\text{DD}} < 2.7~V$			-4.0	mA
		Total of P15 to P17, P3	230 to P32,	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			-30.0	mA
		P50 to P54, P70 to P74, P125 to P127 (When duty = 70% ^{Note 3})		$2.7~V \leq EV_{\text{DD}} < 4.0~V$			-15.0	mA
				$2.4~V \leq EV_{\text{DD}} < 2.7~V$			-8.0	mA
Іон2		Total of all pins (When duty = 70% ^{Note 3})					-60.0	mA
	Іон2	P20, P21	Per pin				-0.1	mA
			Total of all pins	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			-0.2	mA

- **Notes 1.** Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} and EV_{DD} pins to an output pin.
 - 2. Do not exceed the total current value.
 - **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = (Іон × 0.7)/(n × 0.01)
- <Example> Where n = 80% and IoH = -30.0 mA

Total output current of pins = $(-30.0 \times 0.7)/(80 \times 0.01) \cong -26.25$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.



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Items	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Output current, IoL1	Iol1	•	Per pin for P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147				8.5 Note 2	mA
		Per pin for Pe	60, P61				15.0 Note 2	mA
		Total of P10	to P14, P40 to P43, P120,	$4.0~V \le EV_{\text{DD}} \le 5.5~V$			40.0	mA
				$2.7~V \leq EV_{\text{DD}} < 4.0~V$			15.0	mA
	T T T	(When duty = 70% ^{Note 3})	$2.4~V \leq EV_{\text{DD}} < 2.7~V$			9.0	mA	
		Total of P15 to P17, P30 to P32 to P54, P60, P61, P70 to P74, P125 to P127 (When duty = 70% ^{Note 3})	to P17, P30 to P32, P50	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$			40.0	mA
			, ,	$2.7~V \leq EV_{\text{DD}} < 4.0~V$			35.0	mA
				$2,4 \text{ V} \le \text{EV}_{\text{DD}} \le 2.7 \text{ V}$			20.0	mA
			Fotal of all pins When duty = 70% ^{Note 3})				80.0	mA
	IOL2	P20, P21 Per pin					0.4	mA
			Total of all pins	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			0.8	mA

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$



Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the V_{DD} and EV_{DD} pins to an output pin.

- 2. Do not exceed the total current value.
- **3.** Specification under conditions where the duty factor \leq 70%. The output current value that has changed to the duty factor \geq 70% the duty ratio of

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (IoL × 0.7)/(n × 0.01)

<Example> Where n = 80% and IoL = 40.0 mA

Total output current of pins = $(40.0 \times 0.7)/(80 \times 0.01) \approx 35.0 \text{ mA}$

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.



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Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	Vih1	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P70 to P74, P120, P125 to P127, P140 to P147	Normal input buffer	0.8EVdd		EVDD	V
	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	EVDD	V				
				2.0		EVDD	V
				1.50		EVDD	V
	Vінз	P20, P21		0.7Vdd		Vdd	V
	VIH4	P60, P61		0.7EV _{DD}		EVDD	V
	VIH5	P121 to P124, P137, EXCLK, EXCLKS	S, RESET	0.8Vdd			V
Input voltage, low	VIL1	P50 to P54, P70 to P74, P120,	Normal input buffer	0		VDD EVDD VDD 0.2EVDD	V
	VIL2	P10, P11, P15, P16		0		0.8	V
				0		0.5	V
				0		0.32	V
	VIL3	P20, P21		0		0.3Vdd	V
nput voltage, low	VIL4	P60, P61		0		0.3EV _{DD}	V
	VIL5	P121 to P124, P137, EXCLK, EXCLKS	S, RESET	0		EVDD EVDD EVDD EVDD EVDD EVDD EVDD ODD OOD OOSVDD	V

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$



Caution The maximum value of VIH of pins P10, P12, P15, and P17 is EVDD, even in the N-ch open-drain mode.



Items	Symbol	Conditions	MIN.	TYP.	MAX.	Unit	
Output voltage, high	V _{OH1}		$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -3.0 \ \text{mA} \end{array}$	EV _{DD} - 0.7			V
		P125 to P127, P130, P140 to P147	$\begin{array}{l} 2.7 \ \text{V} \leq \text{EV}_{\text{DD}} \leq 5.5 \ \text{V}, \\ \text{I}_{\text{OH1}} = -2.0 \ \text{mA} \end{array}$	EV _{DD} – 0.6			V
			$\begin{array}{l} 2.4 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OH1}} = -1.5 \ mA \end{array}$	EV _{DD} – 0.5			V
	Voh2	P20, P21	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V},$ Ioh2 = -100 μ A	$V_{\text{DD}}-0.5$			V
Output voltage, low	Vol1	P50 to P54, P70 to P74, P120, P125 to P127, P130, P140 to P147	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 8.5 \ mA \end{array} \end{array} \label{eq:eq:electropy}$			0.7	V
			$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 3.0 \ mA \end{array} \end{array} \label{eq:DD}$			0.6	V
			$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 1.5 \ mA \end{array} \end{array} \label{eq:eq:obs}$			0.4	V
			$\label{eq:local_def} \begin{array}{l} 2.4 \ V \leq E V_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL1}} = 0.6 \ mA \end{array}$			0.4	V
	Vol2	P20, P21	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V},$ $\text{I}_{\text{OL2}} = 400 \ \mu \text{ A}$			0.4	V
	Vol3		$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 15.0 \ mA \end{array} \end{array} \label{eq:eq:entropy}$			2.0	V
			$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 5.0 \ mA \end{array} \end{array} \label{eq:eq:entropy}$			0.4	V
			$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ I_{\text{OL3}} = 3.0 \ mA \end{array} \end{array} \label{eq:DD}$			0.4	V
			$\label{eq:loss} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \\ \\ I_{\text{OL3}} = 2.0 \ mA \end{array}$			0.4	V

(TA = -40 to +105°C, 2.4 V \leq EVDD = VDD \leq 5.5 V, Vss = EVss = 0 V)



Caution P10, P12, P15, and P17 do not output high level in N-ch open-drain mode.



Items	Symbol	Conditio		MIN.	TYP.	MAX.	Unit	
Input leakage current, high	Ішнт	P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	VI = EVDD				1	μA
	ILIH2	P20, P21, P137, RESET	VI = VDD				1	μA
	Ілнз	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = VDD	In input port or external clock input			1	μA
				In resonator connection			10	μA
Input leakage current, low		P10 to P17, P30 to P32, P40 to P43, P50 to P54, P60, P61, P70 to P74, P120, P125 to P127, P140 to P147	Vı = EVss				-1	μA
	ILIL2	P20, P21, P137, RESET	VI = VSS				-1	μA
	Ililis	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	VI = Vss	In input port or external clock input			-1	μA
				In resonator connection			-10	μA
On-chip pll-up	Ruı	Vi = EVss	SEGxx port					
resistance			$2.4~\text{V} \leq EV_{\text{DD}} = V_{\text{DD}} \leq 5.5~\text{V}$		10	20	100	kΩ
	Ru2			Ports other than above (Except for P60, P61, and P130)		20	100	kΩ

 $(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

(5/5)



3.3.2 Supply current characteristics

(TA = -40 to +105°C, 2.4 V \leq EVDD = VDD \leq 5.5 V, Vss = EVss = 0 V)

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Parameter	Symbol			Conditions			MIN.	TYP.	MAX.	Unit
Supply ID	IDD1	Operating	HS (high-	fi⊩ = 24 MHz ^{Note 3}	Basic	V _{DD} = 5.0 V		1.5		mA
current		mode	speed main) mode ^{Note 5}		operation	V _{DD} = 3.0 V		1.5		mA
Note 1			mode		Normal	V _{DD} = 5.0 V		3.3	5.3	mA
					operation	V _{DD} = 3.0 V		3.3	5.3	mA
				f⊮ = 16 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		2.5	3.9	mA
					operation	V _{DD} = 3.0 V		2.5	3.9	mA
			HS (high-	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.7	mA
			speed main) mode ^{Note 5}	V _{DD} = 5.0 V	operation	Resonator connection		3.0	4.8	mA
			mode	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.7	mA
				V _{DD} = 3.0 V	operation	Resonator connection		3.0	4.8	mA
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		1.8	2.8	mA
				V _{DD} = 5.0 V	operation	Resonator connection		1.8	2.8	mA
				f _{MX} = 10 MHz ^{Note 2} ,	Normal operation	Square wave input		1.8	2.8	mA
				V _{DD} = 3.0 V		Resonator connection		1.8	2.8	mA
		Subsystem	fsuв = 32.768 kHz	Normal	Square wave input		3.5	4.9	μA	
			clock operation	Note 4 T _A = −40°C	operation	Resonator connection		3.6	5.0	μA
				fsuв = 32.768 kHz	Normal	Square wave input		3.6	4.9	μA
				Note 4 T _A = +25°C	operation	Resonator connection		3.7	5.0	μA
				fsuв = 32.768 kHz	Normal	Square wave input		3.7	5.5	μA
				Note 4 T _A = +50°C	operation	Resonator connection		3.8	5.6	μA
				fsuв = 32.768 kHz	Normal	Square wave input		3.8	6.3	μA
				Note 4 T _A = +70°C	operation	Resonator connection		3.9	6.4	μA
				fsuв = 32.768 kHz	Normal	Square wave input		4.1	7.7	μA
				Note 4 T _A = +85°C	operation	Resonator connection		4.2	7.8	μA
				fsuв = 32.768 kHz	Normal	Square wave input		6.4	19.7	μA
				Note 4 T _A = +105°C	operation	Resonator connection		6.5	19.8	μA

(Notes and Remarks are listed on the next page.)



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- **Notes 1.** Total current flowing into V_{DD} and EV_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD} or V_{SS}, EV_{SS}. The following points apply in the HS (high-speed main) mode.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

- 2. When high-speed on-chip oscillator and subsystem clock are stopped.
- 3. When high-speed system clock and subsystem clock are stopped.
- **4.** When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation).
- 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode: $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}@1 \text{ MHz}$ to 24 MHz $2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}@1 \text{ MHz}$ to 16 MHz
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. file: High-speed on-chip oscillator clock frequency
 - 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 4. Except subsystem clock operation, temperature condition of the TYP. value is $T_A = 25^{\circ}C$



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				$J \leq 0.0 \mathbf{v}, \mathbf{v}_{33} = \mathbf{L} \mathbf{v}_{33}$,				(2/5
Parameter	Symbol	Conditions MIN.						MAX.	Unit
Supply	IDD2	HALT	HS (high-	fı⊣ = 24 MHz ^{Note 4}	V _{DD} = 5.0 V		0.44	2.3	mA
current	Note 2	mode	speed main) mode ^{Note 6}		V _{DD} = 3.0 V		0.44	2.3	mA
Note 1				fi⊢ = 16 MHz ^{Note 4}	V _{DD} = 5.0 V		0.40	1.7	mA
					V _{DD} = 3.0 V		0.40	1.7	mA
			HS (high-	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.9	mA
			speed main) mode ^{Note 6}	V _{DD} = 5.0 V	Resonator connection		0.45	2.0	mA
				f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.9	mA
				V _{DD} = 3.0 V	Resonator connection		0.45	2.0	mA
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	1.02	mA
				V _{DD} = 5.0 V	Resonator connection		0.26	1.10	mA
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	1.02	mA
				V _{DD} = 3.0 V	Resonator connection		0.26	1.10	mA
			Subsystem	fsub = 32.768 kHz ^{Note 5}	Square wave input		0.31	0.57	μA
			clock operation	T _A = -40°C	Resonator connection		0.50	0.76	μA
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.37	0.57	μA
				T _A = +25°C	Resonator connection		0.56	0.76	μA
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.46	1.17	μA
				T _A = +50°C	Resonator connection		0.65	1.36	μA
				fsub = 32.768 kHz ^{Note 5}	Square wave input		0.57	1.97	μA
				T _A = +70°C	Resonator connection		0.76	2.16	μA
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		0.85	3.37	μA
				T _A = +85°C	Resonator connection		1.04	3.56	μA
				fsuв = 32.768 kHz ^{Note 5}	Square wave input		3.04	15.37	μA
				T _A = +105°C	Resonator connection		3.23	15.56	μA
	Іддз	STOP	T _A = -40°C				0.17	0.50	μA
		mode ^{Note 7}	T _A = +25°C				0.23	0.50	μA
			T _A = +50°C				0.32	1.10	μA
			T _A = +70°C				0.43	1.90	μA
			T _A = +85°C				0.71	3.30	μA
			T _A = +105°C				2.90	15.30	μA

(TA = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

(2/3)

(Notes and $\ensuremath{\textit{Remarks}}$ are listed on the next page.)

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- **Notes 1.** Total current flowing into V_{DD} and EV_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD} or V_{SS}, EV_{SS}. The following points apply in the HS (high-speed main) mode.
 - The currents in the "TYP." column do not include the operating currents of the peripheral modules.
 - The currents in the "MAX." column include the operating currents of the peripheral modules, except for those flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors, and those flowing while the data flash memory is being rewritten.

In the subsystem clock operation, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules. However, in HALT mode, including the current flowing into the RTC.

In the STOP mode, the currents in both the "TYP." and "MAX." columns do not include the operating currents of the peripheral modules.

- **2.** During HALT instruction execution by flash memory.
- 3. When high-speed on-chip oscillator and subsystem clock are stopped.
- 4. When high-speed system clock and subsystem clock are stopped.
- 5. When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1).
- 6. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
 - HS (high-speed main) mode: 2.7 V \leq VDD \leq 5.5 V@1 MHz to 24 MHz
 - 2.4 V \leq VDD \leq 5.5 V@1 MHz to 16 MHz
- 7. Regarding the value for current operate the subsystem clock in STOP mode, refer to that in HALT mode.

Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

- **2.** fin: High-speed on-chip oscillator clock frequency
- 3. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
- 4. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



$(T_A = -40 \text{ to } +$	105°C, 2.	$4 V \le EV_{DD} = V_{DD} \le 5.5 V, V_{SS} = EV_{SS} = 0 V$						(3/3)	
Parameter	Symbol	Conditions				TYP.	MAX.	Unit	
Low-speed on- chip oscillator operating current	_{FIL} Note 1					0.20		μA	
RTC operating current	IRTC Notes 1, 2, 3	fmain is stopped		0.08		μA			
12-bit interval timer current	i⊤ Notes 1, 2, 4			0.08		μA			
Watchdog timer operating current	WDT Notes 1, 2, 5	f⊩ = 15 kHz		0.24		μA			
A/D converter operating current	IADC Notes 1, 6	When conversion at maximum speed		$V_{REFP} = V_{DD} = 5.0 V$ de, $AV_{REFP} = V_{DD} = 3.0 V$		1.3 0.5	1.7 0.7	mA mA	
A/D converter reference voltage current	IADREF Note 1							μA	
Temperature sensor operating current	ITMPS Note 1					75.0		μA	
LVD operating current	ILVD Notes 1, 7			0.08		μA			
Self- programming operating current	FSP Notes 1, 9					2.50	12.20	mA	
BGO operating current	BGO Notes 1, 8					2.50	12.20	mA	
LCD operating current	ILCD1 Notes 11, 12	External resistance	division method	$V_{DD} = EV_{DD} = 5.0 V$ $V_{L4} = 5.0 V$		0.04	0.20	μA	
	ILCD2 Note 11	Internal voltage boo	osting method $V_{DD} = EV_{DD} = 5.0 V$ $V_{L4} = 5.1 V (VLCD = 12H)$			1.12	3.70	μA	
				$V_{DD} = EV_{DD} = 3.0 V$ $V_{L4} = 3.0 V (VLCD = 04H)$		0.63	2.20	μA	
	LCD3 Note 11	Capacitor split method		$V_{DD} = EV_{DD} = 3.0 V$ $V_{L4} = 3.0 V$		0.12	0.50	μA	
SNOOZE	ISNOZ Note 1	ADC operation	The mode is perfo	rmed Note 10		0.50	1.10	mA	
operating current			The A/D conversion operations are performed, Low voltage mode, $AV_{REFP} = V_{DD}$ = 3.0 V			1.20	2.04	mA	
		Simplified SPI (CSI)/UART operation					1.54	mA	



(Notes and Remarks are listed on the next page.)



- Notes 1. Current flowing to VDD.
 - 2. When high speed on-chip oscillator and high-speed system clock are stopped.
 - 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
 - 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
 - 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.
 - 6. Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
 - 7. Current flowing only to the LVD circuit. The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit is in operation.
 - 8. Current flowing only during data flash rewrite.
 - 9. Current flowing only during self programming.
 - **10.** For shift time to the SNOOZE mode.
 - 11. Current flowing only to the LCD controller/driver. The supply current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1 or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.

The TYP. value and MAX. value are following conditions.

- When fsub is selected for system clock, LCD clock = 128 Hz (LCDC0 = 07H)
- 4-Time-Slice, 1/3 Bias Method
- **12.** Not including the current that flows through the external divider resistor when the external resistance division method is used.
- **Remarks 1.** fil: Low-speed on-chip oscillator clock frequency
 - 2. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 3. fcLK: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is $T_A = 25^{\circ}C$



3.4 AC Characteristics

3.4.1 Basic operation

(TA = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum	Тсч	Main	HS (high-speed	$2.7V \!\leq\! V_{DD} \!\leq\! 5.5V$	0.04167		1	μs
instruction execution time)		system main) clock (fмаіn) operation	main) mode	$2.4 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$	0.0625		1	μs
		Subsystem of operation	lock (fsuв)	$2.4~V \le V_{DD} \le 5.5~V$	28.5	30.5	31.3	μS
		In the self	HS (high-speed	$2.7 V \le V_{DD} \le 5.5 V$	0.04167		1	μs
		programming ma		$2.4 \text{ V} \le \text{V}_{DD} < 2.7 \text{ V}$	0.0625		1	μs
External system clock frequency	fex	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq$	≤ 5.5 V		1.0		20.0	MHz
		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			1.0		16.0	MHz
	fexs				32		35	kHz
External system clock input high-	texh, texl	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$			24			ns
level width, low-level width		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$			30			ns
	texhs, texls				13.7			μS
TI00 to TI07 input high-level width, low-level width	tтıн, tтı∟				1/fмск+10			ns
TO00 to TO07 output frequency	fто	HS (high-spe	ed 4.0 V	$\leq EV_{DD} \leq 5.5 V$			16	MHz
		main) mode	2.7 V	\leq EV _{DD} < 4.0 V			8	MHz
			2.4 V	$2.4~V \leq EV_{\text{DD}} < 2.7~V$			4	MHz
PCLBUZ0, PCLBUZ1 output	f PCL	HS (high-spe	ed 4.0 V	$\leq EV_{DD} \leq 5.5 \text{ V}$			16	MHz
frequency		main) mode	2.7 V	\leq EV _{DD} < 4.0 V			8	MHz
			2.4 V	≤ EV _{DD} < 2.7 V			4	MHz
Interrupt input high-level width,	tinth,	INTP0	2.4 V	$\leq V_{\text{DD}} \leq 5.5 \text{ V}$	1			μS
low-level width	t intl	INTP1 to INT	P7 2.4 V	$\leq EV_{DD} \leq 5.5 \text{ V}$	1			μS
Key interrupt input low-level width	t kr	KR0 to KR3	2.4 V	$\leq EV_{\text{DD}} \leq 5.5 \text{ V}$	250			ns
RESET low-level width	t RSL				10			μS

Remark fmck: Timer array unit operation clock frequency

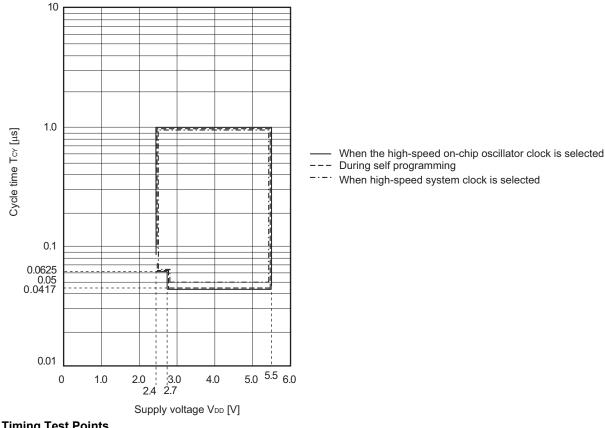
(Operation clock to be set by the CKS0n bit of timer mode register 0n (TMR0n).

n: Channel number (n = 0 to 7))



Minimum Instruction Execution Time during Main System Clock Operation

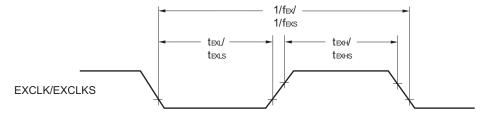
TCY vs VDD (HS (high-speed main) mode)



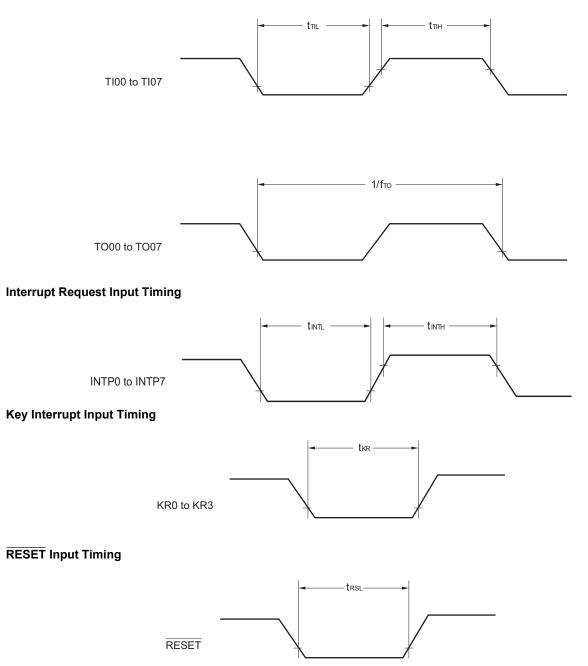
AC Timing Test Points



External System Clock Timing



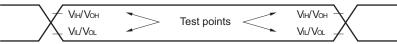
TI/TO Timing





3.5 Peripheral Functions Characteristics

AC Timing Test Points



3.5.1 Serial array unit

(1) During communication at same potential (UART mode) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

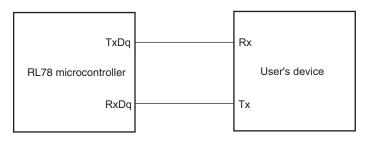
Parameter	Symbol	Conditions	HS (high-spee	Unit	
			MIN.	MAX.	
Transfer rate Note 1				fмск/12	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		2.0	Mbps

- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.
 - **2.** The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are: HS (high-speed main) mode: $24 \text{ MHz} (2.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V})$

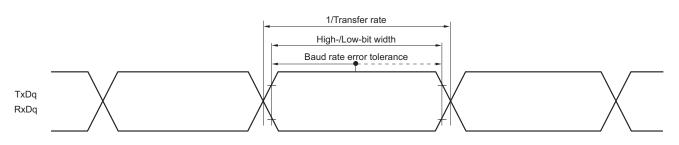
$$16 \text{ MHz} (2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V})$$

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



Remarks 1. q: UART number (q = 0), g: PIM and POM number (g = 1)

 fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	Conc	litions	HS (high-spee	Unit	
					MAX.	
SCKp cycle time	tkcy1	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		334 Note 1		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		500 ^{Note 1}		ns
SCKp high-/low-level width	t кн1,	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		tксү1/2 – 24		ns
	tĸL1	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		tkcy1/2 - 36		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		tkcy1/2 - 76		ns
SIp setup time (to SCKp↑) ^{Note 2}	tsik1	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		66		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		113		ns
SIp hold time (from SCKp↑) ^{Note 3}	tksi1	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		38		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso1	C = 30 pF ^{Note 5}	$2.4~V \le EV_{\text{DD}} \le 5.5~V$		50	ns

(TA = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

Notes 1. Set a cycle of 4/fmck or longer.

- **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM numbers (g = 1)
 - fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



Unit

ns ns

ns ns Ns

(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Conditions		HS (high-speed main) Mode	
				MIN.	MAX.
SCKp cycle time Note 5	t ксү2	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$	20 MHz < fмск	16/f мск	
			fмск ≤ 20 MHz	12/fмск	
		$2.7~V \leq EV_{\text{DD}} < 4.0~V$	16 MHz < fмск	16/fмск	
			fмск ≤ 16 MHz	12/fмск	
		$2.4~V \leq EV_{DD} \leq 5.5~V$		12/fмск and 1000	
SCKp high-/low-level	t кн2,	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		tксү2/2 – 14	
width	tĸ∟2	$2.7~V \leq EV_{\text{DD}} < 4.0~V$		tксү2/2 – 16	
		$2.4~V \leq EV_{\text{DD}} < 2.7~V$		tксү2/2 – 36	
SIp setup time	tsıĸ2	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		1/fмск + 40	
(to SCKp↑) ^{Note 1}		$2.4~V \leq EV_{\text{DD}} < 2.7~V$		1/fмск + 60	
SIp hold time (from SCKp↑) ^{Note 2}	tksi2	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		1/fмск + 62	
Delay time from SCKp \downarrow	tĸso2	C = 30 pF Note 4	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V$		2/fмск + 66
to SOp output Note 3			$2.7~V \leq EV_{\text{DD}} < 4.0~V$		2/fмск + 66
			$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$		2/fмск + 113

- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp \downarrow " when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp[↑]" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 4. C is the load capacitance of the SOp output lines.
 - 5. Transfer rate in the SNOOZE mode : MAX. 1 Mbps

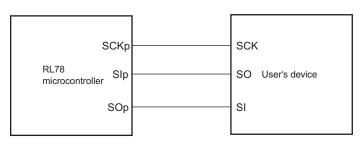
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remarks 1. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1),

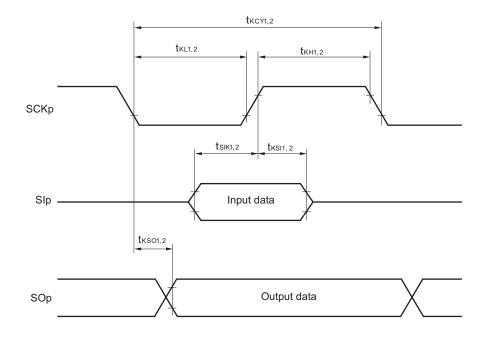
- g: PIM number (g = 1)
- 2. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))

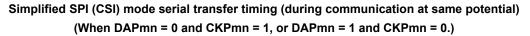
Simplified SPI (CSI) mode connection diagram (during communication at same potential)

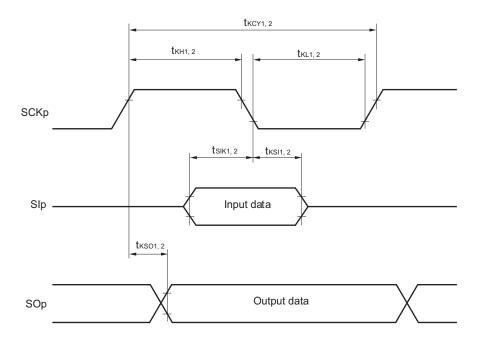






Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





Remarks 1. p: CSI number (p = 00, 01)

2. m: Unit number, n: Channel number (mn = 00, 01)

(4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2) (T_A = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol		Conditions HS (high-speed main) M		eed main) Mode	Unit	
					MIN.	MAX.	
Transfer rate		Reception	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V,$			fмск/12 ^{Note 1}	bps
			maximum tra	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 2		2.0	Mbps
				·		fмск/12 Note 1	bps
		$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate f _{MCK} = f _{CLK} Note 2		2.0	Mbps	
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$			fмск/12 ^{Note 1}	bps	
		$1.6 V \le V_b \le 2.0 V$	Theoretical value of the maximum transfer rate f _{MCK} = f _{CLK} ^{Note 2}		2.0	Mbps	

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

 $\begin{array}{l} 24 \mbox{ MHz} \ (2.7 \mbox{ V} \leq V_{DD} \leq 5.5 \mbox{ V}) \\ 16 \mbox{ MHz} \ (2.4 \mbox{ V} \leq V_{DD} \leq 5.5 \mbox{ V}) \end{array}$

- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance (32- to 52-pin products)/EV_{DD} tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- Remarks 1. Vb[V]: Communication line voltage

HS (high-speed main) mode:

- **2.** q: UART number (q = 0), g: PIM and POM number (g = 1)
- **3.** fMCK: Serial array unit operation clock frequency
 - (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01)



(4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode)

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V})$

(2/2)

Parameter	Symbol		Conditi	ons	HS (high-spee	ed main) Mode	Unit
					MIN.	MAX.	
Transfer rate		Transmission	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V,$			Note 1	bps
			$2.7~V \leq V_b \leq 4.0~V$	Theoretical value of the maximum transfer rate $C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega, V_b = 2.7 \text{ V}$		2.0 Note 2	Mbps
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 4.0 \text{ V},$			Note 3	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate		1.2 Note 4	Mbps
				$C_{\rm b}$ = 50 pF, $R_{\rm b}$ = 2.7 kΩ, $V_{\rm b}$ = 2.3 V			
			$2.4~V \leq EV_{\text{DD}} < 3.3~V,$			Note 5	bps
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate		0.43 Note 6	Mbps
				C_b = 50 pF, R_b = 5.5 kΩ, V_b = 1.6 V			

Notes 1. The smaller maximum transfer rate derived by using fMck/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq EV_{DD} \leq 5.5 V and 2.7 V \leq V_b \leq 4.0 V

Maximum transfer rate = $\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$ [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

- **2.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- **3.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD} < 4.0 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.
4. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.



5. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.8 V \leq EV_{DD} < 3.3 V and 1.6 V \leq V_b \leq 2.0 V

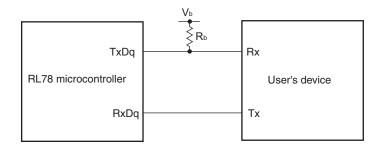
Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

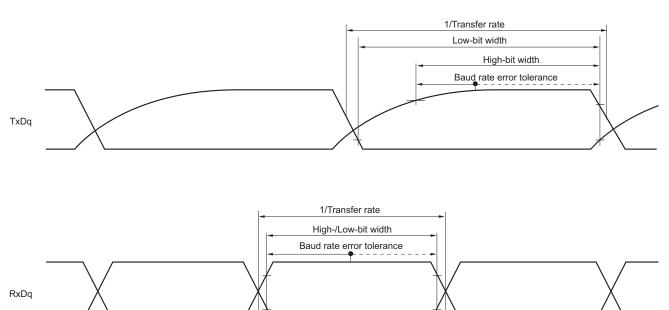
* This value is the theoretical value of the relative difference between the transmission and reception sides.

- **6.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 5 above to calculate the maximum transfer rate under conditions of the customer.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance (32- to 52-pin products)/EV_{DD} tolerance (64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

UART mode connection diagram (during communication at different potential)







UART mode bit width (during communication at different potential) (reference)

Remarks 1. $R_b[\Omega]$:Communication line (TxDq) pull-up resistance,

 $C_{b}[F]: \mbox{ Communication line (TxDq) load capacitance, V_{b}[V]: \mbox{ Communication line voltage}$

2. q: UART number (q = 0, 1), g: PIM and POM number (g = 1)

 fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))



(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

(1/2)

Parameter	Symbol	Conditions		HS (high-speed	HS (high-speed main) Mode	
			MIN.		MAX.	
SCKp cycle time	t ксү1	$t_{\text{KCY1}} \ge 4/f_{\text{CLK}}$	$4.0~V \leq EV_{\text{DD}} \leq 5.5~V,~2.7~V \leq V_{\text{b}} \leq 4.0~V,$	600		ns
			C_b = 30 pF, R_b = 1.4 k Ω			
			$\label{eq:2.7} 2.7 \ V \leq EV_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_{\text{b}} \leq 2.7 \ V,$	600		ns
			C_b = 30 pF, R_b = 2.7 k Ω			
			$2.4~V \leq EV_{\text{DD}} < 3.3~V,~1.6~V \leq V_{\text{b}} \leq 2.0~V,$	2300		ns
			C_b = 30 pF, R_b = 5.5 k Ω			
SCKp high-level width	tĸH1	$4.0 \; V \leq EV_{\text{DD}}$	≤ 5.5 V, 2.7 V $\leq V_b \leq 4.0$ V,	tксү1/2 – 150		ns
	_	C_b = 30 pF, R_b = 1.4 k Ω				
		$2.7~V \leq EV_{\text{DD}}$	< 4.0 V, 2.3 V \leq Vb \leq 2.7 V,	tксү1/2 – 340		ns
		C_b = 30 pF, R_b = 2.7 k Ω				
		$2.4~V \leq EV_{\text{DD}}$	< 3.3 V, 1.6 V \leq V _b \leq 2.0 V,	tксү1/2 – 916		ns
		C _b = 30 pF, R	R _b = 5.5 kΩ			
SCKp low-level width	t ĸ∟1	$4.0 \; V \leq EV_{\text{DD}}$	≤ 5.5 V, 2.7 V $\leq V_{b} \leq 4.0$ V,	tkcy1/2 - 24		ns
		C₀ = 30 pF, R	R _b = 1.4 kΩ			
		$2.7 \ V \leq EV_{\text{DD}} < 4.0 \ V, \ 2.3 \ V \leq V_b \leq 2.7 \ V,$		tксү1/2 – 36		ns
		C _b = 30 pF, R	R _b = 2.7 kΩ			
		$2.4~V \leq EV_{\text{DD}}$	< 3.3 V, 1.6 V \leq V _b \leq 2.0 V,	tксү1/2 – 100		ns
		C₀ = 30 pF, R	C_b = 30 pF, R_b = 5.5 k Ω			

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (32- to 52-pin

products)/EV_{DD} tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC

characteristics with TTL input buffer selected.

R01DS0157EJ0221 Rev.2.21 Feb 01, 2023



(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

(2/2)

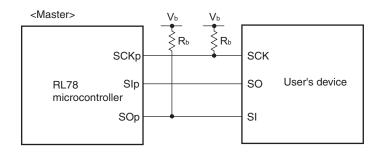
Parameter	Symbol	Conditions	HS (high-spee	ed main) Mode	Unit
			MIN.	MAX.	
SIp setup time	tsik1	$4.0 \text{ V} \le EV_{DD} \le 5.5 \text{ V}, 2.7 \text{ V} \le V_b \le 4.0 \text{ V},$	162		ns
(to SCKp↑) ^{Note 1}		$C_{b} = 30 \text{ pF}, R_{b} = 1.4 \text{ k}\Omega$			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V \le V _b \le 2.7 V,	354		ns
		C _b = 30 pF, R _b = 2.7 kΩ			
		$2.4 \text{ V} \le \text{EV}_{\text{DD}}$ < 3.3 V, 1.6 V \le V _b \le 2.0 V,	958		ns
		C _b = 30 pF, R _b = 5.5 kΩ			
SIp hold time	tksi1	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}, 2.7 \text{ V} \le \text{V}_{\text{b}} \le 4.0 \text{ V},$	38		ns
(from SCKp↑) ^{Note 1}		C₀ = 30 pF, R₀ = 1.4 kΩ			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V \le V _b \le 2.7 V,	38		ns
		C_{b} = 30 pF, R_{b} = 2.7 k Ω			
		$2.4 \text{ V} \le \text{EV}_{\text{DD}}$ < 3.3 V, 1.6 V $\le \text{V}_{\text{b}} \le 2.0 \text{ V}$,	38		ns
		C_{b} = 30 pF, R_{b} = 5.5 k Ω			
Delay time from SCKp↓ to SOp output ^{Note 1}	tkso1	$4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$		200	ns
		C _b = 30 pF, R _b = 1.4 kΩ			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V $\le \text{V}_{b} \le 2.7 \text{ V}$,		390	ns
		C_b = 30 pF, R_b = 2.7 k Ω			
		$2.4 \ V \leq EV_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V,$		966	ns
		C_b = 30 pF, R_b = 2.7 k Ω			
SIp setup time	tsıĸı	$4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$	88		ns
(to SCKp↓) ^{Note}		C_b = 30 pF, R_b = 1.4 k Ω			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V $\le \text{V}_{b} \le 2.7 \text{ V}$,	88		ns
		C_b = 30 pF, R_b = 2.7 k Ω			
		$2.4 \text{ V} \le \text{EV}_{\text{DD}}$ < 3.3 V, 1.6 V $\le \text{V}_{b} \le 2.0 \text{ V}$,	220		ns
		C_b = 30 pF, R_b = 5.5 k Ω			
SIp hold time	tksi1	$4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$	38		ns
(from SCKp↓) ^{Note 2}		C_b = 30 pF, R_b = 1.4 k Ω			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V $\le \text{V}_{b} \le 2.7 \text{ V}$,	38		ns
		C_b = 30 pF, R_b = 2.7 k Ω			
		$2.4 \ V \leq EV_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \leq V_b \leq 2.0 \ V,$	38		ns
		C_b = 30 pF, R_b = 5.5 k Ω			
Delay time from SCKp↑ to	tkso1	$4.0 \ V \leq EV_{\text{DD}} \leq 5.5 \ V, \ 2.7 \ V \leq V_{\text{b}} \leq 4.0 \ V,$		50	ns
SOp output Note 2		C_b = 30 pF, R_b = 1.4 k Ω			
		$2.7 \text{ V} \le \text{EV}_{\text{DD}}$ < 4.0 V, 2.3 V \le V _b \le 2.7 V,		50	ns
		C_b = 30 pF, R_b = 2.7 k Ω			
		$2.4 \ V \le EV_{\text{DD}} < 3.3 \ V, \ 1.6 \ V \le V_{\text{b}} \le 2.0 \ V,$		50	ns
		C_{b} = 30 pF, R_{b} = 5.5 k Ω			

(Notes, Caution and Remarks are listed on the page after the next page.)



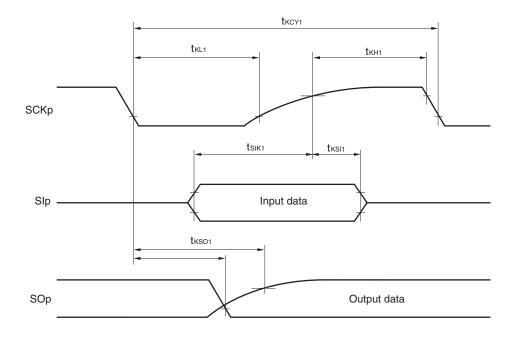
- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - **2.** When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (32- to 52-pin products)/EV_{DD} tolerance (64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

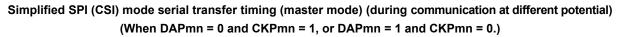


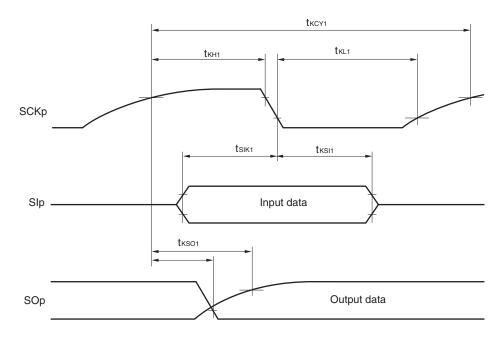
- Remarks 1. Rb[Ω]:Communication line (SCKp, SOp) pull-up resistance,Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
 - **3.** fMCK: Serial array unit operation clock frequency (Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))





Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





Remark p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

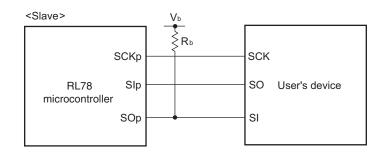
(6) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	Conditions		HS (high-spee	ed main) Mode	Unit
				MIN.	MAX.	
SCKp cycle time Note 1	t ксү2	$4.0~V \leq EV_{DD} \leq 5.5~V,$	20 MHz < fмск ≤ 24 MHz	24/f мск		ns
		$2.7V{\leq}V_b{\leq}4.0V$	$8 \text{ MHz} < f_{MCK} \le 20 \text{ MHz}$	20/f мск		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	16/f мск		ns
			fмск ≤4 MHz	12/fмск		ns
		$2.7 V \le EV_{DD} < 4.0 V$,	20 MHz < fmck \leq 24 MHz	32/f мск		ns
		$2.3V{\leq}V_b{\leq}2.7V$	16 MHz < fmck \leq 20 MHz	28/f мск		ns
			8 MHz < fmck \leq 16 MHz	24/f мск		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	16/f мск		ns
			fмск ≤4 MHz	12/f мск		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$	20 MHz < fmck \leq 24 MHz	72/f мск		ns
		$1.6V{\leq}V_b{\leq}2.0V$	16 MHz < fмск ≤ 20 MHz	64/f мск		ns
			8 MHz < fmck \leq 16 MHz	52/f мск		ns
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	32/f мск		ns
			fмск ≤4 MHz	20/f мск		ns
SCKp high-/low-level width	tкн2, tкL2	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V \end{array} \end{array} \label{eq:VDD}$		tkcy2/2-24		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V},$ $2.3 \text{ V} \le \text{V}_{\text{b}} \le 2.7 \text{ V}$		tkcy2/2-36		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V \end{array}$		tkcy2/2 - 100		ns
SIp setup time (to SCKp↑) ^{Note2}	tsik2	$\begin{array}{l} 4.0 \; V \leq EV_{DD} < 5.5 \\ 2.7 \; V \leq V_b \leq 4.0 \; V \end{array}$	V,	1/fмск + 40		ns
		$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0^{\circ}$ $2.3 \text{ V} \le \text{V}_{b} \le 2.7 \text{ V}$	V,	1/fмск + 40		ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3 \text{ V},$ $1.6 \text{ V} \le \text{V}_{\text{b}} \le 2.0 \text{ V}$		1/fмск + 60		ns
SIp hold time (from SCKp↑) ^{Note 3}	tksi2	$\begin{array}{l} 4.0 \; V \leq EV_{DD} < 5.5 \\ 2.7 \; V \leq V_b \leq 4.0 \; V \end{array}$	V,	1/fмск + 62		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$	V,	1/fмск + 62		ns
		$\begin{array}{l} 2.4 \ V \leq EV_{DD} < 3.3 \\ 1.6 \ V \leq V_b \leq 2.0 \ V \end{array}$	V,	1/fмск + 62		ns
Delay time from SCKp↓ to SOp output ^{Note 4}	tкso2	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \\ C_{b} = 30 \; pF, \; R_{b} = 1.4 \end{array}$	$V, 2.7 V \le V_b \le 4.0 V,$ 4 kΩ		2/fмск + 240	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \\ C_b = 30 \ pF, \ R_b = 2. \end{array}$	$V, 2.3 V \leq V_b \leq 2.7 V,$ 7 kΩ		2/fмск + 428	ns
		$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 3.3$ $C_{\text{b}} = 30 \text{ pF}, R_{\text{b}} = 5.3$	V, 1.6 V \leq V _b \leq 2.0 V 5 k Ω		2/fмск + 1146	ns

(Notes, Caution and Remarks are listed on the page after the next page.)



- Notes 1. Transfer rate in the SNOOZE mode : MAX. 1 Mbps
 - **2.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (V_{DD} tolerance (32- to 52-pin products)/EV_{DD} tolerance (64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.



Simplified SPI (CSI) mode connection diagram (during communication at different potential)

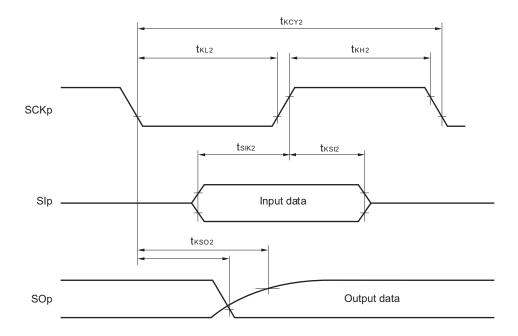
Remarks 1. $R_b[\Omega]$:Communication line (SOp) pull-up resistance,

 $C_{b}[F]: \mbox{ Communication line (SOp) load capacitance, $V_{b}[V]: Communication line voltage}$

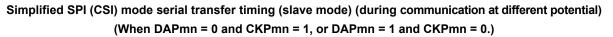
- p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)
- 3. fMCK: Serial array unit operation clock frequency

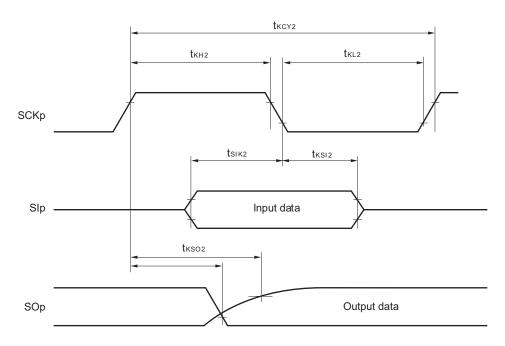
(Operation clock to be set by the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 01))





Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)





Remark p: CSI number (p = 00, 01), m: Unit number (m = 0), n: Channel number (n = 0, 1), g: PIM and POM number (g = 1)

3.5.2 Serial interface IICA

(1) I²C standard mode

(TA = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, Vss = EVss = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		Unit
				MIN. MAX.		
SCLA0 clock frequency	fscL	Standard mode:	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$	0	100	kHz
		$f_{CLK} \geq 1 \ MHz$	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$	0	100	kHz
Setup time of restart condition	tsu:sta	$2.7 V \le EV_{DD} \le 5.$	5 V	4.7		μs
		$2.4 V \le EV_{DD} \le 5.$	5 V	4.7		μs
Hold time ^{Note 1}	thd:sta	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.$	5 V	4.0		μs
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		4.0		μs
Hold time when SCLA0 = "L"	t∟ow	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		4.7		μs
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		4.7		μs
Hold time when SCLA0 = "H"	tніgн	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.$	5 V	4.0		μs
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		4.0		μs
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		250		ns
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		250		ns
Data hold time (transmission) ^{Note 2}	thd:dat	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		0	3.45	μs
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		0	3.45	μs
Setup time of stop condition	tsu:sto	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		4.0		μs
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		4.0		μs
Bus-free time	t BUF	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		4.7		μs
		$2.4 \text{ V} \le EV_{DD} \le 5.$	5 V	4.7		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 k Ω



(2) I²C fast mode

$(T_A = -40 \text{ to } +105^{\circ}C, 2.4 \text{ V} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS} = 0 \text{ V})$

Parameter	Symbol	Co	Conditions		HS (high-speed main) Mode		
					MAX.		
SCLA0 clock frequency	fsc∟	Fast mode:	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$	0	400	kHz	
		$f_{\text{CLK}} \geq 3.5 \; MHz$	$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$	0	400		
Setup time of restart condition	tsu:sta	$2.7 \text{ V} \le EV_{\text{DD}} \le 5.5$	5 V	0.6		μs	
		$2.4 \text{ V} \le EV_{\text{DD}} \le 5.5$	5 V	0.6			
Hold time Note 1	thd:sta	$2.7 \text{ V} \le EV_{\text{DD}} \le 5.5$	5 V	0.6		μs	
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		0.6			
Hold time when SCLA0 = "L"	tLOW	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		1.3		μs	
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		1.3			
Hold time when SCLA0 = "H"	thigh $2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		0.6		μs		
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		0.6			
Data setup time (reception)	tsu:dat	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		100		ns	
		$2.4~V \leq EV_{\text{DD}} \leq 5.5~V$		100			
Data hold time (transmission)Note 2	thd:dat	$2.7 \text{ V} \leq EV_{\text{DD}} \leq 5.5 \text{ V}$		0	0.9	μs	
		$2.4 \text{ V} \le EV_{\text{DD}} \le 5.5$	5 V	0	0.9		
Setup time of stop condition	tsu:sto	$2.7~V \leq EV_{\text{DD}} \leq 5.5~V$		0.6		μs	
		$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		0.6			
Bus-free time	t _{BUF}	$2.7 \text{ V} \le EV_{\text{DD}} \le 5.5$	5 V	1.3		μs	
	$2.4 \text{ V} \leq \text{EV}_{\text{DD}}$		5 V	1.3			

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

- 2. The maximum value (MAX.) of the:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.
- **Remark** The maximum value of Cb (communication line capacitance) and the value of Rb (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$



3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Classification of A/D converter characteristics

		Reference Voltage					
	Reference voltage (+) = AVREFP	Reference voltage (+) = VDD	Reference voltage (+) = V _{BGR}				
Input channel	Reference voltage (-) = AVREFM	Reference voltage (-) = Vss	Reference voltage (-) = AVREFM				
ANIO, ANI1	-	Refer to 3.6.1 (3) .	Refer to 3.6.1 (4).				
ANI16 to ANI23	Refer to 3.6.1 (2) .						
Internal reference voltage Temperature sensor output voltage	Refer to 3.6.1 (1) .		-				

(1) When reference voltage (+) = AVREFP/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pin : internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution AV _{REFP} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$		1.2	±3.5	LSB
Conversion time	t CONV	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal reference	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
Zero-scale error ^{Notes 1, 2} F ₇₅		voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution AV _{REFP} = V _{DD} ^{Note 3}	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.25	%FSR
Full-scale error ^{Notes 1, 2}	Efs	10-bit resolution AV _{REFP} = V _{DD} ^{Note 3}	$1.8~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.25	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution AV _{REFP} = V _{DD} ^{Note 3}	$1.8~V \le AV_{REFP} \le 5.5~V$			±2.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution AV _{REFP} = V _{DD} ^{Note 3}	$1.8 \text{ V} \leq AV_{\text{REFP}} \leq 5.5 \text{ V}$			±1.5	LSB
Analog input voltage V _{AIN}	Vain	Internal reference voltage $(2.4 V \le V_{DD} \le 5.5 V, HS (high-speed main) mode)$ Temperature sensor output voltage $(2.4 V \le V_{DD} \le 5.5 V, HS (high-speed main) mode)$			V _{BGR} Note 4		
					VTMPS25 Note 4		

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD} = \text{V}_{DD} \le 5.5 \text{ V}, 2.4 \text{ V} \le \text{AV}_{REFP} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = \text{EV}_{SS} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{REFP}, \text{Reference voltage (-)} = \text{AV}_{REFM} = 0 \text{ V})$

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- **2.** This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. When AV_{REFP} < V_{DD}, the MAX. values are as follows. Overall error: Add ±1.0 LSB to the MAX. value when AV_{REFP} = V_{DD}. Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV_{REFP} = V_{DD}. Integral linearity error/ Differential linearity error: Add ±0.5 LSB to the MAX. value when AV_{REFP} = V_{DD}.
- 4. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

(2) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target pin : ANI16 to ANI23

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, 2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{Ss}} = 0 \text{ V}, \text{Reference voltage (+)} = \text{AV}_{\text{REFP}}, \text{Reference voltage (-)} = \text{AV}_{\text{REFM}} = 0 \text{ V})$

Parameter	Symbol	Conditio	ns	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$		1.2	±5.0	LSB
Conversion time	t _{CONV}	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.125		39	μs
		AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.35	%FSR
Full-scale error ^{Notes 1, 2}	Efs	10-bit resolution AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$			±0.35	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$			±3.5	LSB
Differential linearity error Note 1	DLE	10-bit resolution AV _{REFP} = EV _{DD} = V _{DD} ^{Note 3}	$2.4~V \leq AV_{\text{REFP}} \leq 5.5~V$			±2.0	LSB
Analog input voltage	Vain	ANI16 to ANI23		0		AV _{REFP} and EV _{DD}	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- **3.** When $AV_{REFP} < EV_{DD} = V_{DD}$, the MAX. values are as follows.

Overall error: Add ± 4.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.

Zero-scale error/Full-scale error: Add $\pm 0.20\%$ FSR to the MAX. value when AV_{REFP} = V_{DD}.

Integral linearity error/ Differential linearity error: Add ± 2.0 LSB to the MAX. value when AV_{REFP} = V_{DD}.



(3) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{ss} (ADREFM = 0), target pin : ANI0, ANI1, ANI16 to ANI23, internal reference voltage, and temperature sensor output voltage

Parameter	Symbol	Condition	s	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$		1.2	±7.0	LSB
Conversion time	t CONV	10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.125		39	μs
			$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μS
		10-bit resolution	$3.6~V \leq V_{\text{DD}} \leq 5.5~V$	2.375		39	μs
		Target pin: Internal reference	$2.7~V \leq V_{\text{DD}} \leq 5.5~V$	3.5625		39	μs
	voltage, and temperature sensor output voltage (HS (high-speed main) mode)	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs	
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
Full-scale error ^{Notes 1, 2}	Ers	10-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±4.0	LSB
Differential linearity error	DLE	10-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±2.0	LSB
Analog input voltage	VAIN	ANIO, ANI1		0		Vdd	V
		ANI16 to ANI23		0		EVDD	V
		Internal reference voltage output (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-s)	V _{BGR} Note 3			V	
		Temperature sensor output volt (2.4 V \leq V _{DD} \leq 5.5 V, HS (high-s)	V _{TMPS25} Note 3			V	

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V}, \text{Reference voltage (+)} = \text{V}_{\text{DD}}, \text{Reference voltage (-)} = \text{V}_{\text{SS}})$

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

- **2.** This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.



(4) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AV_{REFM}/ANI1 (ADREFM = 1), target pin : ANI0, ANI16 to ANI23

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{ss}} = 0 \text{ V}, \text{ Reference voltage (+)} = \text{V}_{\text{BGR}} \text{ }^{\text{Note 3}}, \text{ Reference voltage (-)} = \text{AV}_{\text{REFM}} \text{ }^{\text{Note 4}} = 0 \text{ V}, \text{ HS (high-speed main) mode)}$

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	RES				8		bit
Conversion time	t CONV	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±2.0	LSB
Differential linearity error Note 1	DLE	8-bit resolution	$2.4~V \leq V_{\text{DD}} \leq 5.5~V$			±1.0	LSB
Analog input voltage	VAIN			0		VBGR Note 3	V

Notes 1. Excludes quantization error ($\pm 1/2$ LSB).

2. This value is indicated as a ratio (%FSR) to the full-scale value.

3. Refer to 3.6.2 Temperature sensor/internal reference voltage characteristics.

4. When reference voltage (-) = Vss, the MAX. values are as follows.

Zero-scale error: Add $\pm 0.35\%$ FSR to the MAX. value when reference voltage (-) = AV_{REFM}. Integral linearity error: Add ± 0.5 LSB to the MAX. value when reference voltage (-) = AV_{REFM}. Differential linearity error: Add ± 0.2 LSB to the MAX. value when reference voltage (-) = AV_{REFM}.



3.6.2 Temperature sensor/internal reference voltage characteristics

		, (0 1	,	,		
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	Setting ADS register = 80H, T _A = +25°C		1.05		V
Internal reference voltage	VBGR	Setting ADS register = 81H	1.38	1.45	1.5	V
Temperature coefficient	Fvtmps	Temperature sensor that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tamp		5			μs

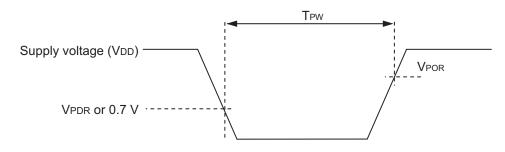
(T_A = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V, HS (high-speed main) mode)

3.6.3 POR circuit characteristics

(T_A = -40 to +105°C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	The power supply voltage is rising.		1.51	1.57	V
	VPDR	The power supply voltage is falling.	1.44	1.50	1.56	V
Minimum pulse width	Tpw		300			μS

Note Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



3.6.4 LVD circuit characteristics

(TA = -40 to +105°C, VPDR \leq EVDD = VDD \leq 5.5 V, Vss = EVss = 0 V)

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	VLVD0	Power supply rise time	3.90	4.06	4.22	V
voltage			Power supply fall time	3.83	3.98	4.13	V
		VLVD1	Power supply rise time	3.60	3.75	3.90	V
			Power supply fall time	3.53	3.67	3.81	V
		VLVD2	Power supply rise time	3.01	3.13	3.25	V
			Power supply fall time	2.94	3.06	3.18	V
		VLVD3	Power supply rise time	2.90	3.02	3.14	V
		Power supply fall time	2.85	2.96	3.07	V	
	VLVD	VLVD4	Power supply rise time	2.81	2.92	3.03	V
			Power supply fall time	2.75	2.86	2.97	V
		VLVD5	Power supply rise time	2.70	2.81	2.92	V
			Power supply fall time	2.64	2.75	2.86	V
		VLVD6	Power supply rise time	2.61	2.71	2.81	V
			Power supply fall time	2.55	2.65	2.75	V
		VLVD7	Power supply rise time	2.51	2.61	2.71	V
			Power supply fall time	2.45	2.55	2.65	V
Minimum pu	Ilse width	t∟w		300			μs
Detection d	elay time					300	μs

LVD Detection Voltage of Interrupt & Reset Mode

$(T_A = -40 \text{ to } +105^{\circ}C, V_{PDR} \le EV_{DD} = V_{DD} \le 5.5 \text{ V}, V_{SS} = EV_{SS} = 0 \text{ V})$

Parameter	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
Interrupt and reset	VLVDD0	VPOC2, VPOC1, VPOC0 = 0, 1, 1,	2.64	2.75	2.86	V	
mode VLVDD1	LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.81	2.92	3.03	V	
			Falling interrupt voltage	2.75	2.86	2.97	V
	VLVDD2	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.90	3.02	3.14	V
			Falling interrupt voltage	2.85	2.96	3.07	V
	VLVDD3	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.90	4.06	4.22	V
			Falling interrupt voltage	3.83	3.98	4.13	V

3.6.5 Power supply voltage rising slope characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V_{DD} reaches the operating voltage range shown in 3.4 AC Characteristics.

3.7 LCD Characteristics

3.7.1 Resistance division method

(1) Static display mode

$(T_A = -40 \text{ to } +105^{\circ}C, V_{L4} \text{ (MIN.)} \le V_{DD}^{Note} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.0		Vdd	V

Note Must be 2.4 V or higher.

(2) 1/2 bias method, 1/4 bias method

(T_A = -40 to +105°C, V_L4 (MIN.) \leq V_DD \leq 5.5 V, V_SS = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.7		Vdd	V

(3) 1/3 bias method

(TA = -40 to +105°C, VL4 (MIN.) \leq VDD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.5		VDD	V



3.7.2 Internal voltage boosting method

(1) 1/3 bias method

(T_A = -40 to +105°C, 2.4 V \leq V_DD \leq 5.5 V, Vss = 0 V)

Parameter	Symbol	Cond	litions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1	C1 to C4 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 <i>µ</i> F	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	Vl2	C1 to C4 ^{Note 1} =	0.47 <i>μ</i> F	2 V∟1 –0.1	2 V _{L1}	2 VL1	V
Tripler output voltage	VL4	C1 to C4 ^{Note 1} =	ε 0.47 <i>μ</i> F	3 V _{L1} -0.15	3 VL1	3 VL1	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C4 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between VL1 and GND

C3: A capacitor connected between VL2 and GND

C4: A capacitor connected between VL4 and GND

C1 = C2 = C3 = C4 = 0.47 μ F \pm 30%

2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).

3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

(2) 1/4 bias method

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1 Note 4	C1 to C5 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 <i>µ</i> F	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	VL2	C1 to C5 ^{Note 1} =	0.47 <i>μ</i> F	2 VL1 - 0.08	2 VL1	2 VL1	V
Tripler output voltage	VL3	C1 to C5 ^{Note 1} =	0.47 μF	$3 V_{L1} - 0.12$	3 VL1	3 VL1	V
Quadruply output voltage	VL4 Note 4	C1 to C5 ^{Note 1} =	0.47 μF	$4 V_{L1} - 0.16$	4 VL1	4 VL1	V
Reference voltage setup time Note 2	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C5 ^{Note 1} =	0.47 μF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between VL2 and GND
- C4: A capacitor connected between VL3 and GND
- C5: A capacitor connected between V_{L4} and GND
- $C1 = C2 = C3 = C4 = C5 = 0.47 \ \mu F \pm 30\%$
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected [by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B] if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** VL4 must be 5.5 V or lower.



3.7.3 Capacitor split method

1/3 bias method

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
VL4 voltage	VL4	C1 to C4 = 0.47 μ F ^{Note 2}		Vdd		V
V∟₂ voltage	VL2	C1 to C4 = 0.47 μ F ^{Note 2}	2/3 V _{L4} - 0.1	2/3 VL4	2/3 V _{L4} + 0.1	V
V∟1 voltage	VL1	C1 to C4 = 0.47 μ F ^{Note 2}	1/3 V∟₄ – 0.1	1/3 VL4	1/3 V∟₄ + 0.1	V
Capacitor split wait time ^{Note 1}	tvwait		100			ms

- Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).
 - 2. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between V_{L1} and GND

C3: A capacitor connected between V_{L2} and GND

C4: A capacitor connected between V_{L4} and GND

 $C1 = C2 = C3 = C4 = 0.47 \ \mu\text{F}{\pm}30\%$

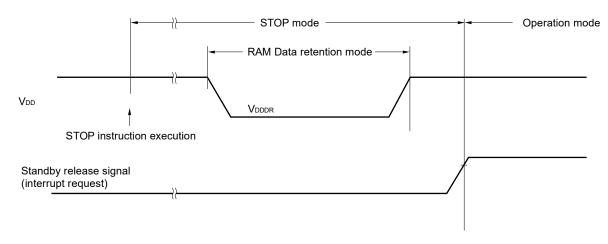


3.8 RAM Data Retention Characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 ^{Note}		5.5	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



3.9 Flash Memory Programming Characteristics

$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclk	$1.8~V \leq V_{\text{DD}} \leq 5.5~V$	1		24	MHz
Number of code flash rewrites Notes 1, 2, 3	Cerwr	Retained for 20 years $T_A = 85^{\circ}C^{Note 4}$	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year T _A = 25°C ^{Note 4}		1,000,000		
		Retained for 5 years $T_A = 85^{\circ}C^{Note 4}$	100,000			
		Retained for 20 years $T_A = 85^{\circ}C^{Note 4}$	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

- The retaining years are until next rewrite after the rewrite.
- 2. When using flash memory programmer and Renesas Electronics self programming library
- 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.
- 4. This temperature is the average value at which data are retained.

3.10 Dedicated Flash Memory Programmer Communication (UART)

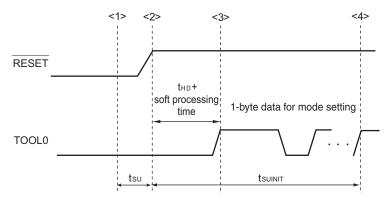
$(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD}} = \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS}} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During flash memory programming	115,200		1,000,000	bps



3.11 Timing Specifications for Switching Flash Memory Programming Modes (T_A = -40 to +105°C, 2.4 V \leq EV_{DD} = V_{DD} \leq 5.5 V, V_{SS} = EV_{SS} = 0 V)

		-				
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	tsu	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms



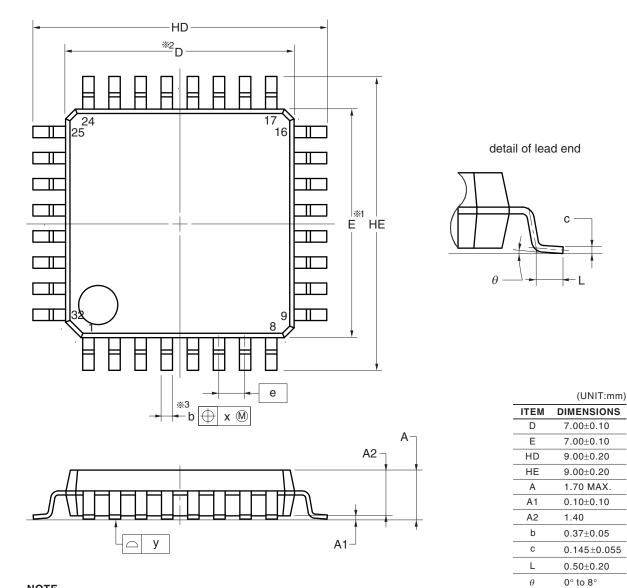
- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: Communication for the initial setting must be completed within 100 ms after the external reset is released during this period.
 - tsu: Time to release the external reset after the TOOL0 pin is set to the low level
 - the: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)



4. PACKAGE DRAWINGS

4.1 32-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP32-7x7-0.80	PLQP0032GB-A	P32GA-80-GBT-1	0.2



NOTE

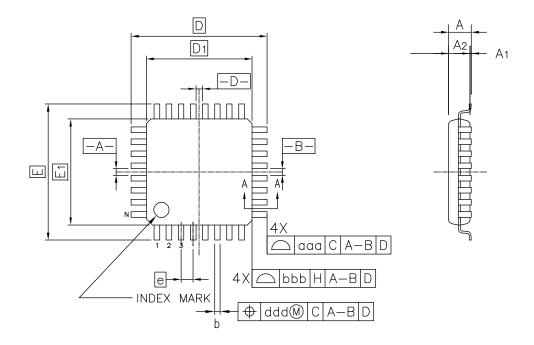
1.Dimensions "%1" and "%2" do not include mold flash.

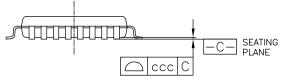
2.Dimension "%3" does not include trim offset.

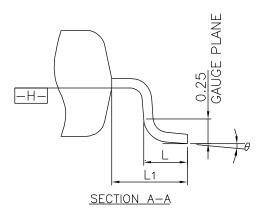
е 0.80 0.20 х у 0.10



JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP32-7x7-0.80	PLQP0032GE-A	0.18





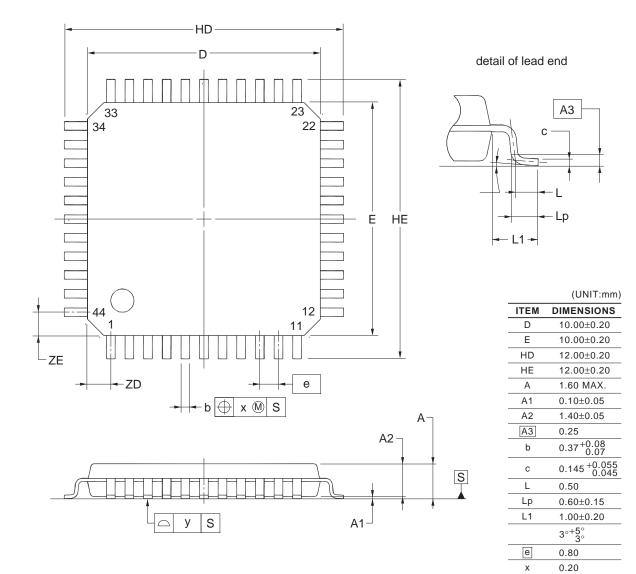


Reference	Dimensi	on in Mil	limeters
Symbol	Min.	Nom.	Max.
A	-	-	1.60
A ₁	0.05	_	0.15
A ₂	1.35	1.40	1.45
D	—	9.00	_
D ₁	—	7.00	-
E	—	9.00	-
E1	—	7.00	-
N	—	32	-
е	—	0.80	-
b	0.30	0.37	0.45
с	0.09	_	0.20
θ	0°	3.5°	7°
L	0.45	0.60	0.75
L	—	1.00	-
aaa	_	-	0.20
bbb	_	-	0.20
ссс	_	-	0.10
ddd	_	-	0.20



4.2 44-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP44-10x10-0.80	PLQP0044GC-A	P44GB-80-UES-2	0.36



NOTE

Each lead centerline is located within 0.20 mm of its true position at maximum material condition.

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ZE

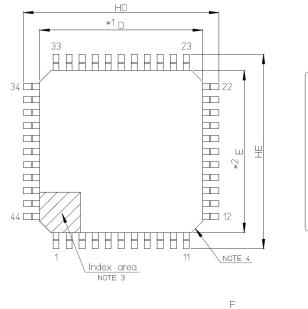
0.10

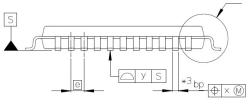
1.00

1.00



JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LQFP44-10×10-0.80	PLQP0044GC-D		0.36g





Detail F

L1



DIMENSIONS **1" AND **2" DO NOT INCLUDE MOLD FLASH. DIMENSION **3" DOES NOT INCLUDE TRIM OFFSET. PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA. CHAMFERS AT CORVERS ARE OPTIONAL; SIZE MAY VARY. 1. 2. 3.

Reference

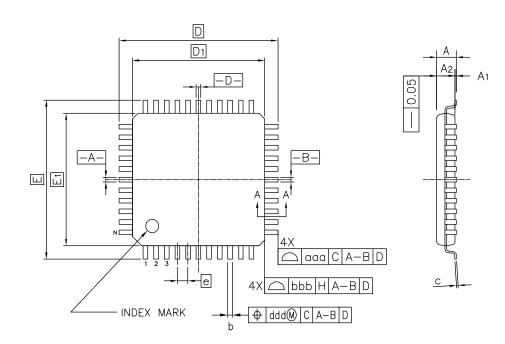
4.

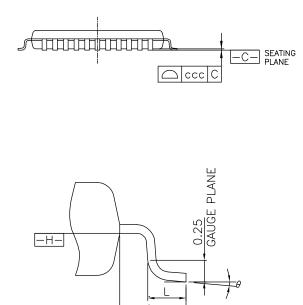
Symbol	Min	Nom	Max
D	9.8	10.0	10.2
E	9.8	10.0	10.2
A2		1.4	
HD	11.8	12.0	12.2
HE	11.8	12.0	12.2
А			1.6
A1	0.05		0.15
bp	0.22	0.37	0,45
С	0.09	· · · · · · · · · · · · · · · · · · ·	0.20
θ	0"	3.5	8 "
e	_	0.80	
×		1 <u> </u>	0.20
У		·	0.10
Lp	0.45	0.6	0,75
L1		1.0	

Dimension in Millimeters



JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP044-10x10-0.80	PLQP0044GE-A	0.34





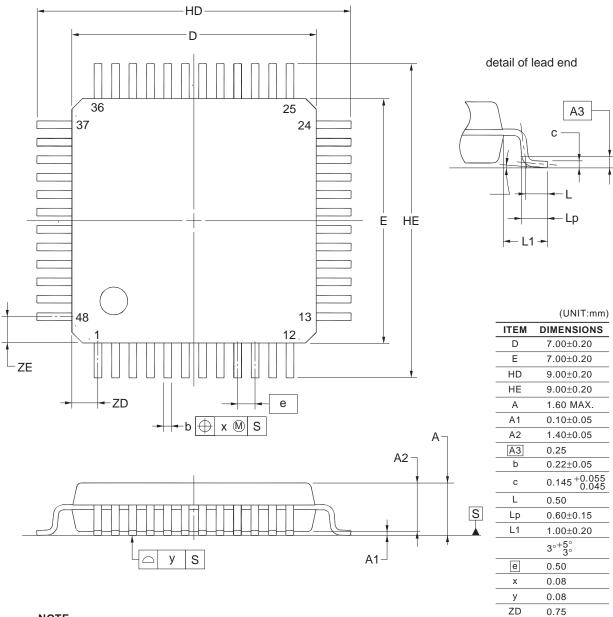
SECTION A-A

Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
A	-	_	1.60
A ₁	0.05	_	0.15
A ₂	1.35	1.40	1.45
D	—	12.00	Ι
D ₁	—	10.00	-
E	—	12.00	-
E1	—	10.00	-
N	—	44	-
е	—	0.80	_
b	0.30	0.37	0.45
с	0.09	—	0.20
θ	0°	3.5°	7°
L	0.45	0.60	0.75
L	—	1.00	-
aaa	_	_	0.20
bbb	_	_	0.20
ссс	_	_	0.10
ddd	—	—	0.20



4.3 48-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LFQFP48-7x7-0.50	PLQP0048KF-A	P48GA-50-8EU-1	0.16



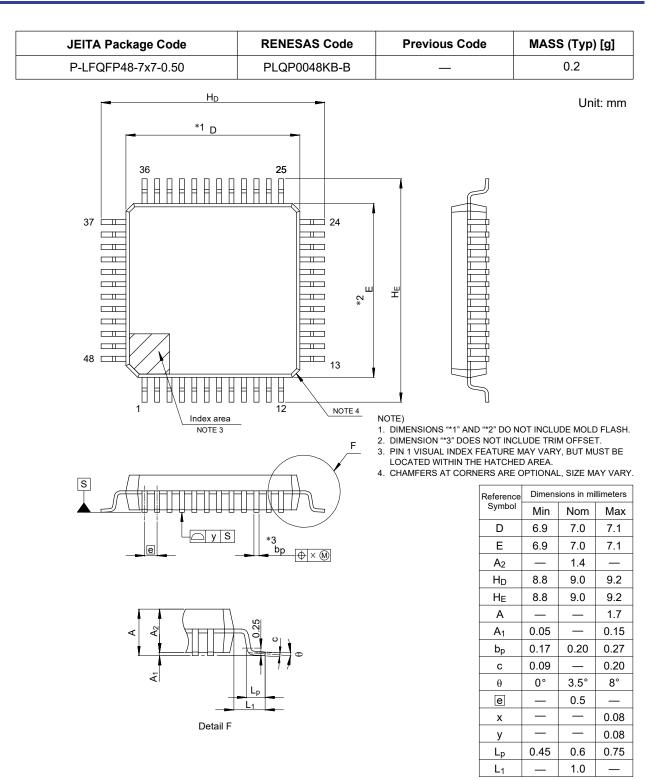
NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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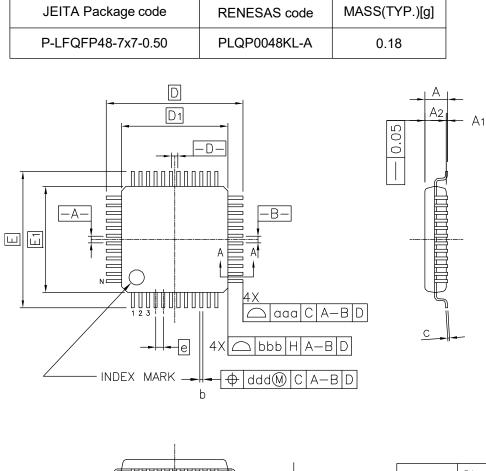
ZE

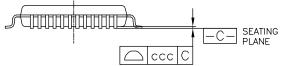
0.75

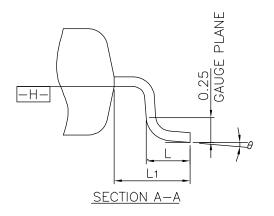


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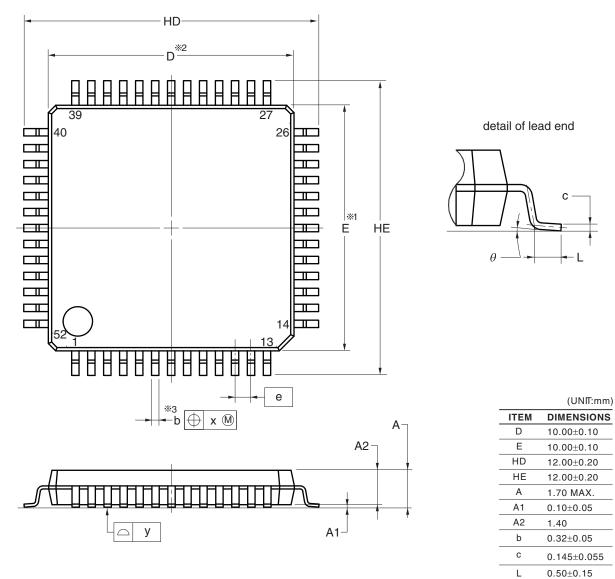


Reference	Dimension in Millimeters		
Symbol	Min.	Nom.	Max.
A	-	_	1.60
A ₁	0.05	—	0.15
A ₂	1.35	1.40	1.45
D	—	9.00	—
D ₁	—	7.00	—
E	—	9.00	—
E ₁	—	7.00	—
N	—	48	—
е	—	0.50	-
b	0.17	0.22	0.27
с	0.09	—	0.20
θ	0°	3.5°	7°
L	0.45	0.60	0.75
L	—	1.00	—
aaa	-	_	0.20
bbb	-	_	0.20
ссс	—	_	0.08
ddd	—	—	0.08



4.4 52-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP52-10x10-0.65	PLQP0052JA-A	P52GB-65-GBS-1	0.3



NOTE1.Dimensions "%1" and "%2" do not include mold flash. 2.Dimension "%3" does not include trim offset.

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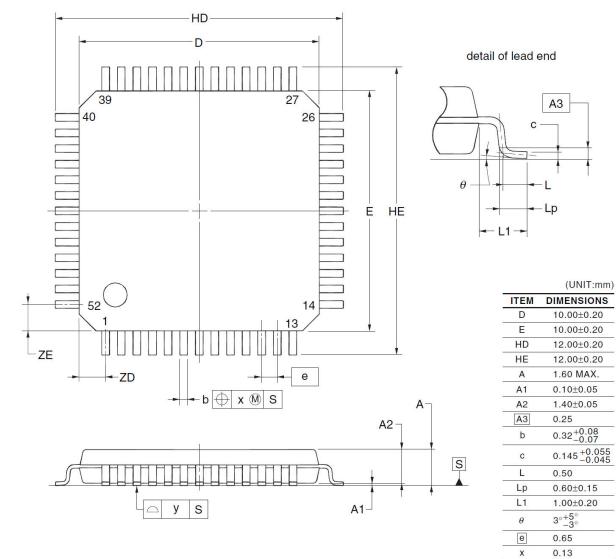
 0° to 8°

0.65

0.10



JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP52-10x10-0.65	PLQP0052JD-B	P52GB-65-UET-2	0.36



NOTE

Each lead centerline is located within 0.13 mm of its true position at maximum material condition.



у

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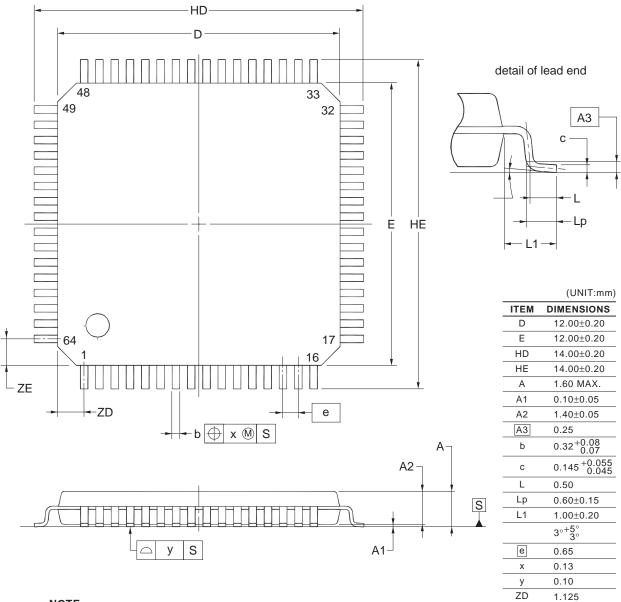
0.10

1.10

1.10

4.5 64-pin Package

JEITA Package Code	RENESAS Code	Previous Code	MASS (TYP.) [g]
P-LQFP64-12x12-0.65	PLQP0064JA-A	P64GK-65-UET-2	0.51



NOTE

Each lead centerline is located within 0.13 mm of its true position at maximum material condition.

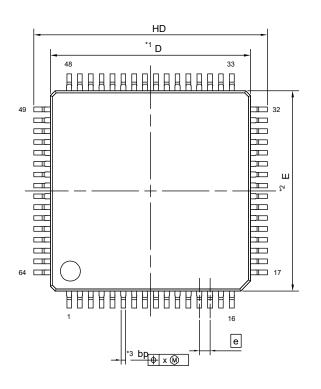
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ZE

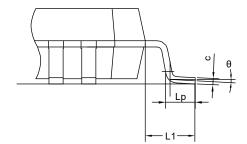
1.125

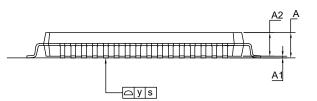
<R>

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LQFP64-12x12-0.65	PLQP0064JB-A	0.50



detail of lead end





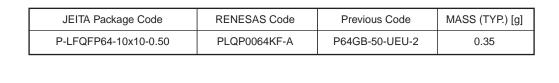
NOTE

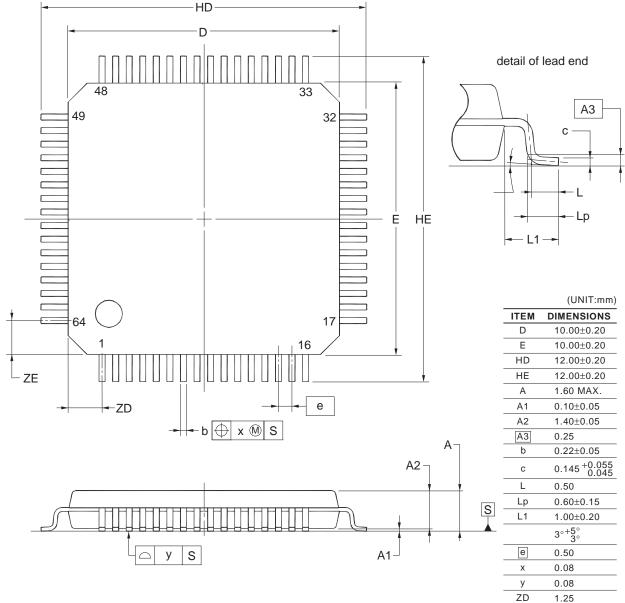
1.DIMENSIONS "*1" AND "*2"DO NOT INCLUDE MOLD FLASH. 2.DIMENSION "*3" DOES NOT INCLUDE TRIM OFFSET.

Reference	Dimension in Millimeters		imeters
Symbol	Min.	Nom.	Max.
E	11.90	12.00	12.10
D	11.90	12.00	12.10
A ₂		1.40	-
H _D	13.80	14.00	14.20
H _E	13.80	14.00	14.20
A	-	_	1.70
A ₁	0.05	-	0.15
Lp	0.45	0.60	0.75
L1	-	1.00	—
b _p	0.27	0.32	0.37
с	0.09	—	0.20
е	1	0.65	—
θ	0.00	3.50	8.00
х	_	_	0.08
у	_	_	0.08









NOTE

Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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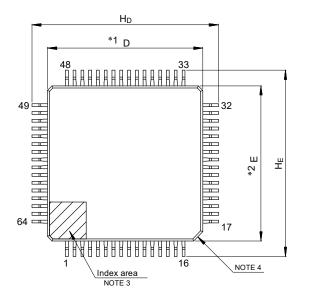
ZE

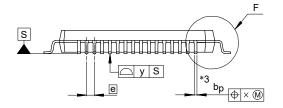
1.25

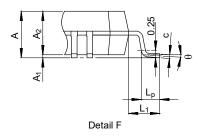


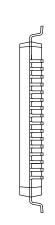
Unit: mm

JEITA Package Code	RENESAS Code	Previous Code	MASS (Typ) [g]
P-LFQFP64-10x10-0.50	PLQP0064KB-C	_	0.3









NOTE)

- NOTE)
 DIMENSIONS "*1" AND "*2" DO NOT INCLUDE MOLD FLASH.
 DIMENSION "*3" DOES NOT INCLUDE TRIM OFFSET.
 PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA.

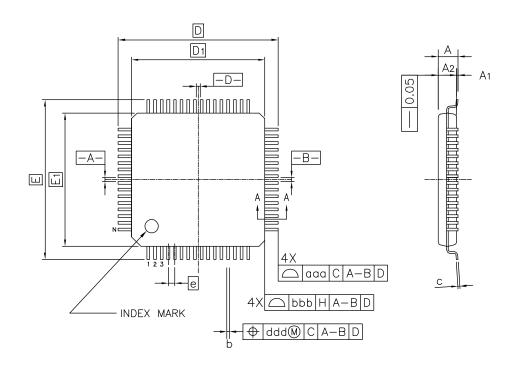
- 4. CHAMFERS AT CORNERS ARE OPTIONAL, SIZE MAY VARY.

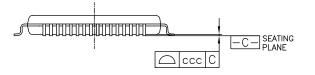
Reference	Dimensions in millimeters		
Symbol	Min	Nom	Max
D	9.9	10.0	10.1
E	9.9	10.0	10.1
A ₂	_	1.4	_
H _D	11.8	12.0	12.2
HE	11.8	12.0	12.2
Α	_		1.7
A ₁	0.05		0.15
bp	0.15	0.20	0.27
с	0.09	_	0.20
θ	0°	3.5°	8°
е	—	0.5	—
х	_		0.08
у		_	0.08
Lp	0.45	0.6	0.75
L ₁	—	1.0	_

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JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP064-10x10-0.50	PLQP0064KL-A	0.36

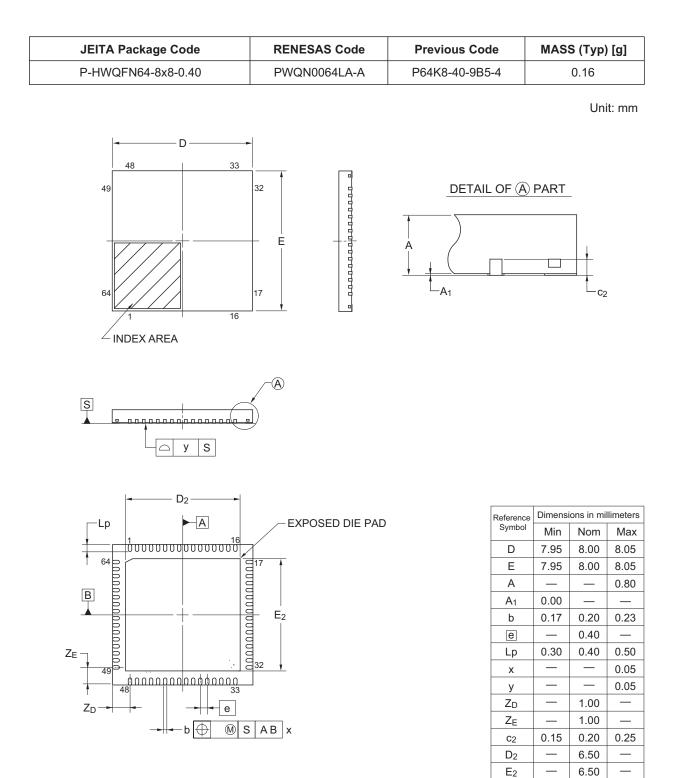




	GAUGE PLANE
SECTION A-	A

Reference	Dimensi	on in Mil	limeters
Symbol	Min.	Nom.	Max.
A	_	_	1.60
A ₁	0.05	—	0.15
A ₂	1.35	1.40	1.45
D	—	12.00	—
D ₁	—	10.00	—
E	—	12.00	—
Eı	—	10.00	—
N	—	64	—
e	_	0.50	-
b	0.17	0.22	0.27
с	0.09	_	0.20
θ	0°	3.5°	7°
L	0.45	0.60	0.75
Ц	—	1.00	—
aaa	_	_	0.20
bbb	_	_	0.20
ccc	—	—	0.08
ddd	—	—	0.08

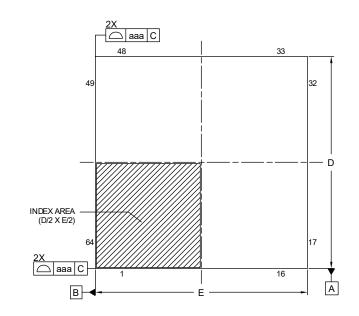


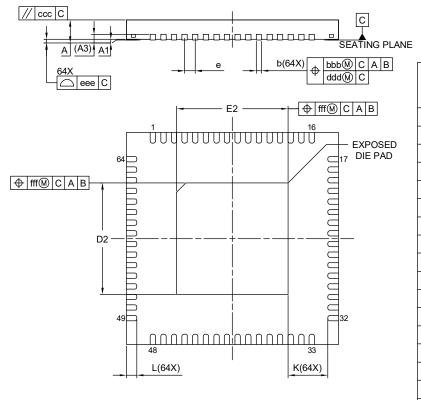


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JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-HWQFN064-8x8-0.40	PWQN0064LB-A	0.18





Reference Symbol	Dimension in Millimeters		
	Min.	Nom.	Max.
А		—	0.80
A ₁	0.00	0.02	0.05
A ₃	(0.203 REF	
b	0.15	0.20	0.25
D		8.00 BSC	
Е		8.00 BSC	
е	0.40 BSC		
L	0.35	0.40	0.45
К	0.20	—	—
D ₂	4.15	4.20	4.25
E ₂	4.15	4.20	4.25
aaa		0.10	
bbb	0.07		
CCC	0.10		
ddd		0.05	
eee		0.08	
fff	0.10		



Revision History

RL78/L12 Datasheet

Date	1	
	Page	Summary
Feb 20, 2012	-	First Edition issued
Sep 26, 2012	7, 8	Modification of caution 2 in 1.3.5 64-pin products
	15	Modification of I/O port in 1.6 Outline of Functions
	-	Modification of 2. ELECTRICAL SPECIFICATIONS (TARGET)
	-	Update of package drawings in 3. PACKAGE DRAWINGS
Jan 31, 2013	11 to 15	Modification of 1.5 Block Diagram
	16	Modification of Note 2 in 1.6 Outline of Functions
	17	Modification of 1.6 Outline of Functions
	-	Deletion of target in 2. ELECTRICAL SPECIFICATIONS
	18	Addition of caution 2 to 2. ELECTRICAL SPECIFICATIONS
	19	Addition of description, note 3, and remark 2 to 2.1 Absolute Maximum Ratings
	20	Modification of description and addition of note to 2.1 Absolute Maximum Ratings
	22, 23	Modification of 2.2 Oscillator Characteristics
	30	Modification of notes 1 to 4 in 2.3.2 Supply current characteristics
	32	Modification of notes 1, 3 to 6, 8 in 2.3.2 Supply current characteristics
	34	Modification of notes 7, 9, 11, and addition of notes 8, 12 to 2.3.2 Supply current
		characteristics
	36	Addition of description to 2.4 AC Characteristics
	38, 40 to	Modification of 2.5.1 Serial array unit
	42, 44 to	
	46, 48 to	
		Modification of 2.5.2 Serial interface IICA
	62	Modification of 2.6.2 Temperature sensor/internal reference voltage characteristics
	64	Addition of note and caution in 2.6.5 Supply voltage rise time
	69	Modification of 2.8 Data Memory STOP Mode Low Supply Voltage Data Retention
		Characteristics
	69	Modification of conditions in 2.9 Timing Specs for Switching Flash Memory
		Programming Modes
	70	Modification of 2.10 Timing Specifications for Switching Flash Memory Programming Modes
lan 10, 2014	1	Modification of 1.1 Features
Jan 10, 2014		Modification of Figure 1-1
		Modification of part number, note, and caution
	5 to 10	Deletion of COMEXP pin in 1.3.1 to 1.3.5.
	11	Modification of description in 1.4 Pin Identification
	12 to 16	Deletion of COMEXP pin in 1.5.1 to 1.5.5
	17	Modification of table and note 2 in 1.6 Outline of Functions
	20	Modification of description in Absolute Maximum Ratings (T _A = 25°C) (1/3)
	21	Modification of description and note 2 in Absolute Maximum Ratings ($T_A = 25^{\circ}C$) (2/3)
	23	Modification of table, note, caution, and remark in 2.2.1 X1, XT1 oscillator characteristics
	23	Modification of table in 2.2.2 On-chip oscillator characteristics
	24	Modification of table, notes 2 and 3 in 2.3.1 Pin characteristics (1/5)
	25	Modification of notes 1 and 3 in 2.3.1 Pin characteristics (2/5)
	30	Modification of notes 1 and 4 in 2.3.2 Supply current characteristics (1/3)
	31, 32	Modification of table, notes 1, 5, and 6 in 2.3.2 Supply current characteristics (2/3)
	33, 34	Modification of table, notes 1, 3, 4, and 5 to 10 in 2.3.2 Supply current characteristics (3/3)
		15 11 11 11 16 17 - 18 19 20 22, 23 30 32 34 36 38, 40 to 42, 44 to 46, 48 to 52, 54, 55 57, 58 62 64 69 61 69 61 11 12 to 16 17 20 21 23 24 25 30 31, 32

			Description
Rev.	Date	Page	Summary
2.00	Jan 10, 2014	35	Modification of table in 2.4 AC Characteristics
		36	Addition of Minimum Instruction Execution Time during Main System Clock Operation
		37	Modification of AC Timing Test Points and External System Clock Timing
		39	Modification of AC Timing Test Points
		39	Modification of description, notes 1 and 2 in (1) During communication at same potential (UART mode)
		41, 42	Modification of description, remark 2 in (2) During communication at same potential (CSI mode)
		42, 43	Modification of description in (3) During communication at same potential (CSI mode)
		45	Modification of description, notes 1 and 3, and remark 3 in (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2)
		46, 48	Modification of description, and remark 3 in (4) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)
		49, 50	Modification of table, and note 1, caution, and remark 3 in (5) Communication at different potential (2.5 V, 3 V) (CSI mode)
		51	Modification of table and note in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (1/3)
		52	Modification of table and notes 1 to 3 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (2/3)
		53, 54	Modification of table, note 3, and remark 3 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (3/3)
		56	Modification of table in (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/2)
		57	Modification of table in (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/2)
		59, 60	Addition of (1) I ² C standard mode
		61	Addition of (2) I ² C fast mode
		62	Addition of (3) I ² C fast mode plus
		63	Addition of table in 2.6.1 A/D converter characteristics
		63, 64	Modification of description and notes 3 to 5 in 2.6.1 (1)
		65	Modification of description, notes 3 and 4 in 2.6.1 (2)
		66	Modification of description, notes 3 and 4 in 2.6.1 (3)
		67	Modification of description, notes 3 and 4 in 2.6.1 (4)
		67	Modification of the table in 2.6.2 Temperature sensor/internal reference voltage characteristics
		68	Modification of the table and note in 2.6.3 POR circuit characteristics
		70	Modification of the table of LVD Detection Voltage of Interrupt & Reset Mode
		70	Modification from V_{DD} rise slope to Power supply voltage rising slope in 2.6.5 Supply voltage rise time
		75	Modification of description in 2.10 Dedicated Flash Memory Programmer Communication (UART)
		76	Modification of the figure in 2.11 Timing Specifications for Switching Flash Memory Programming Modes
		77 to 126	Addition of products for industrial applications (G: $T_A = -40$ to $+105^{\circ}C$)
		127 to 133	Addition of product names for industrial applications (G: $T_A = -40$ to $+105^{\circ}C$)
2.10	Sep 30, 2016	5	Modification of pin configuration in 1.3.1 32-pin products
		6	Modification of pin configuration in 1.3.2 44-pin products
		7	Modification of pin configuration in 1.3.3 48-pin products
		8	Modification of pin configuration in 1.3.4 52-pin products
		9, 10	Modification of pin configuration in 1.3.5 64-pin products
		17	Modification of description of main system clock in 1.6 Outline of Functions
		74	Modification of title of 2.8 RAM Data Retention Characteristics, Note, and figure
		74	Modification of table of 2.9 Flash Memory Programming Characteristics
		123	Modification of title of 3.8 RAM Data Retention Characteristics, Note, and figure
		123	Modification of table of 3.9 Flash Memory Programming Characteristics and addition of Note 4
		131	Modification of 4.5 64-pin Products

			Description
Rev.	Date	Page	Summary
2.11	Feb 14, 2020	3	Addition of packaging specifications in Figure 1-1 Part Number, Memory Size, and Package of RL78/L12
		4, 5	Addition of ordering part numbers and RENESAS codes in Table 1-1 List of Ordering Part Numbers
		6 to 11	Additions of the package size and pin pitch in 1.3 Pin Configuration (Top View)
		126, 127,	Modification of the titles of the subchapters and deletion of product names in
		129,	Chapter 4
		131 to 133,	
		135	
		128	Addition of figure in 4.2 44-pin Package
		130	Addition of figure in 4.3 48-pin Package
		134	Addition of figure in 4.5 64-pin Package
2.12	Dec 22, 2020	3	Modification of Figure 1-1 Part Number, Memory Size, and Package of RL78/L12
		4	Modification of description in Table 1-1 List of Ordering Part Numbers
		135	Addition of figure in 4.5 64-pin Package
2.20	Dec 22, 2021	67	Modification of description in 2.6.3 POR circuit characteristics
0.01	0 00 0000	117	Modification of description in 3.6.3 POR circuit characteristics
2.21	Sep 30, 2022	All	The module name for CSI was changed to Simplified SPI(CSI)
		All	"wait" for IIC was modified to "clock stretch"
		4, 5	Modification of description in Table 1-1. (1/2) to (2/2)
		127 130	Addition of package drawing in 4.1 32-pin Package
			Addition of package drawing in 4.2 44-pin Package
		133	Addition of package drawing in 4.3 48-pin Package
		135 137, 140	Addition of package drawing in 4.4 52-pin Package
2.24	Fab 01 2022		Addition of package drawing in 4.5 64-pin Package
2.21	Feb 01, 2023	5	Addition of title in Table 1-1. List of Ordering Part Numbers
		6, 7	Modification of 32-pin plastic LQFP (7 × 7 mm, 0.8 mm pitch) Addition of Table 1-2. Alternate function of 32-pin products
		8	
		8 to 10	Modification of 44-pin plastic LQFP (10 × 10 mm, 0.8 mm pitch) Addition of Table 1-3. Alternate function of 44-pin products
		11	Modification of 48-pin plastic LFQFP (7 × 7 mm, 0.5 mm pitch)
		11 to 13	Addition of Table 1-4. Alternate function of 48-pin products
		14	Modification of 52-pin plastic LQFP (10 × 10 mm, 0.65 mm pitch)
		14 to 16	Addition of Table 1-5. Alternate function of 52-pin products
		17	Modification of 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm pitch)
		17	Deletion of Cautions and Remarks in 64-pin plastic HWQFN (8 × 8 mm, 0.4 mm
			pitch)
		18	Modification of 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch), 64-pin plastic LQFP (12 × 12 mm, 0.65 mm pitch)
		19 to 21	Addition of Table 1-6. Alternate function of 64-pin products
		22	Modification of description in 1.4 Pin Identification
		23	Modification of block diagram in 1.5.1 32-pin products
		24	Modification of block diagram in 1.5.2 44-pin products
		25	Modification of block diagram in 1.5.3 48-pin products
		26	Modification of block diagram in 1.5.4 52-pin products
		27	Modification of block diagram in 1.5.5 64-pin products
		41	Modification of Notes 1 and 4 in 2.3.2 Supply current characteristics
		42	Modification of table in 2.3.2 Supply current characteristics
		43	Modification of Notes 1 and 5 and delete Notes 6 in 2.3.2 Supply current
			characteristics
		71 to 73	Modification of Notes 2 in 2.5.2 Serial interface IICA
		99	Modification of Notes 1 and 4 in 3.3.2 Supply current characteristics
		100	Modification of table in 3.3.2 Supply current characteristics
		101	Modification of Notes 1 and 5 and delete Notes 6 in 3.3.2 Supply current
		A A 🗝	characteristics
		147	Replacement of package drawing in 4.5 64-pin Package

The mark "<R>" shows major revised points. The revised points can be easily searched by copying an "<R>" in the PDF file and specifying it in the "Find what:" field.

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General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power is supplied until the power reaches the level at which reseting is specified.

3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a system-evaluation test for the given product.

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